

40MX and 42MX FPGA Families

Features

High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages

- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

Ease of Integration

- Mixed-Voltage Operation (5.0V or 3.3V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

Product Profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	—	—	—	—	—	2,560
Logic Modules						
Sequential	—	—	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	—	—	—	—	24	24
Clock-to-Out	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)	—	—	—	—	—	10
Dedicated Flip-Flops	—	—	348	624	954	1,230
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	—	—	—	—	Yes	Yes
Boundary Scan Test (BST)	—	—	—	—	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	—
PQFP	100	100	100, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	—	—
TQFP	—	—	176	176	176	—
CQFP	—	—	—	—	—	208, 256
PBGA	—	—	—	—	—	272

Ordering Information

A42MX16	PQ	100	
Application (Temperature Range)			
Blank = Commercial (0 to +70°C)			
I = Industrial (-40 to +85°C)			
A = Automotive (-40 to +125°C)			
M = Military (-55 to +125°C)			
B = MIL-STD-883			
Package Lead Count			
Package Type			
PL = Plastic Leaded Chip Carrier			
PQ = Plastic Quad Flat Pack			
TQ = Thin (1.4 mm) Quad Flat Pack			
VQ = Very Thin (1.0 mm) Quad Flat Pack			
BG = Plastic Ball Grid Array			
CQ = Ceramic Quad Flat Pack			
Speed Grade			
Blank = Standard Speed			
-1 = Approximately 15% Faster than Standard			
-2 = Approximately 25% Faster than Standard			
-3 = Approximately 35% Faster than Standard			
-F = Approximately 40% Slower than Standard			
Part Number			
A40MX02 = 3,000 System Gates			
A40MX04 = 6,000 System Gates			
A42MX09 = 14,000 System Gates			
A42MX16 = 24,000 System Gates			
A42MX24 = 36,000 System Gates			
A42MX36 = 54,000 System Gates			

Plastic Device Resources

Device	User I/Os										
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 160-Pin	PQFP 208-Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100-Pin	TQFP 176-Pin	PBGA 272-Pin
A40MX02	34	57	—	57	—	—	—	57	—	—	—
A40MX04	34	57	69	69	—	—	—	69	—	—	—
A42MX09	—	—	72	83	101	—	—	—	83	104	—
A42MX16	—	—	72	83	125	140	—	—	83	140	—
A42MX24	—	—	72	—	125	176	—	—	—	150	—
A42MX36	—	—	—	—	—	176	202	—	—	—	202

Package Definitions

PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack,
 PBGA = Plastic Ball Grid Array

Ceramic Device Resources

Device	User I/Os	
	CQFP 208-Pin	CQFP 256-Pin
A42MX36	176	202

Package Definitions

CQFP = Ceramic Quad Flat Pack

Temperature Grade Offerings

Package	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
PLCC 44	C, I, M	C, I, M				
PLCC 68	C, I, A, M	C, I, M				
PLCC 84		C, I, A, M	C, I, A, M	C, I, M	C, I, M	
PQFP 100	C, I, A, M	C, I, A, M	C, I, A, M	C, I, M		
PQFP 160			C, I, A, M	C, I, M	C, I, A, M	
PQFP 208				C, I, A, M	C, I, A, M	C, I, A, M
PQFP 240						C, I, A, M
VQFP 80	C, I, A, M	C, I, A, M				
VQFP 100			C, I, A, M	C, I, A, M		
TQFP 176			C, I, A, M	C, I, A, M	C, I, A, M	
PBGA 272						C, I, M
CQFP 208						C, M, B
CQFP 256						C, M, B

Notes:*C = Commercial**I = Industrial**A = Automotive**M = Military**B = MIL-STD-883 Class B*

Speed Grade Offerings

	-F	Std	-1	-2	-3
C	✓	✓	✓	✓	✓
I		✓	✓	✓	✓
A		✓			
M		✓	✓		
B		✓	✓		

Note: Refer to the 40MX and 42MX Automotive Family FPGAs datasheet for details on automotive-grade MX offerings.

Contact your local Actel representative for device availability.

General Description

Actel's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Actel's patented antifuse technology implemented in a $0.45\mu\text{m}$ triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. Actel's MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

Actel's A42MX24 and A42MX36 devices also feature MultiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI Local Bus Specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide datapath manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed datapath functions such as FIFOs, LIFOs and scratchpad memory. A42MX24 and A42MX36 also contain wide-decode modules.

Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources (Figure 1).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

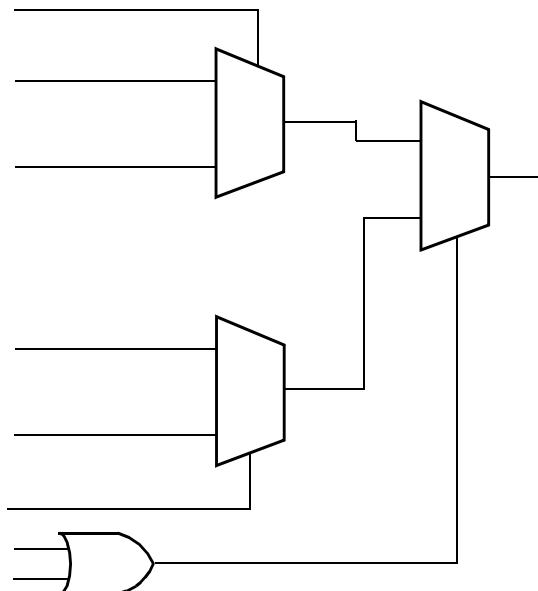


Figure 1 • 40MX Logic Module

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). [Figure 2](#) illustrates the combinatorial logic module. The S-module, shown in [Figure 3](#), implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

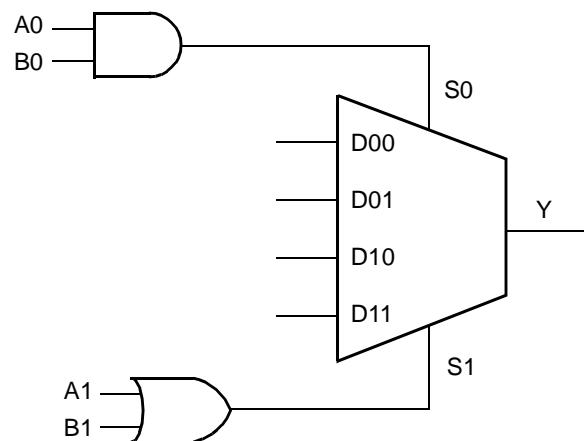


Figure 2 • 42MX C-Module Implementation

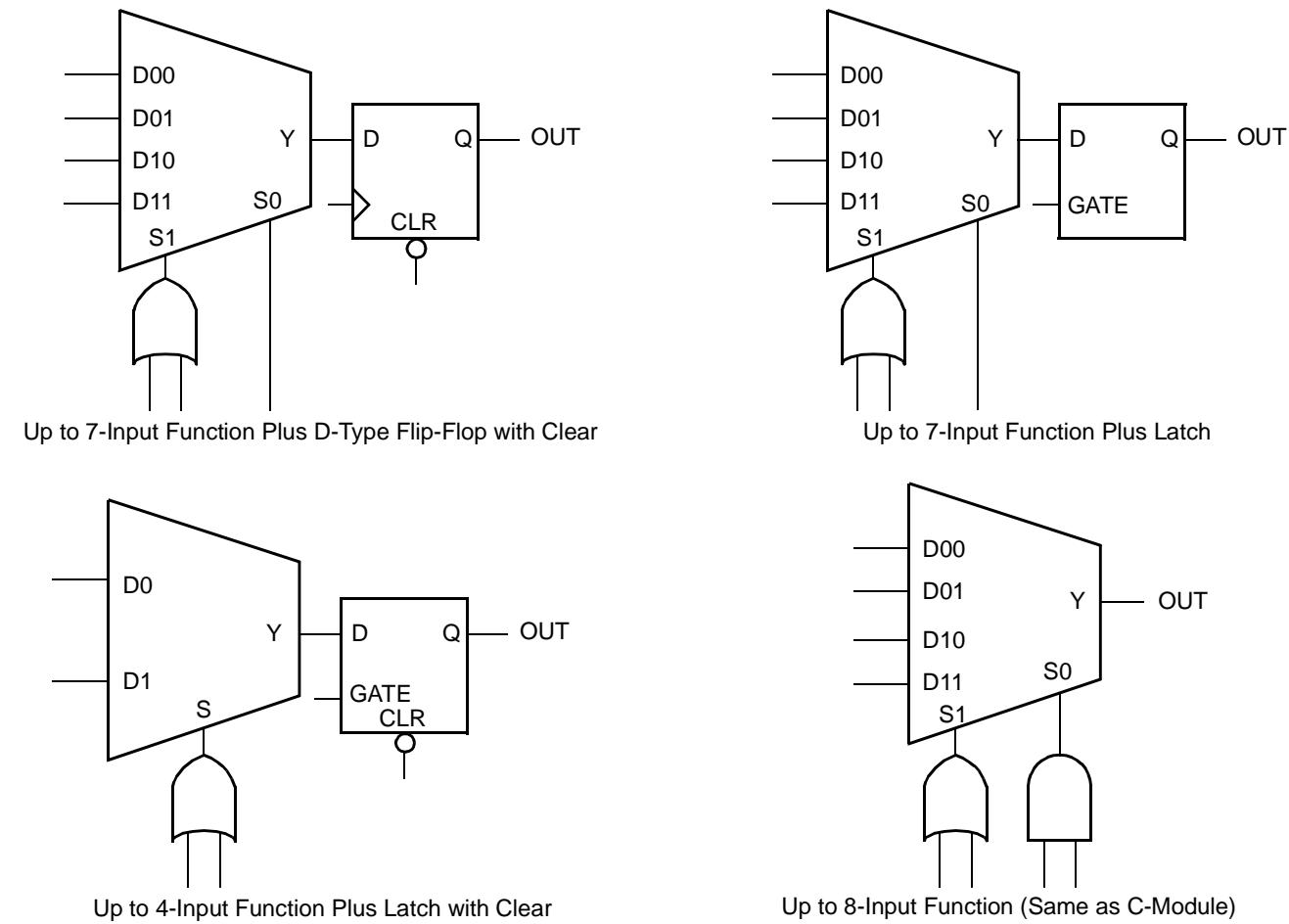


Figure 3 • 42MX S-Module Implementation

A42MX24 and A42MX36 devices contain D-modules, which are arranged around the periphery of the device. D-modules contain wide-decode circuitry, providing a fast, wide-input AND function similar to that found in CPLD architectures (Figure 4). The D-module allows A42MX24 and A42MX36 devices to perform wide-decode functions at speeds comparable to CPLDs and PALs. The output of the D-module has a programmable inverter for active HIGH or LOW assertion. The D-module output is hardwired to an output pin, and can also be fed back into the array to be incorporated into other logic.

Dual-Port SRAM Modules

The A42MX36 device contains dual-port SRAM modules that have been optimized for synchronous or asynchronous applications. The SRAM modules are arranged in 256-bit blocks that can be configured as 32x8 or 64x4. SRAM modules can be cascaded together to form memory spaces of user-definable width and depth. A block diagram of the A42MX36 dual-port SRAM block is shown in Figure 5.

The A42MX36 SRAM modules are true dual-port structures containing independent read and write ports. Each SRAM module contains six bits of read and write addressing (RDAD[5:0] and WRAD[5:0], respectively) for 64x4-bit blocks. When configured in byte mode, the highest order address bits (RDAD5 and WRAD5) are not used. The read and write ports of the SRAM block contain independent clocks (RCLK and WCLK) with programmable polarities

offering active HIGH or LOW implementation. The SRAM block contains eight data inputs (WD[7:0]), and eight outputs (RD[7:0]), which are connected to segmented vertical routing tracks.

The A42MX36 dual-port SRAM blocks provide an optimal solution for high-speed buffered applications requiring FIFO and LIFO queues. The ACTgen Macro Builder within Actel's Designer software provides capability to quickly design memory functions with the SRAM blocks. Unused SRAM blocks can be used to implement registers for other user logic within the design.

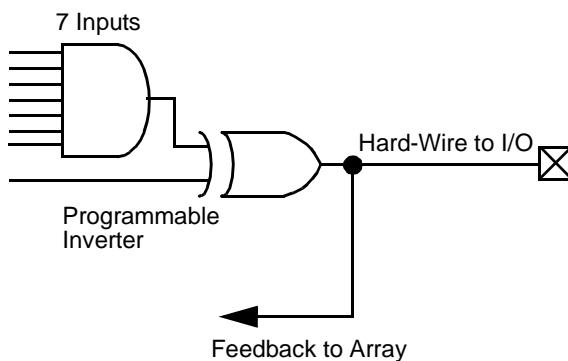


Figure 4 • A42MX24 and A42MX36 D-Module Implementation

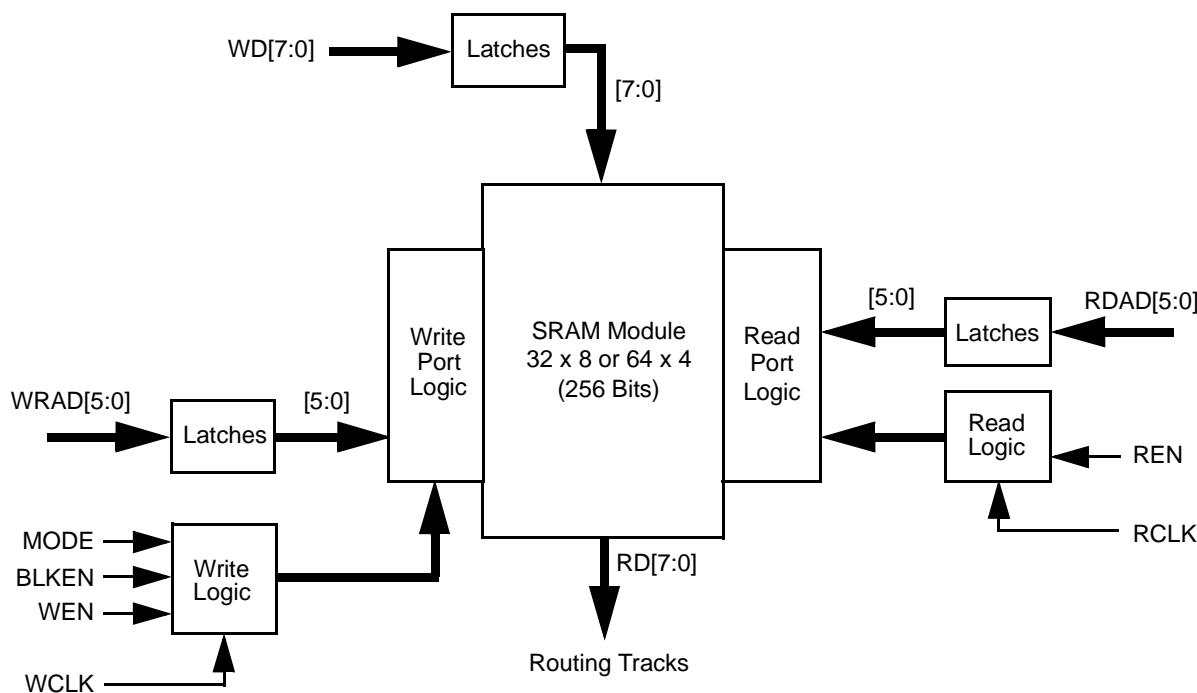


Figure 5 • A42MX36 Dual-Port SRAM Block

Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in Figure 6. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

Vertical Routing

Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing. Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 6.

Antifuse Structures

An antifuse is a "normally open" structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

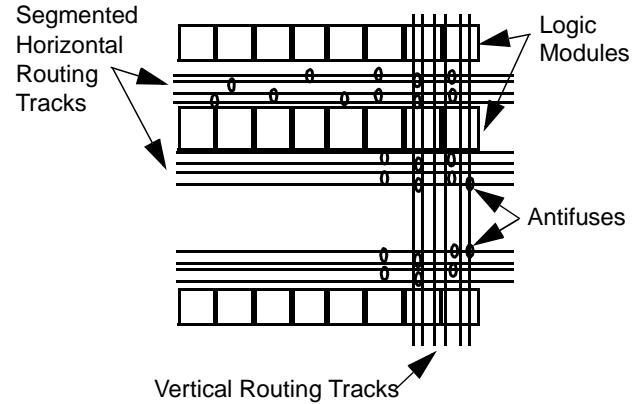


Figure 6 • MX Routing Structure

Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 7 on page 8):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 8 on page 8). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

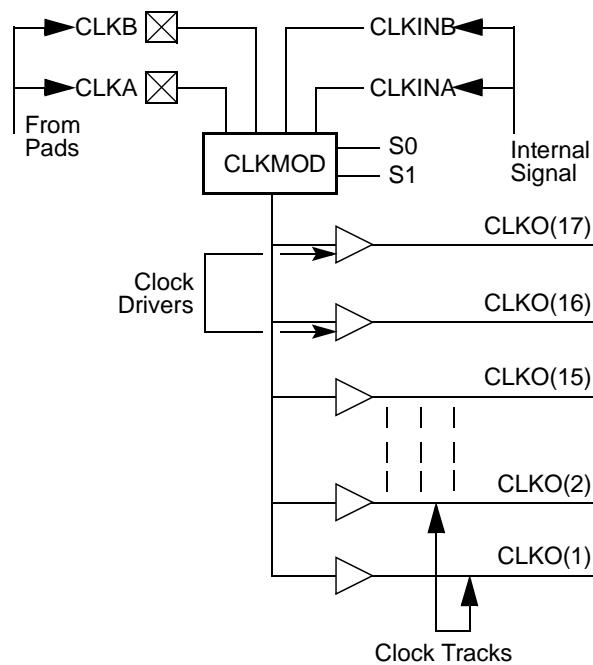
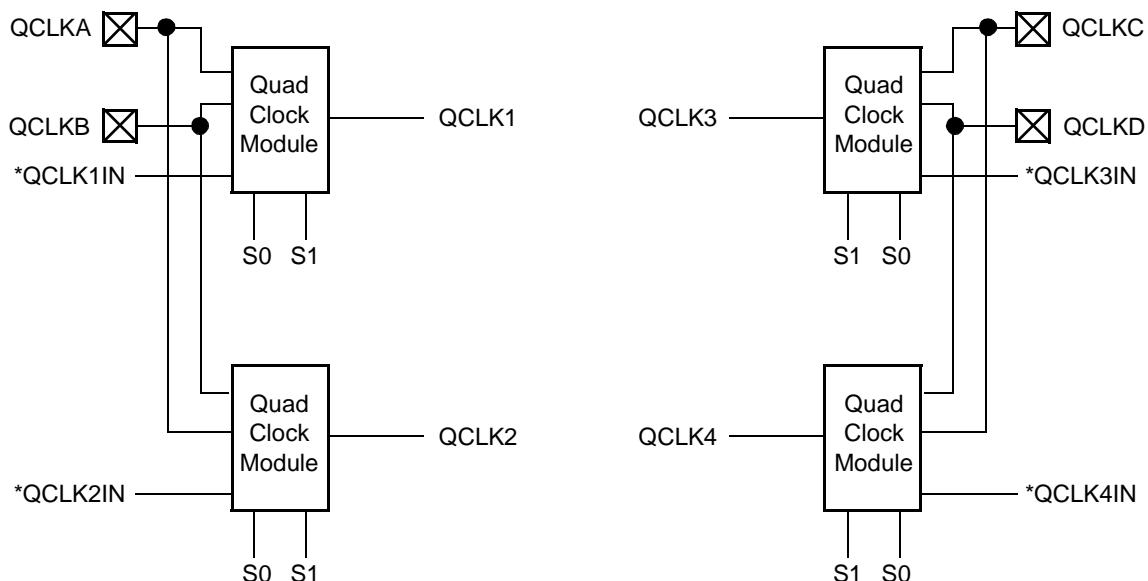


Figure 7 • Clock Networks of 42MX Devices



*QCLK1IN, QCLK2IN, QCLK3IN, and QCLK4IN are internally-generated signals.

Figure 8 • Quadrant Clock Network of A42MX36 Devices

MultiPlex I/O Modules

42MX devices feature Multiplex I/Os and support 5.0V, 3.3V, and mixed 3.3V/5.0V operations.

The MultiPlex I/O modules provide the interface between the device pins and the logic array. [Figure 9](#) is a block diagram of the 42MX I/O module. A variety of user functions, determined by a library macro selection, can be implemented in the module. (Refer to the [Antifuse Macro Library Guide](#) for more information.) All 42MX I/O modules contain tristate buffers, with input and output latches that can be configured for input, output, or bidirectional operation.

All 42MX devices contain flexible I/O structures, where each output pin has a dedicated output-enable control ([Figure 9](#)). The I/O module can be used to latch input or output data, or both, providing fast set-up time. In addition, the Actel Designer software tools can build a D-type flip-flop using a C-module combined with an I/O module to register input and output signals. Refer to the [Antifuse Macro Library Guide](#) for more details.

A42MX24 and A42MX36 devices also offer selectable PCI output drives, enabling 100% compliance with version 2.1 of the PCI specification. For low-power systems, all inputs and outputs are turned off to reduce current consumption to below 500 μ A.

To achieve 5.0V or 3.3V PCI-compliant output drives on A42MX24 and A42MX36 devices, a chip-wide PCI fuse is programmed via the Device Selection Wizard in the Designer software ([Figure 10](#)). When the PCI fuse is not programmed, the output drive is standard.

Actel's Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

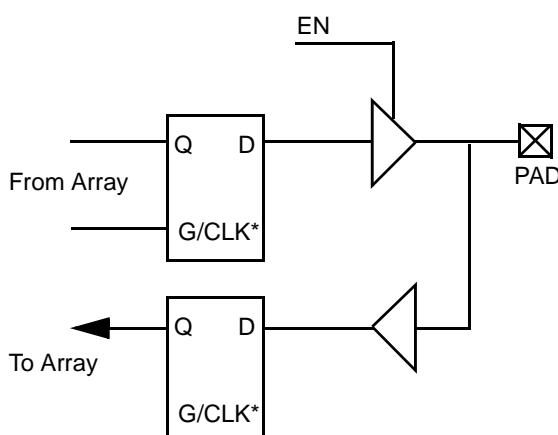


Figure 9 • 42MX I/O Module

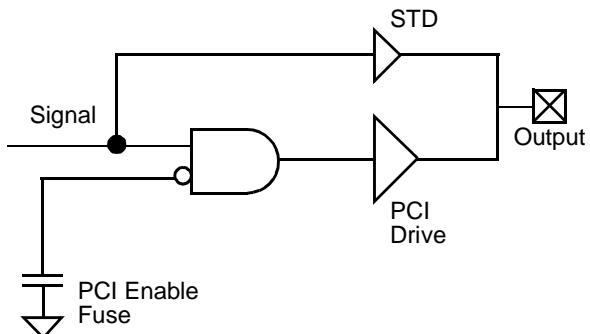


Figure 10 • PCI Output Structure of A42MX24 and A42MX36 Devices

Other Architectural Features

Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

User Security

The Actel FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and prevent unauthorized users from accessing the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Actel antifuse FPGAs immune to both invasive and noninvasive attacks.

Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

Look for this symbol to ensure your valuable IP is secure.

For more information, refer to [Actel's Implementation of Security in Actel Antifuse FPGAs](#) application note.



Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor II is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor II is designed to allow concurrent programming of multiple units from the same PC.

Silicon Sculptor II programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and nonprogrammed), Silicon Sculptor II also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor II is as follows:

Table 1 • Voltage Support of MX Devices

Device	V _{CC}	V _{CCA}	V _{CCI}	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0V	–	–	5.5V	5.0V
	3.3V	–	–	3.6V	3.3V
42MX	–	5.0V	5.0V	5.5V	5.0V
	–	3.3V	3.3V	3.6V	3.3V
	–	5.0V	3.3V	5.5V	3.3V

Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode ($V_{CCA} = 5.0V$ and $V_{CCI} = 3.3V$), V_{CCA} must be greater than or equal to V_{CCI} throughout the power-up sequence. If V_{CCI} exceeds V_{CCA} during power up, either the I/Os' input protection junction on the I/Os will be forward-biased or the I/Os will be at logical HIGH, and I_{CC} rises to high levels. For power-down, any sequence with V_{CCA} and V_{CCI} can be implemented.

1. Load the .AFM file

2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, please refer to the [Programming Actel Devices](#) and the [Silicon Sculptor II](#) user's guides.

Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0V/3.3V systems. **Table 1** describes the voltage support of MX devices.

Low Power Mode

42MX devices have been designed with a Low Power Mode. This feature, activated with setting the special LP pin to HIGH for a period longer than 800 ns, is particularly useful for battery-operated systems where battery life is a primary concern. In this mode, the core of the device is turned off and the device consumes minimal power with low standby current. In addition, all input buffers are turned off, and all outputs and bidirectional buffers are tristated. Since the core of the device is turned off, the states of the registers are lost. The device must be re-initialized when exiting Low Power Mode. I/Os can be driven during LP mode, and clock pins should be driven HIGH or LOW and should not float to avoid drawing current. To exit LP mode, the LP pin must be pulled LOW for over 200 μ s to allow for charge pumps to power up, and device initialization will begin.

Power Dissipation

The general power consumption of MX devices is made up of static and dynamic power and can be expressed with the following equation:

General Power Equation

$$P = [I_{CC\text{standby}} + I_{CC\text{active}}] * V_{CC1} + I_{OL} * V_{OL} * N + I_{OH} * (V_{CC1} - V_{OH}) * M$$

where:

$I_{CC\text{standby}}$ is the current flowing when no inputs or outputs are changing.

$I_{CC\text{active}}$ is the current flowing due to CMOS switching.

I_{OL}, I_{OH} are TTL sink/source currents.

V_{OL}, V_{OH} are TTL level output voltages.

N equals the number of outputs driving TTL loads to V_{OL} .

M equals the number of outputs driving TTL loads to V_{OH} .

Accurate values for N and M are difficult to determine because they depend on the family type, on design details, and on the system I/O. The power can be divided into two components: static and active.

Static Power Component

The static power due to standby current is typically a small component of the overall power consumption. Standby power is calculated for commercial, worst-case conditions. The static power dissipation by TTL loads depends on the number of outputs driving, and on the DC load current. For instance, a 32-bit bus sinking 4mA at 0.33V will generate 42mW with all outputs driving LOW, and 140mW with all outputs driving HIGH. The actual dissipation will average somewhere in between, as I/Os switch states with time.

Active Power Component

Power dissipation in CMOS devices is usually dominated by the dynamic power dissipation. Dynamic power consumption is frequency-dependent and is a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitances due to PC board traces and load device inputs. An additional component of the active power dissipation is the totem pole current in the CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

The power dissipated by a CMOS circuit can be expressed by the equation:

$$\text{Power } (\mu\text{W}) = C_{EQ} * V_{CCA}^2 * F \quad (1)$$

where:

C_{EQ} = Equivalent capacitance expressed in picofarads (pF)

V_{CCA} = Power supply in volts (V)

F = Switching frequency in megahertz (MHz)

Equivalent Capacitance

Equivalent capacitance is calculated by measuring $I_{CC\text{active}}$ at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of V_{CC} . Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

C_{EQ} Values for Actel MX FPGAs

Modules (C_{EQM})	3.5
Input Buffers (C_{EQI})	6.9
Output Buffers (C_{EQO})	18.2
Routed Array Clock Buffer Loads (C_{EQCR})	1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\text{Power} = V_{CCA}^2 * [(m * C_{EQM} * f_m)_{\text{Modules}} + (n * C_{EQI} * f_n)_{\text{Inputs}} + (p * (C_{EQO} + C_L) * f_p)_{\text{outputs}} + 0.5 * (q_1 * C_{EQCR} * f_{q1})_{\text{routed_Clk1}} + (r_1 * f_{q1})_{\text{routed_Clk1}} + 0.5 * (q_2 * C_{EQCR} * f_{q2})_{\text{routed_Clk2}} + (r_2 * f_{q2})_{\text{routed_Clk2}}} \quad (2)$$

where:

m = Number of logic modules switching at frequency f_m

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

q_1 = Number of clock loads on the first routed array clock

q_2 = Number of clock loads on the second routed array clock

r_1 = Fixed capacitance due to first routed array clock

r_2 = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

f_{q2} = Average second routed array clock rate in MHz

Fixed Capacitance Values for MX FPGAs (pF)

Device Type	r_1 routed_Clk1	r_2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

Test Circuitry and Silicon Explorer II Probe
 MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully

functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 11 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 12 on page 13 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (Refer to "User Security" section on page 9 for the security fuses of 40MX and 42MX devices). Table 2 on page 13 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the "Reserve Probe Pin" is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and "Reserve Probe Pin" is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

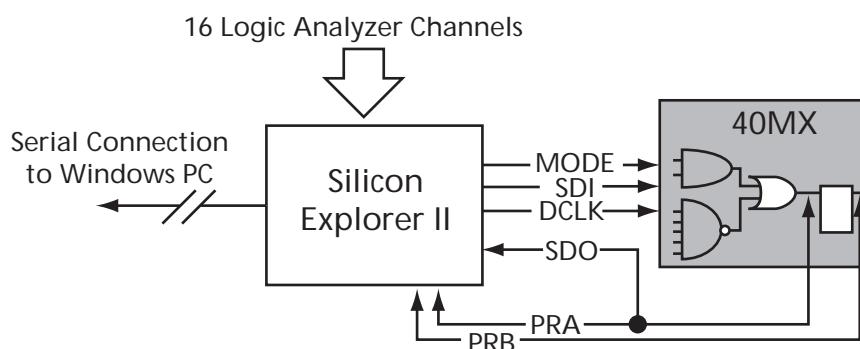
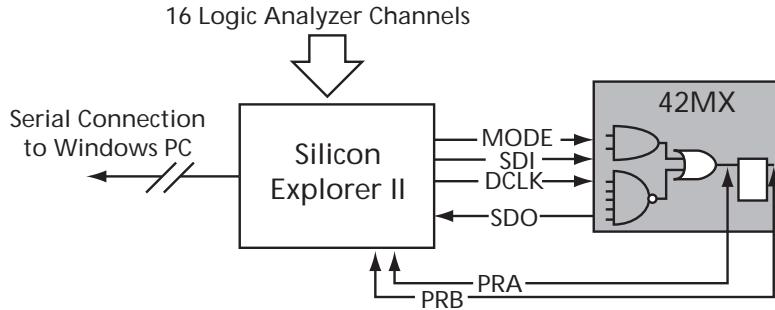


Figure 11 • Silicon Explorer II Setup with 40MX

**Figure 12 • Silicon Explorer II Setup with 42MX****Table 2 • Device Configuration Options for Probe Capability**

Security Fuse(s) Programmed	MODE	PRA, PRB ¹	SDI, SDO, DCLK ¹
No	LOW	User I/Os ²	User I/Os ²
No	HIGH	Probe Circuit Outputs	Probe Circuit Inputs
Yes	—	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. Avoid using SDI, SDO, DCLK, PRA and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
2. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. See the “Pin Descriptions” section on page 80 for information on unused I/O pins.

Design Consideration

It is recommended to use a series 70Ω termination resistor on every probe connector (SDI, SDO, MODE, DCLK, PRA and PRB). The 70Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

IEEE Standard 1149.1 Boundary Scan Test (BST) Circuitry

42MX24 and 42MX36 devices are compatible with IEEE Standard 1149.1 (informally known as Joint Testing Action Group Standard or JTAG), which defines a set of hardware architecture and mechanisms for cost-effective board-level testing. The basic MX boundary-scan logic circuit is composed of the TAP (test access port), TAP controller, test data registers and instruction register (Figure 13 on page 14). This circuit supports all mandatory IEEE 1149.1 instructions (EXTEST, SAMPLE/PRELOAD and BYPASS) and some optional instructions. Table 3 on page 14 describes the ports that control JTAG testing, while Table 4 on page 14 describes the test instructions supported by these MX devices.

Each test section is accessed through the TAP, which has four associated pins: TCK (test clock input), TDI and TDO (test data input and output), and TMS (test mode selector).

The TAP controller is a four-bit state machine. The '1's and '0's represent the values that must be present at TMS at a

rising edge of TCK for the given state transition to occur. IR and DR indicate that the instruction register or the data register is operating in that state.

The TAP controller receives two control inputs (TMS and TCK) and generates control and clock signals for the rest of the test logic architecture. On power-up, the TAP controller enters the Test-Logic-Reset state. To guarantee a reset of the controller from any of the possible states, TMS must remain high for five TCK cycles.

42MX24 and 42MX36 devices support three types of test data registers: bypass, device identification, and boundary scan. The bypass register is selected when no other register needs to be accessed in a device. This speeds up test data transfer to other devices in a test data path. The 32-bit device identification register is a shift register with four fields (lowest significant byte (LSB), ID number, part number and version). The boundary-scan register observes and controls the state of each I/O pin.

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

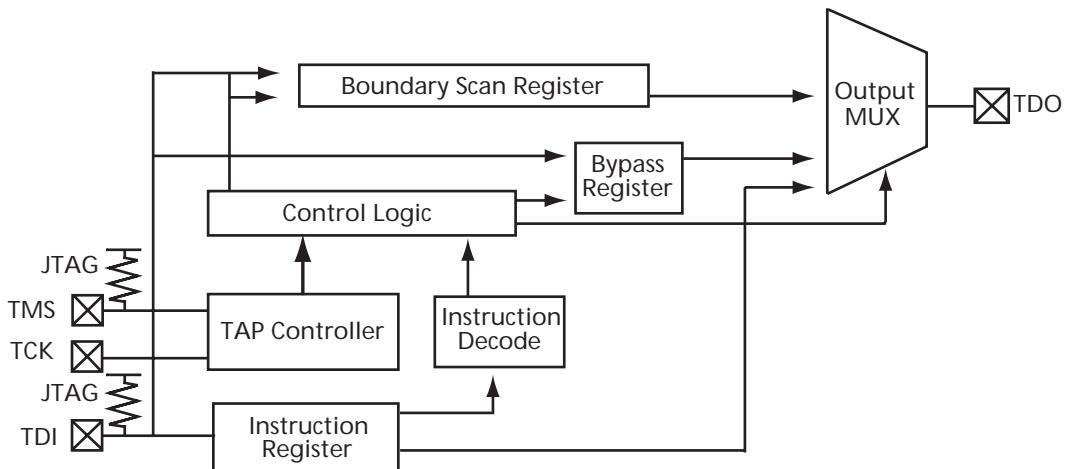


Figure 13 • 42MX IEEE 1149.1 Boundary Scan Circuitry

Table 3 • Test Access Port Descriptions

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 4 • Supported BST Public Instructions

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. Please refer to the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. Please refer to the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

JTAG Mode Activation

The JTAG test logic circuit is activated in the Designer software by selecting Tools -> Device Selection. This brings up the Device Selection dialog box as shown in [Figure 14](#). The JTAG test logic circuit can be enabled by clicking the "Reserve JTAG Pins" check box. [Table 5](#) explains the pins' behavior in either mode.



Figure 14 • Device Selection Wizard

Table 5 • Boundary Scan Pin Configuration and Functionality

Reserve JTAG	Checked	Unchecked
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating	User I/O
TDI, TMS	BST input; may float or be tied to HIGH	User I/O
TDO	BST output; may float or be connected to TDI of another device	User I/O

TRST Pin and TAP Controller Reset

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

Boundary Scan Description Language (BSDL) File

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, please refer to [Actel BSDL Files Format Description](#) application note.

Actel BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on Actel's website at <http://www.actel.com/techdocs/models/bsdl.html>.

Development Tool Support

The MX family of FPGAs is fully supported by both Actel's Libero™ Integrated Design Environment and Designer FPGA Development software. Actel Libero IDE is a design management environment that streamlines the design flow. Libero IDE provides an integrated design manager that seamlessly integrates design tools while guiding the user through the design flow, managing all design and log files,

and passing necessary design data among tools. Additionally, Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw for Actel from Mentor Graphics, ModelSim™ HDL Simulator from Mentor Graphics®, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the [Libero IDE flow](#) (located on Actel's website) diagram for more information.

Actel's Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can lock his/her design pins before layout while minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Actel's integrated verification and logic analysis tool. Another tool included in the Designer software is the ACTgen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel's Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys, and Cadence Design Systems. The Designer software is available for both the Windows and UNIX operating systems.

Actel's Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys, and Cadence Design Systems. The Designer software is available for both the Windows and UNIX operating systems.

Related Documents

Application Notes

Actel BSDL Files Format Description

<http://www.actel.com/documents/BSDLformat.pdf>

Programming Actel Devices

<http://www.actel.com/documents/ProgrammingGuide.pdf>

User's Guides and Manuals

Antifuse Macro Library Guide

<http://www.actel.com/documents/libguide.pdf>

Actel's Implementation of Security in Actel Antifuse FPGAs

<http://www.actel.com/documents/AntifuseSecurityAN.pdf>

Silicon Sculptor II

<http://www.actel.com/techdocs/manuals/default.asp#programmers>

Miscellaneous

Libero IDE Flow Diagram

<http://www.actel.com/products/tools/libero/flow.html>

5.0V Operating Conditions

Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
V_{CC}	DC Supply Voltage	-0.5 to +7.0	V
V_I	Input Voltage	-0.5 to $V_{CC}+0.5$	V
V_O	Output Voltage	-0.5 to $V_{CC}+0.5$	V
t_{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the Recommended Operating Conditions.

Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	-0.5 to +7.0	V
V_{CCA}	DC Supply Voltage for Array	-0.5 to +7.0	V
V_I	Input Voltage	-0.5 to $V_{CCI}+0.5$	V
V_O	Output Voltage	-0.5 to $V_{CCI}+0.5$	V
t_{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the Recommended Operating Conditions.

Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	-40 to +85	-55 to +125	°C
V_{CC} (40MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
V_{CCA} (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
V_{CCI} (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

5V TTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		'Industrial		Military		Units
		Min.	Max	Min.	Max	Min.	Max	Min.	Max	
V_{OH}^1	$I_{OH} = -10\text{mA}$	2.4		2.4						V
	$I_{OH} = -4\text{mA}$					3.7		3.7		V
V_{OL}^1	$I_{OL} = 10\text{mA}$		0.5		0.5					V
	$I_{OL} = 6\text{mA}$						0.4		0.4	V
V_{IL}		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
V_{IH} (40MX)		2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	V
V_{IH} (42MX)		2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	V
I_{IL}	$V_{IN} = 0.5\text{V}$		-10		-10		-10		-10	μA
I_{IH}	$V_{IN} = 2.7\text{V}$		-10		-10		-10		-10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, I_{CC}^2	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low-Power Mode Standby Current	42MX devices only		0.5		$I_{CC} - 5.0$		$I_{CC} - 5.0$		$I_{CC} - 5.0$	mA
I_{IO} , I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.actel.com/techdocs/models/ibis.html)									

Notes:

1. Only one output tested at a time. $V_{CC}/V_{CCI} = \text{min.}$
2. All outputs unloaded. All inputs = V_{CC}/V_{CCI} or GND.

3.3V Operating Conditions

Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
V_{CC}	DC Supply Voltage	-0.5 to +7.0	V
V_I	Input Voltage	-0.5 to $V_{CC}+0.5$	V
V_O	Output Voltage	-0.5 to $V_{CC}+0.5$	V
t_{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the Recommended Operating Conditions.

Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	-0.5 to +7.0	V
V_{CCA}	DC Supply Voltage for Array	-0.5 to +7.0	V
V_I	Input Voltage	-0.5 to $V_{CCI}+0.5$	V
V_O	Output Voltage	-0.5 to $V_{CCI}+0.5$	V
t_{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the Recommended Operating Conditions.

Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	-40 to +85	-55 to +125	°C
V_{CC} (40MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
V_{CCA} (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
V_{CCI} (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

3.3V LVTTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max	Min.	Max	Min.	Max	Min.	Max	
V_{OH}^1	$I_{OH} = -4mA$	2.15		2.15		2.4		2.4		V
V_{OL}^1	$I_{OL} = 6mA$		0.4		0.4		0.48		0.48	V
V_{IL}		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
V_{IH} (40MX)		2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	2.0	$V_{CC}+0.3$	V
V_{IH} (42MX)		2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	V
I_{IL}			-10		-10		-10		-10	μA
I_{IH}			-10		-10		-10		-10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, I_{CC}^2	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		15		25		25		25	mA
Low-Power Mode Standby Current	42MX devices only		0.5		$I_{CC} - 5.0$		$I_{CC} - 5.0$		$I_{CC} - 5.0$	mA
I_{IO} , I/O source sink current	Can be derived from the IBIS model (http://www.actel.com/techdocs/models/ibis.html)									

Notes:

1. Only one output tested at a time. $V_{CC}/V_{CCI} = \text{min.}$
2. All outputs unloaded. All inputs = V_{CC}/V_{CCI} or GND.

Mixed 5.0V/3.3V Operating Conditions (for 42MX devices only)

Absolute Maximum Ratings*

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	-0.5 to +7.0	V
V_{CCA}	DC Supply Voltage for Array	-0.5 to +7.0	V
V_I	Input Voltage	-0.5 to $V_{CCI}+0.5$	V
V_O	Output Voltage	-0.5 to $V_{CCI}+0.5$	V
t_{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the Recommended Operating Conditions.

Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	-40 to +85	-55 to +125	°C
V_{CCA}	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
V_{CCI}	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

Mixed 5.0V/3.3V Electrical Specifications

Symbol	Parameter	Commercial		Commercial '-F		'Industrial		Military		Units
		Min.	Max	Min.	Max	Min.	Max	Min.	Max	
V_{OH}^1	$I_{OH} = -10\text{mA}$	2.4		2.4						V
	$I_{OH} = -4\text{mA}$					3.7		3.7		V
V_{OL}^1	$I_{OL} = 10\text{mA}$		0.5		0.5					V
	$I_{OL} = 6\text{mA}$						0.4		0.4	V
V_{IL}		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
V_{IH}		2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	2.0	$V_{CCI}+0.3$	V
I_L	$V_{IN} = 0.5\text{V}$		-10		-10		-10		-10	μA
I_H	$V_{IN} = 2.7\text{V}$		-10		-10		-10		-10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, I_{CC}^2	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low-Power Mode Standby Current			0.5		$I_{CC} - 5.0$		$I_{CC} - 5.0$		$I_{CC} - 5.0$	mA
I_{IO} I/O source sink current	Can be derived from the IBIS model (http://www.actel.com/techdocs/models/ibis.html)									

Notes:

1. Only one output tested at a time. $V_{CCI} = \text{min.}$
2. All outputs unloaded. All inputs = V_{CCI} or GND.

Output Drive Characteristics for 5.0V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 15 on page 24 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

DC Specification (5.0V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max	Min.	Max	
V_{CC1}	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
V_{IH}	Input High Voltage		2.0	$V_{CC} + 0.5$	2.0	$V_{CC1} + 0.3$	V
V_{IL}	Input Low Voltage		-0.5	0.8	-0.3	0.8	V
I_{IH}	Input High Leakage Current	$V_{IN} = 2.7V$		70	—	10	μA
I_{IL}	Input Low Leakage Current	$V_{IN}=0.5V$		-70	—	-10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -2 mA$ $I_{OUT} = -6 mA$	2.4		3.84		V
V_{OL}	Output Low Voltage	$I_{OUT} = 3 mA$, 6 mA		0.55	—	0.33	V
C_{IN}	Input Pin Capacitance			10	—	10	pF
C_{CLK}	CLK Pin Capacitance		5	12	—	10	pF
L_{PIN}	Pin Inductance			20	—	< 8 nH ³	nH

Notes:

1. PCI Local Bus Specification, Version 2.1, Section 4.2.1.1.
2. Maximum rating for V_{CC1} –0.5V to 7.0V.
3. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

AC Specifications (5.0V PCI Signaling)*

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max	Min.	Max	
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1) / 0.015$		-60	-10	mA
Slew (r)	Output Rise Slew Rate	0.4V to 2.4V load	1	5	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	2.4V to 0.4V load	1	5	2.8	4.3	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.1.2.

Output Drive Characteristics for 3.3V PCI Signaling

DC Specification (3.3V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max	Min.	Max	
V _{CCI}	Supply Voltage for I/Os		3.0	3.6	3.0	3.6	V
V _{IH}	Input High Voltage		0.5	V _{CC} + 0.5	0.5	V _{CCI} + 0.3	V
V _{IL}	Input Low Voltage		-0.5	0.8	-0.3	0.8	V
I _{IH}	Input High Leakage Current	V _{IN} = 2.7V		70		10	µA
I _{IL}	Input Leakage Current			-70		-10	µA
V _{OH}	Output High Voltage	I _{OUT} = -2 mA	0.9		3.3		V
V _{OL}	Output Low Voltage	I _{OUT} = 3 mA, 6 mA		0.1		0.1 V _{CCI}	V
C _{IN}	Input Pin Capacitance			10		10	pF
C _{CLK}	CLK Pin Capacitance		5	12		10	pF
L _{PIN}	Pin Inductance			20		< 8 nH ³	nH

Notes:

1. *PCI Local Bus Specification, Version 2.1, Section 4.2.2.1.*
2. Maximum rating for V_{CCI} –0.5V to 7.0V.
3. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

AC Specifications for (3.3V PCI Signaling)*

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max	Min.	Max	
I _{CL}	Low Clamp Current	-5 < V _{IN} ≤ -1	-25 + (V _{IN} + 1) / 0.015		-60	-10	mA
Slew (r)	Output Rise Slew Rate	0.2V to 0.6V load	1	4	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	0.6V to 0.2V load	1	4	2.8	4.0	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.2.2.

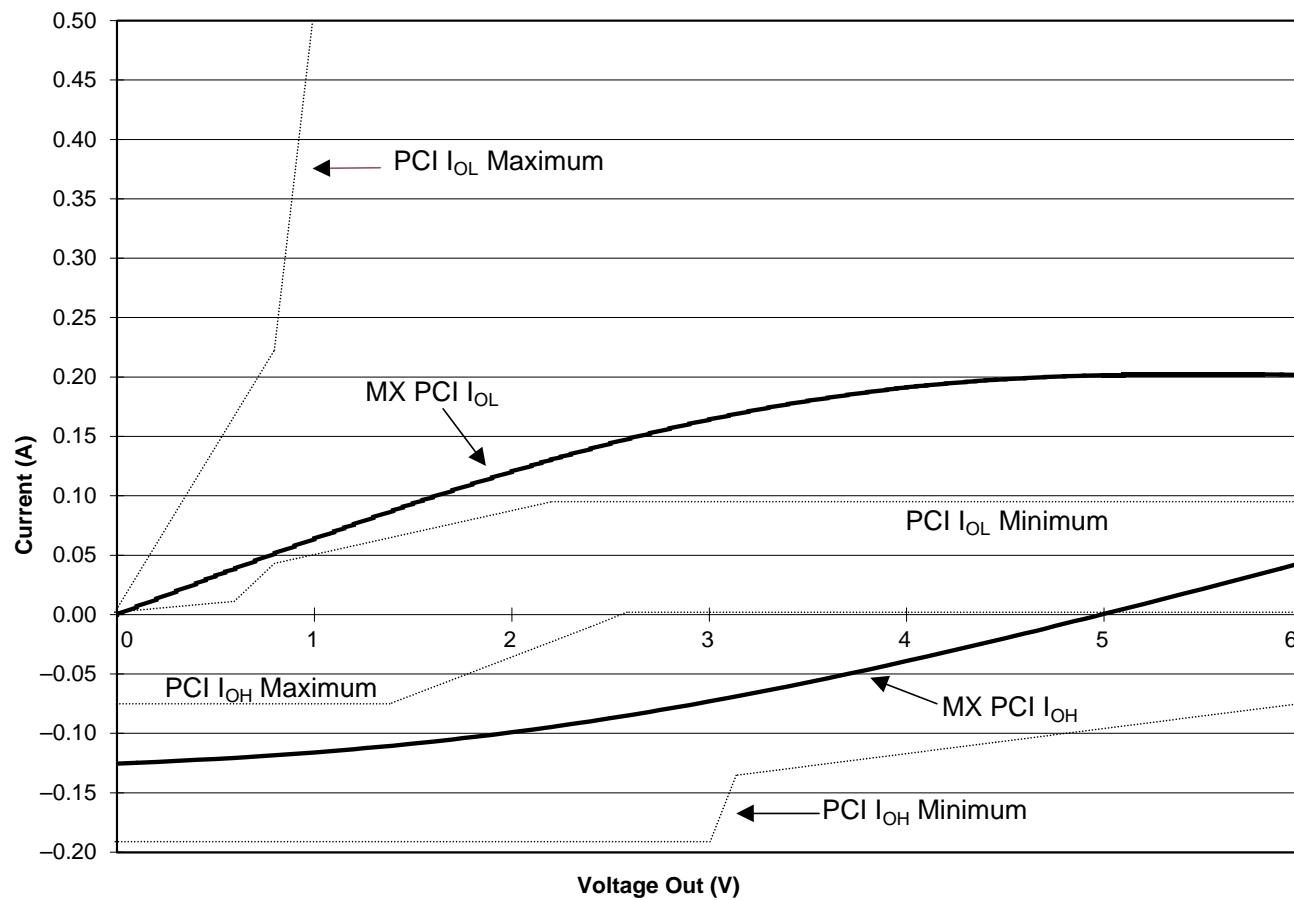


Figure 15 • Typical Output Drive Characteristics (based upon measured data)

Junction Temperature (T_J)

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because the heat generated from dynamic power consumption is usually hotter than the ambient temperature. Equation 1, shown below, can be used to calculate junction temperature.

$$\text{Junction Temperature} = \Delta T + T_a \quad (1)$$

Where:

T_a = Ambient Temperature

ΔT = Temperature gradient between junction (silicon) and ambient

$$\Delta T = \theta_{ja} * P \quad (2)$$

P = Power

θ_{ja} = Junction to ambient of package. θ_{ja} numbers are located in the Package Thermal Characteristics table below.

Package Thermal Characteristics

The device junction-to-case thermal characteristic is θ_{jc} , and the junction-to-ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

The maximum junction temperature is 150°C.

Maximum power dissipation for commercial- and industrial-grade devices is a function of θ_{ja} .

A sample calculation of the absolute maximum power dissipation allowed for a TQFP 176-pin package at commercial temperature and still air is as follows:

$$\text{Maximum Power Allowed} = \frac{\text{Max. junction temp. } (\text{°C}) - \text{Max. ambient temp. } (\text{°C})}{\theta_{ja} (\text{°C/W})} = \frac{150\text{°C} - 70\text{°C}}{28\text{°C/W}} = 2.86\text{W}$$

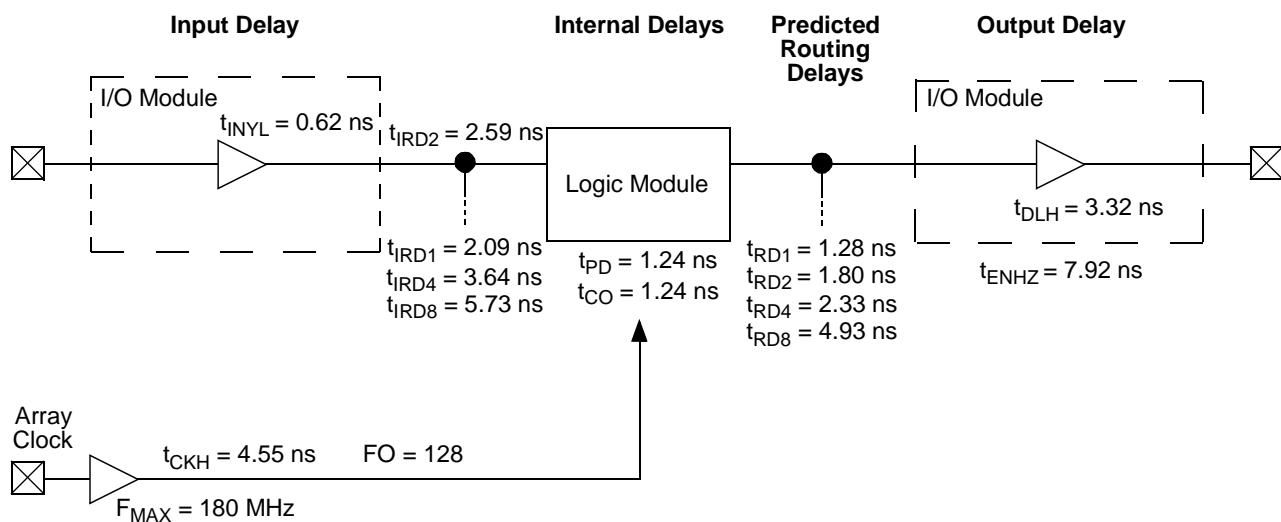
The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is as follows:

$$\text{Maximum Power Allowed} = \frac{\text{Max. junction temp. } (\text{°C}) - \text{Max. ambient temp. } (\text{°C})}{\theta_{jc} (\text{°C/W})} = \frac{150\text{°C} - 125\text{°C}}{6.3\text{°C/W}} = 3.97\text{W}$$

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min	2.5 m/s 500 ft/min	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W

Ceramic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min	2.5 m/s 500 ft/min	
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W

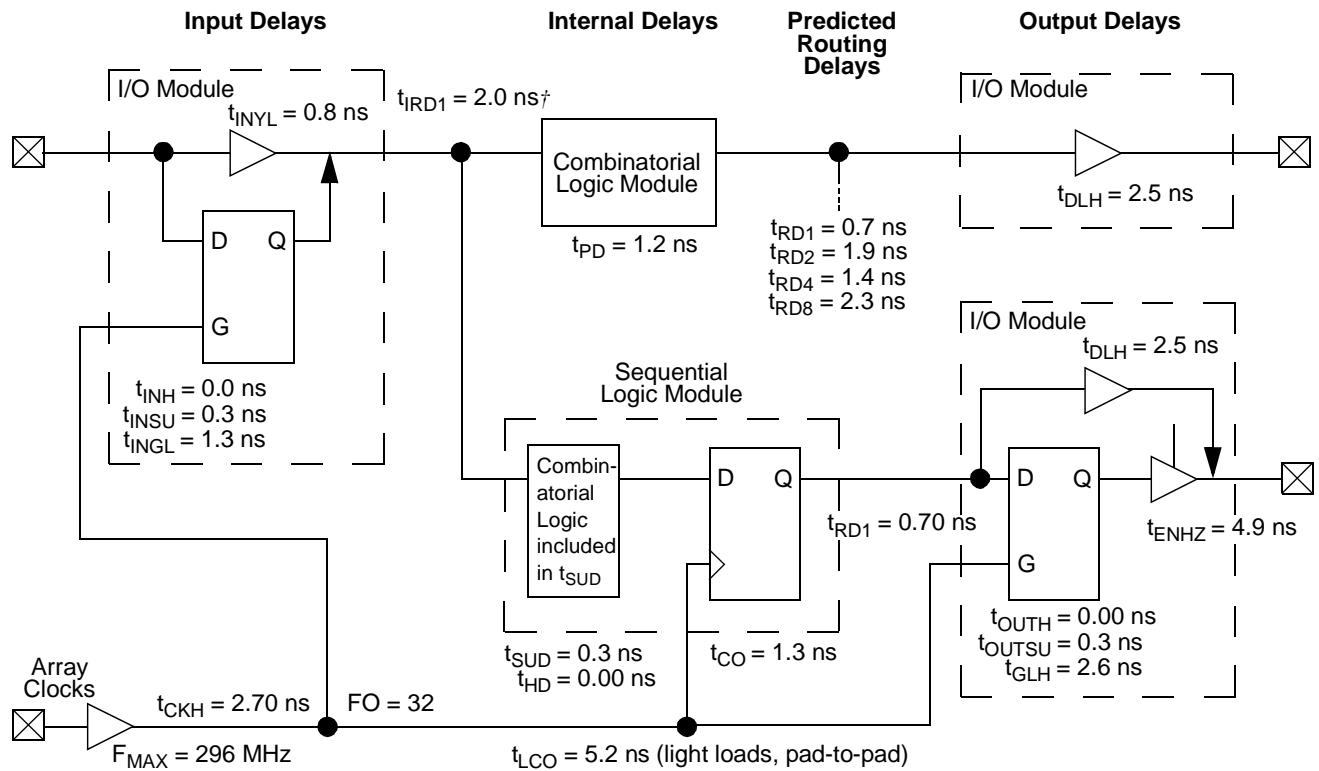
40MX Timing Model*



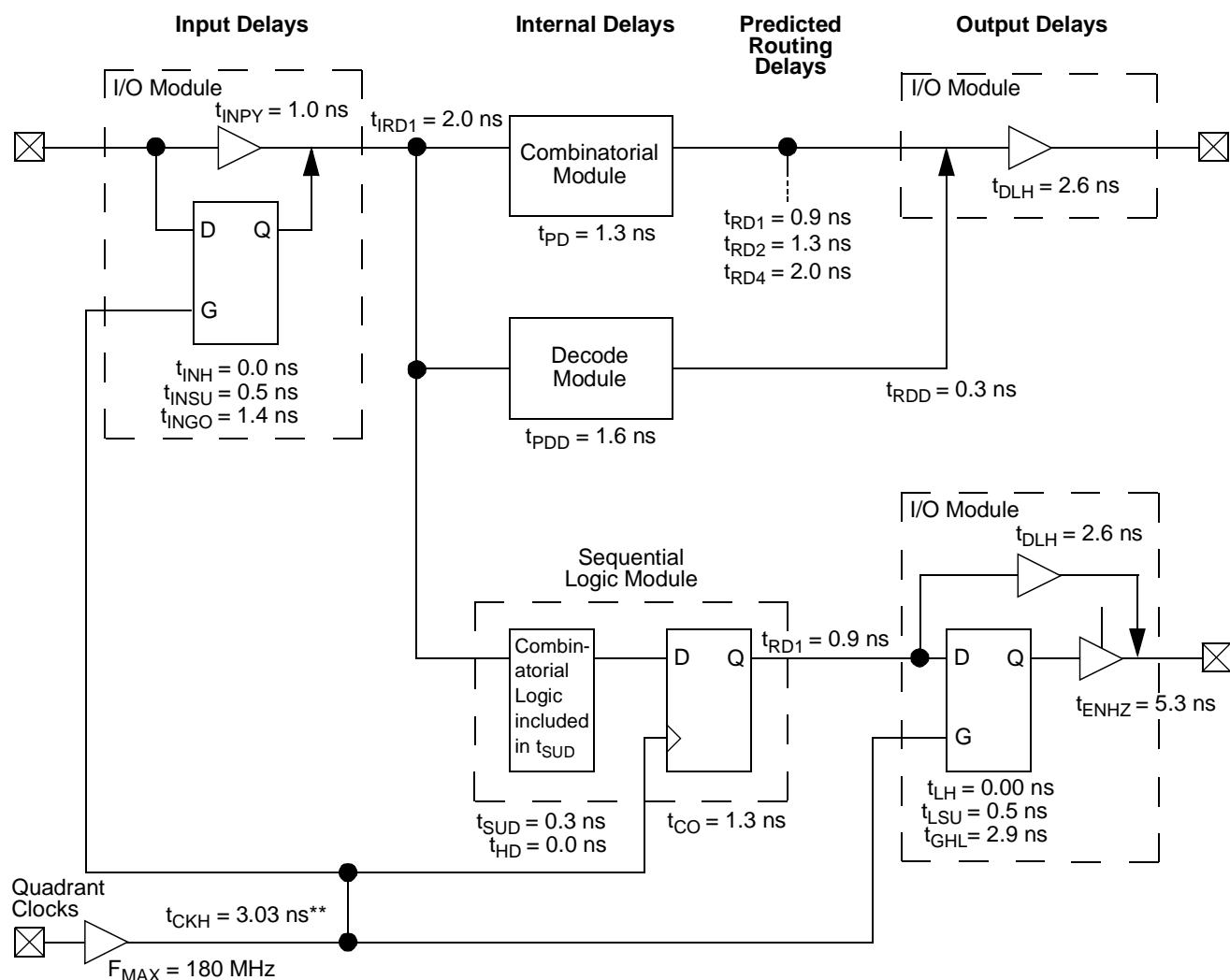
Note:

* Values are shown for 40MX '-3' speed devices at 5.0V worst-case commercial conditions.

42MX Timing Model*



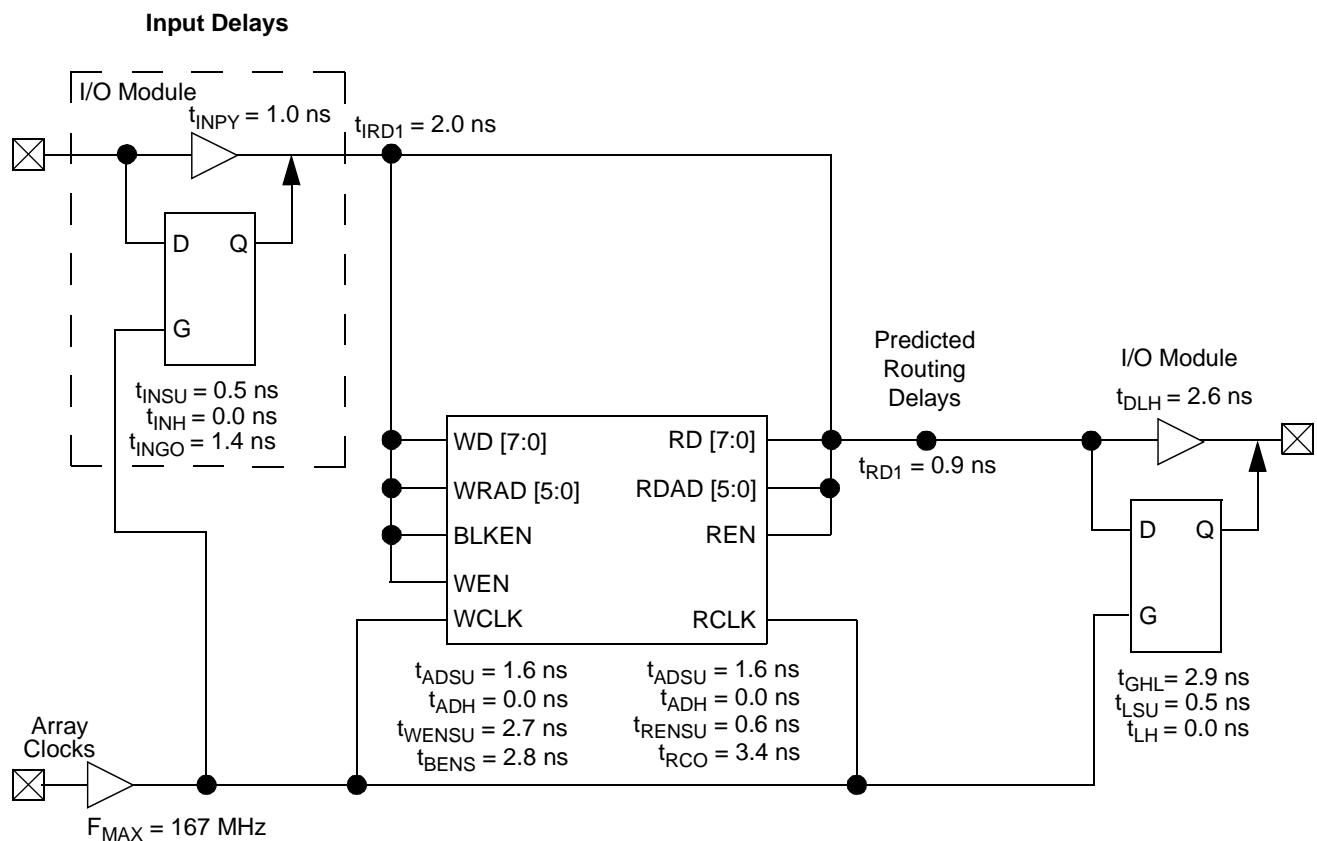
42MX Timing Model (Logic Functions using Quadrant Clocks)*


Notes:

* Values are shown for A42MX36 '-3' at 5.0V worst-case commercial conditions.

** Load-dependent

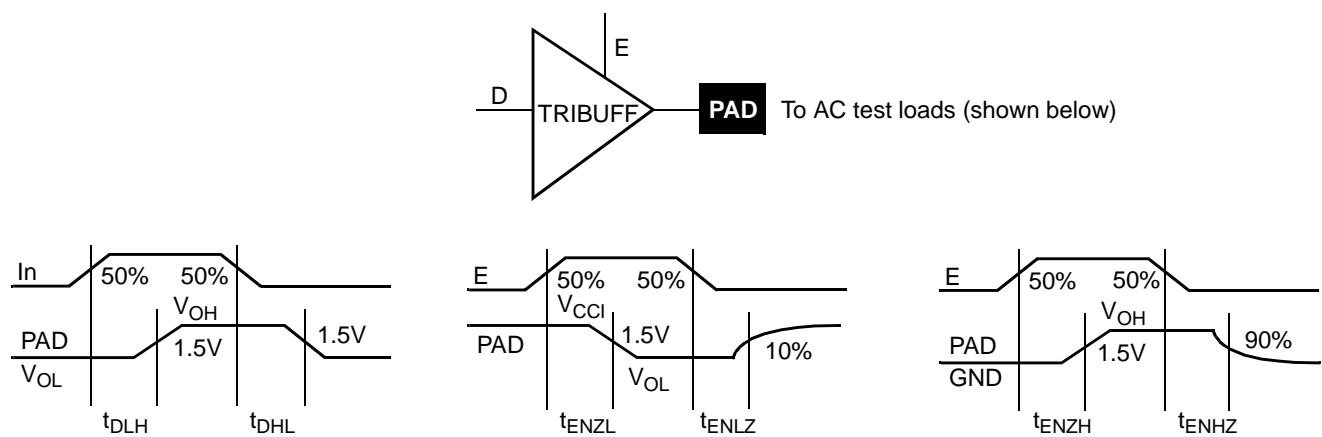
42MX Timing Model (SRAM Functions)*



Note: *Values are shown for A42MX36 -3 at 5.0V worst-case commercial conditions.

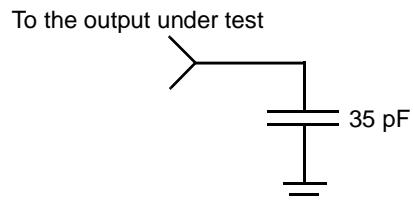
Parameter Measurement

Output Buffer Delays

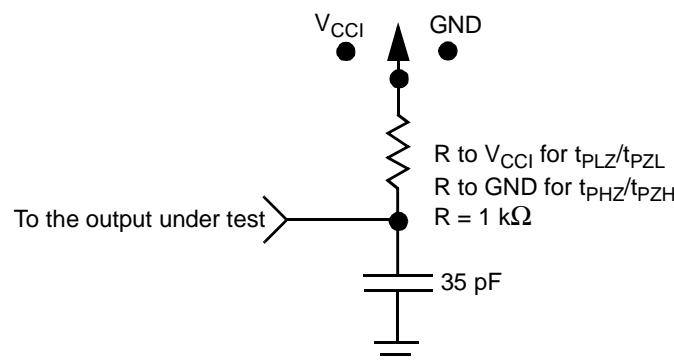


AC Test Loads

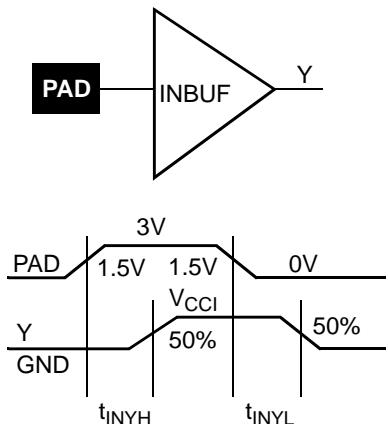
Load 1
(Used to measure propagation delay)



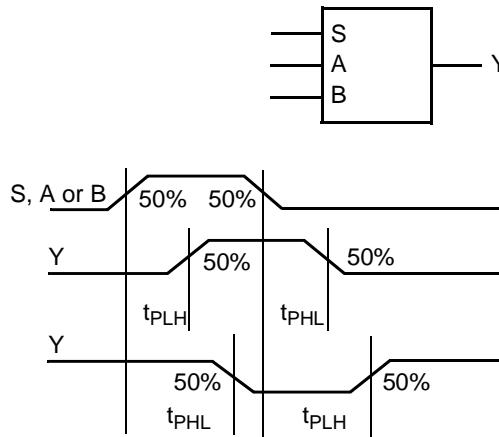
Load 2
(Used to measure rising/falling edges)



Input Buffer Delays

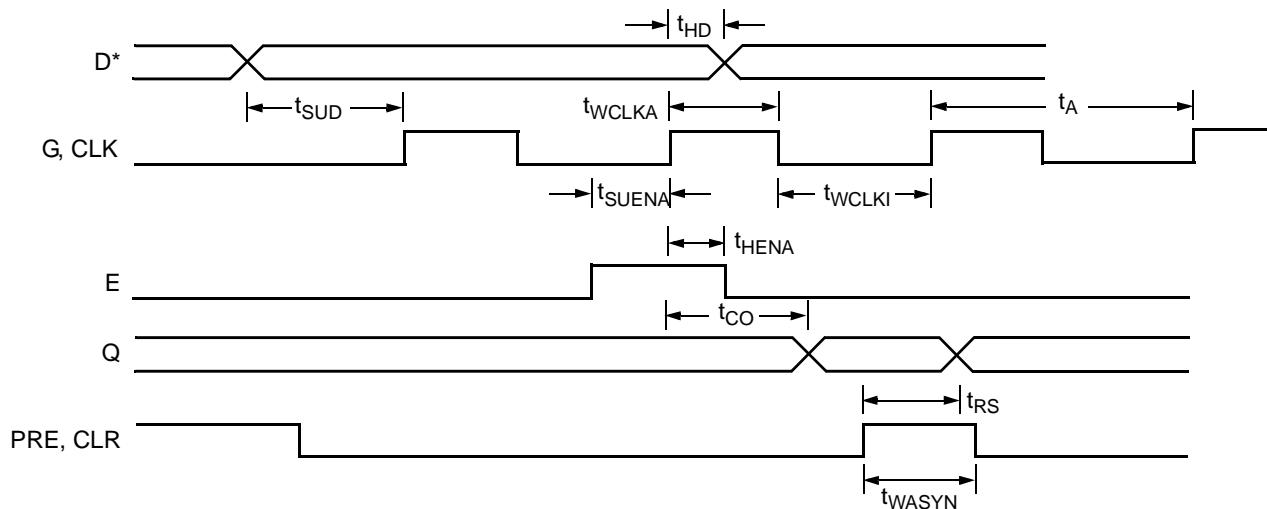
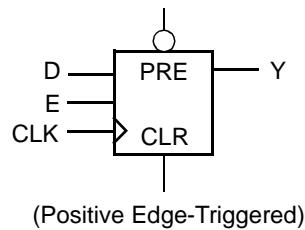


Module Delays



Sequential Module Timing Characteristics

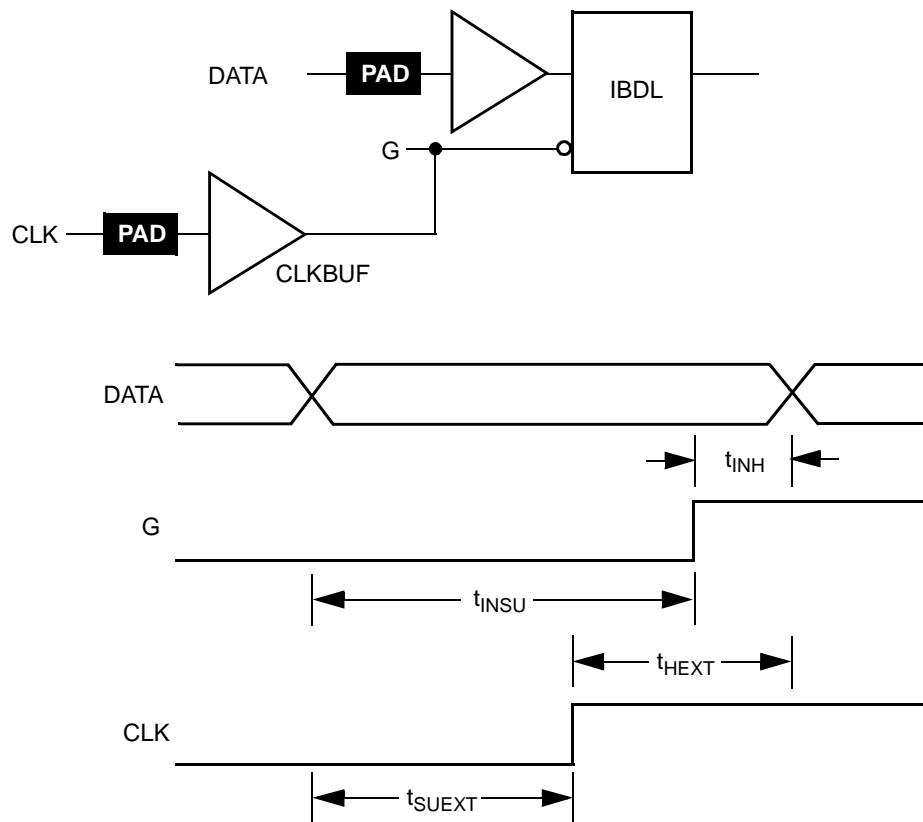
Flip-Flops and Latches



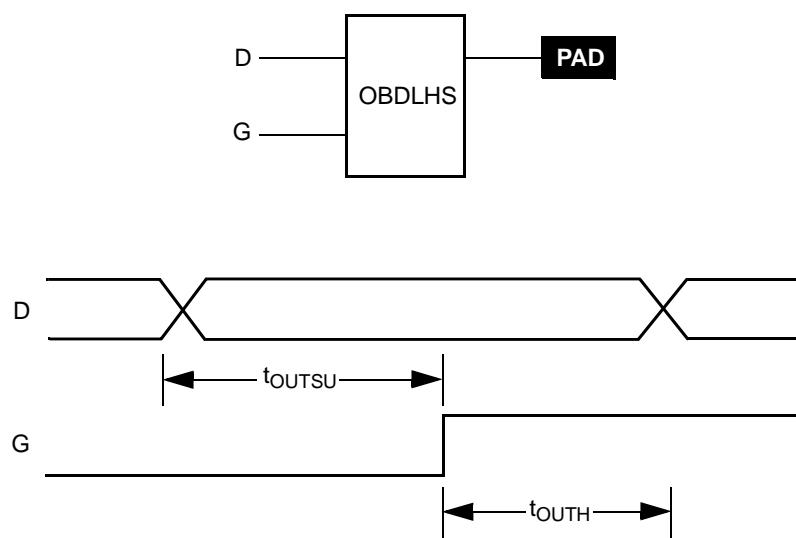
Note: *D represents all data functions involving A, B, and S for multiplexed flip-flops.

Sequential Timing Characteristics (continued)

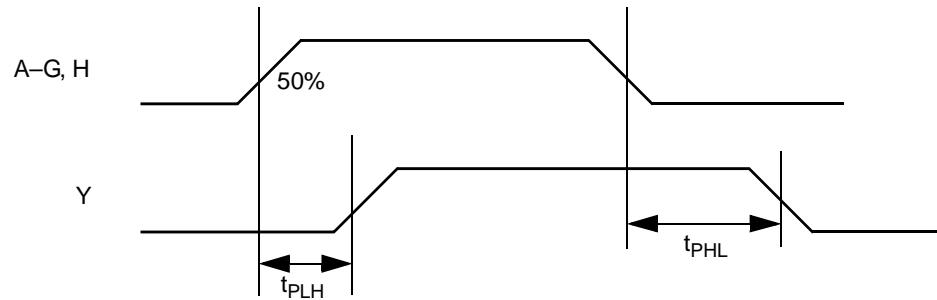
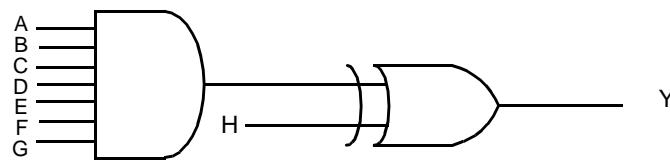
Input Buffer Latches



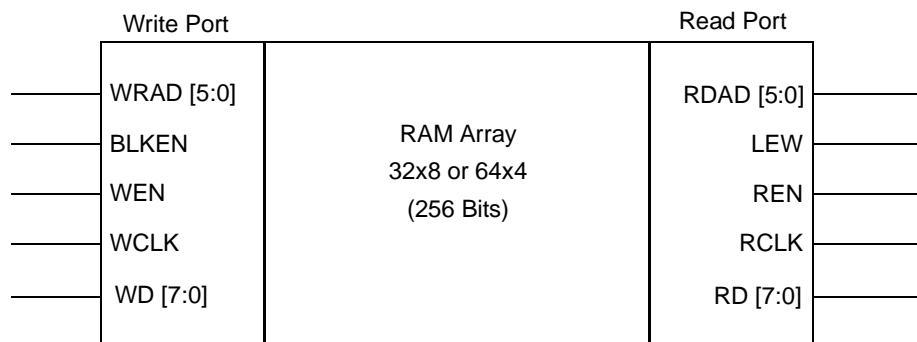
Output Buffer Latches



Decode Module Timing

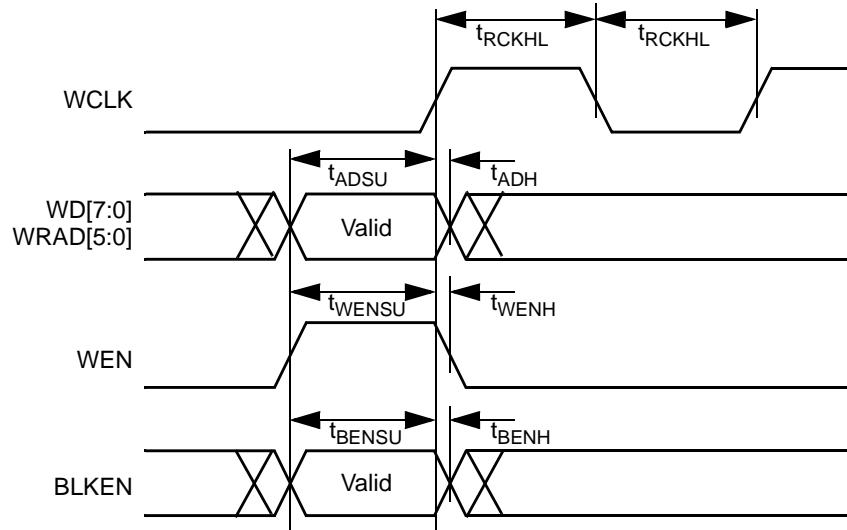


SRAM Timing Characteristics



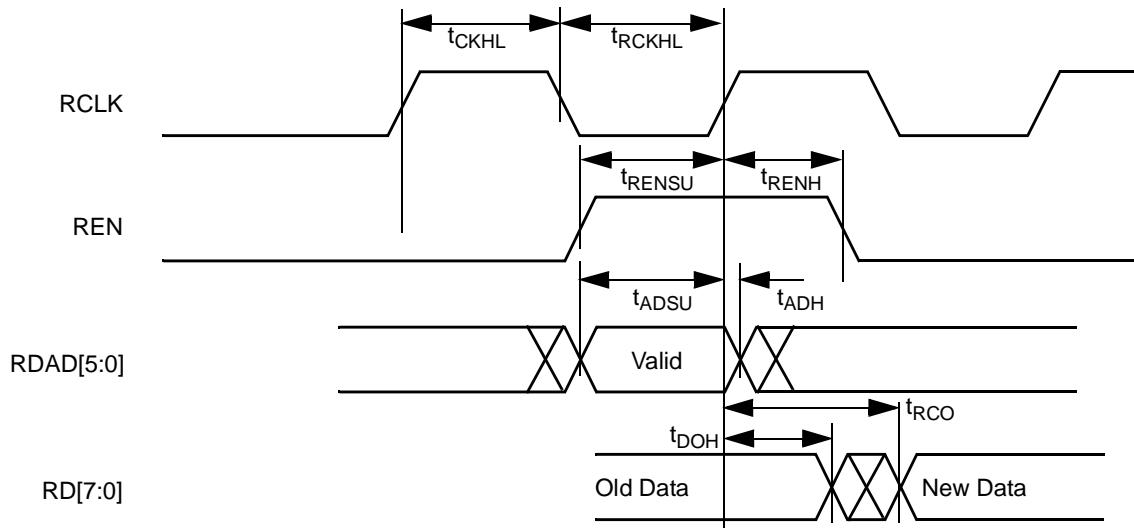
Dual-Port SRAM Timing Waveforms

42MX SRAM Write Operation



Note: Identical timing for falling edge clock.

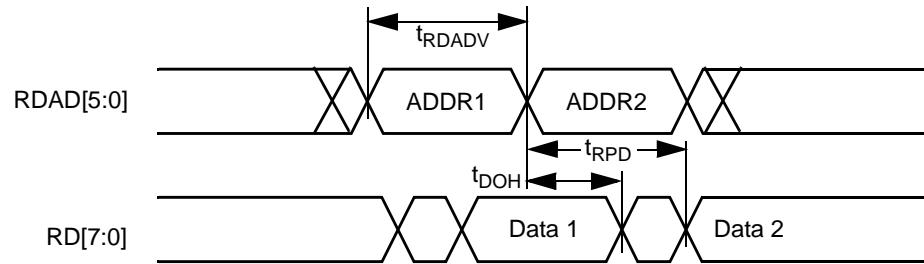
42MX SRAM Synchronous Read Operation



Note: Identical timing for falling edge clock.

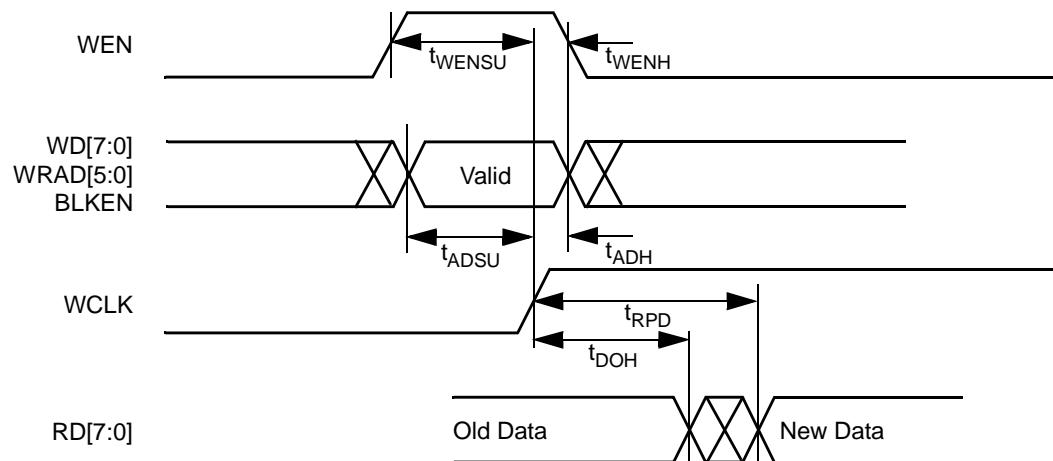
42MX SRAM Asynchronous Read Operation—Type 1

(Read Address Controlled)



42MX SRAM Asynchronous Read Operation—Type 2

(Write Address Controlled)



Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Actel's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 µm lithography, offer nominal levels of 100Ω resistance and 7.0fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Actel's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add approximately a 3 ns to a 6 ns delay, which is represented statistically in higher fanout (FO=8) routing delays in the data sheet specifications section, beginning on page 42.

Timing Derating

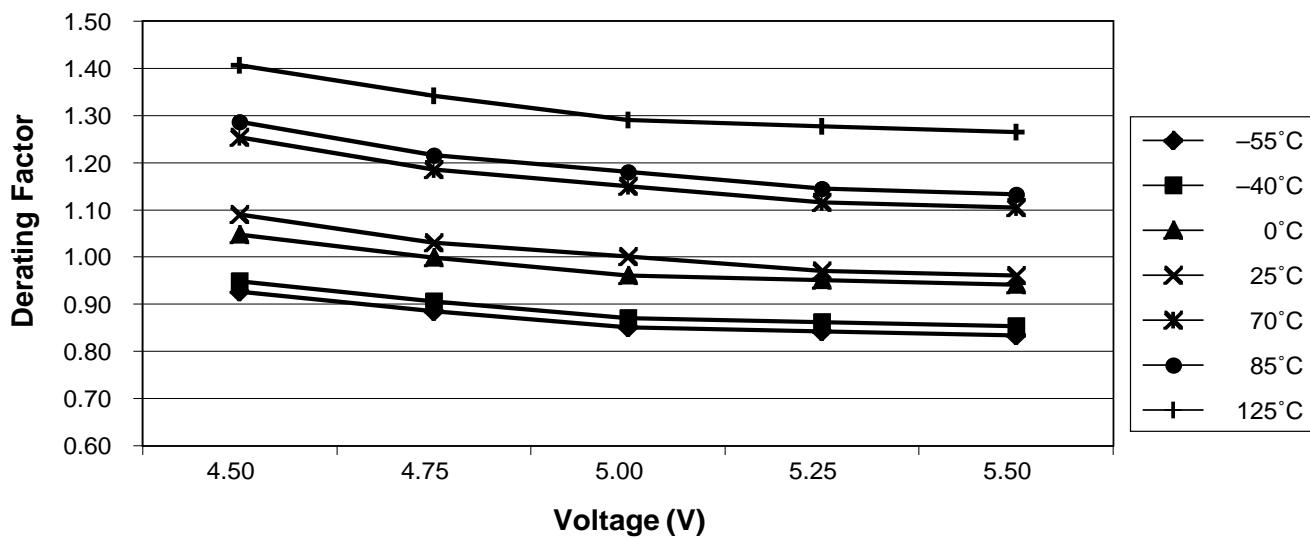
MX devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature and worst-case processing.

42MX Temperature and Voltage Derating Factors

(Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.93	0.95	1.05	1.09	1.25	1.29	1.41
4.75	0.88	0.90	1.00	1.03	1.18	1.22	1.34
5.00	0.85	0.87	0.96	1.00	1.15	1.18	1.29
5.25	0.84	0.86	0.95	0.97	1.12	1.14	1.28
5.50	0.83	0.85	0.94	0.96	1.10	1.13	1.26

42MX Junction Temperature and Voltage Derating Curves
(Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{V}$)



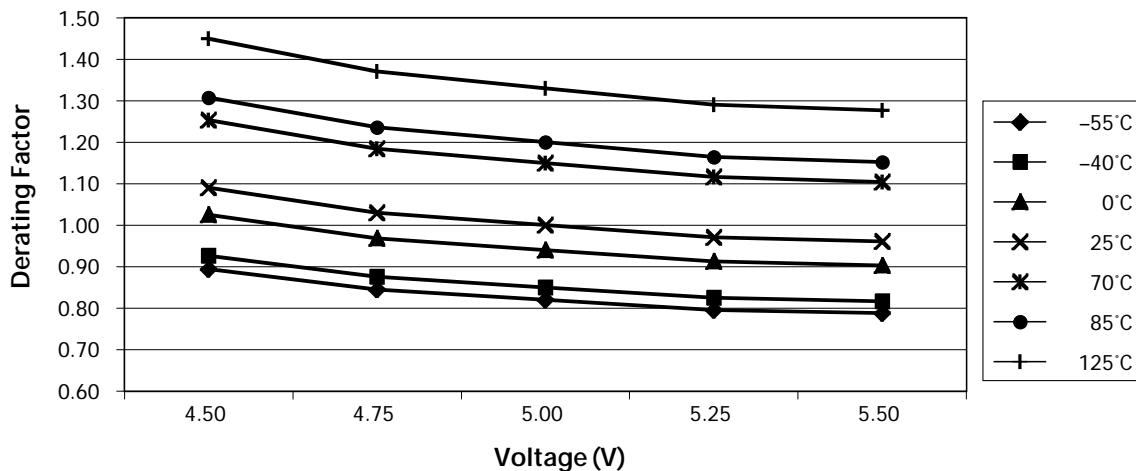
Note: This derating factor applies to all routing and propagation delays.

40MX Temperature and Voltage Derating Factors

(Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.89	0.93	1.02	1.09	1.25	1.31	1.45
4.75	0.84	0.88	0.97	1.03	1.18	1.24	1.37
5.00	0.82	0.85	0.94	1.00	1.15	1.20	1.33
5.25	0.80	0.82	0.91	0.97	1.12	1.16	1.29
5.50	0.79	0.82	0.90	0.96	1.10	1.15	1.28

40MX Junction Temperature and Voltage Derating Curves
(Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{V}$)

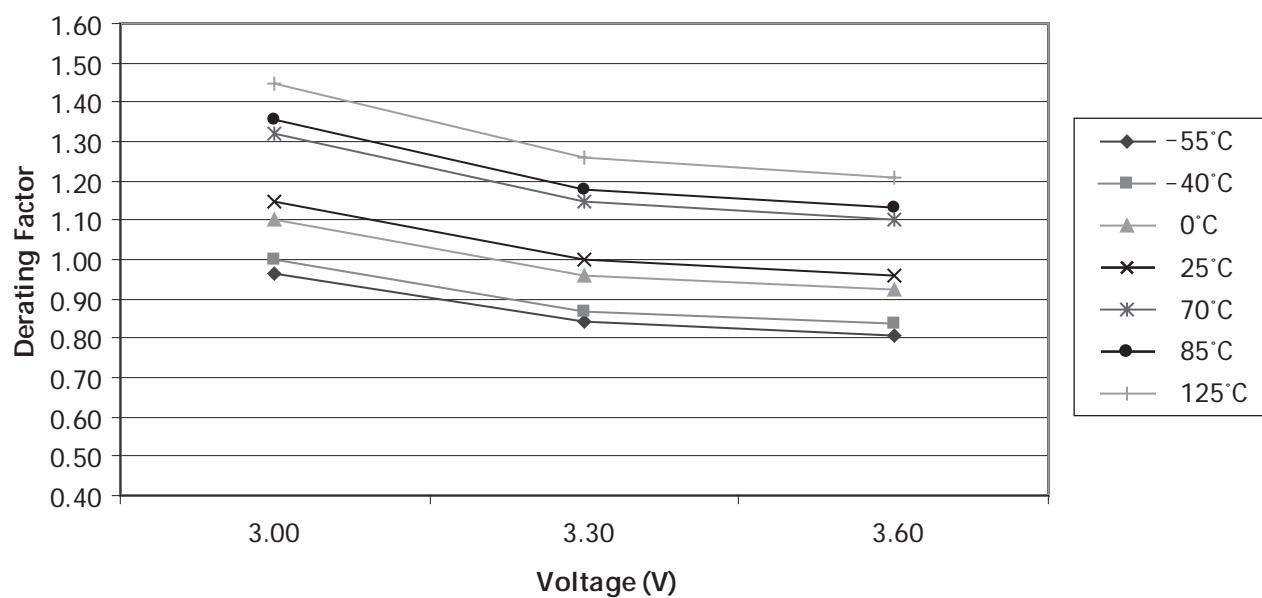


Note: This derating factor applies to all routing and propagation delays.

42MX Temperature and Voltage Derating Factors
 (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21

42MX Junction Temperature and Voltage Derating Curves
 (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{V}$)

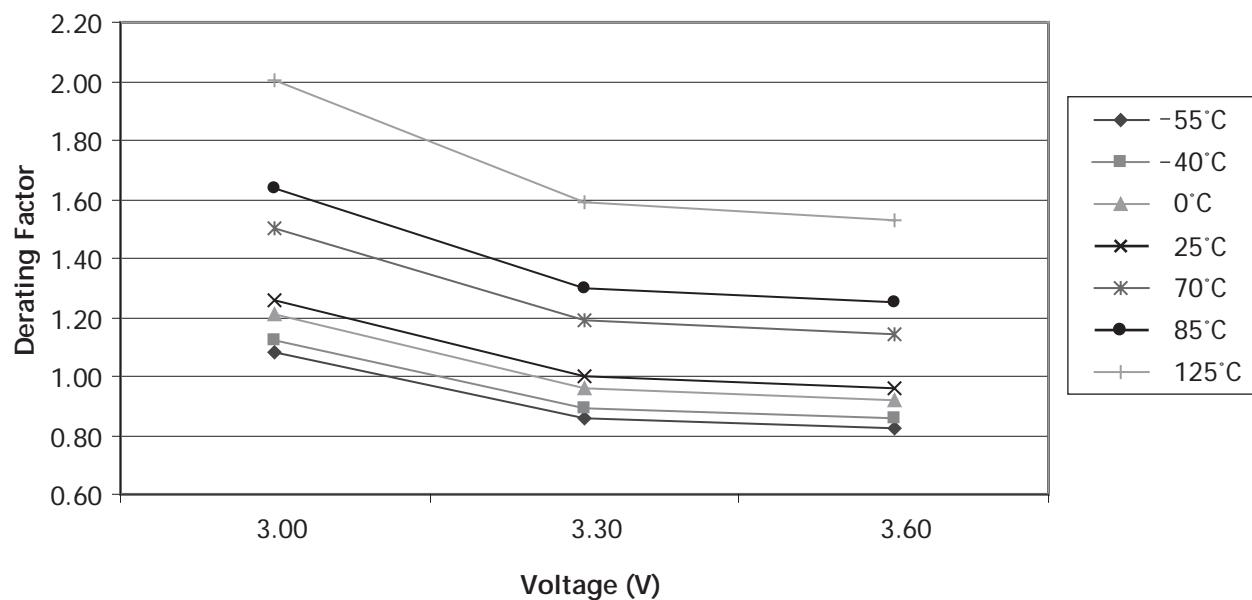


Note: This derating factor applies to all routing and propagation delays.

40MX Temperature and Voltage Derating Factors
 (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59
3.60	0.83	0.85	0.92	0.96	1.14	1.25	1.53

40MX Junction Temperature and Voltage Derating Curves
 (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{V}$)



Note: This derating factor applies to all routing and propagation delays.

PCI System Timing Specification

Table 6 and **Table 7** list the critical PCI timing parameters and the corresponding timing parameters for the MX PCI-compliant devices.

PCI Models

Actel provides synthesizable VHDL and Verilog-HDL models for a PCI Target interface, a PCI Target and Target+DMA Master interface. Contact your Actel sales representative for more details.

Table 6 • Clock Specification for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{CYC}	CLK Cycle Time	30	—	4.0	—	4.0	—	ns
t _{HIGH}	CLK High Time	11	—	1.9	—	1.9	—	ns
t _{LOW}	CLK Low Time	11	—	1.9	—	1.9	—	ns

Table 7 • Timing Parameters for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
t _{VAL}	CLK to Signal Valid—Bused Signals	2	11	2.0	9.0	2.0	9.0	ns
t _{VAL(PTP)}	CLK to Signal Valid—Point-to-Point	2 ²	12	2.0	9.0	2.0	9.0	ns
t _{ON}	Float to Active	2	—	2.0	4.0	2.0	4.0	ns
t _{OFF}	Active to Float	—	28	—	8.3 ¹	—	8.3 ¹	ns
t _{SU}	Input Set-Up Time to CLK—Bused Signals	7	—	1.5	—	1.5	—	ns
t _{SU(PTP)}	Input Set-Up Time to CLK—Point-to-Point	10, 12 ²	—	1.5	—	1.5	—	ns
t _H	Input Hold to CLK	0	—	0	—	0	—	ns

Notes:

1. T_{OFF} is system dependent. MX PCI devices have 7.4 ns turn-off time, reflection is typically an additional 10 ns.
2. REQ# and GNT# are point-to-point signals and have different output valid delay and input setup times than do bussed signals. GNT# has a setup of 10; REW# has a setup of 12.

A40MX02 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, $V_{CC} = 4.75V$, $T_J = 70^{\circ}C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t_{PD2}	Dual-Module Macros		2.7		3.1		3.5		4.1		5.7	ns
t_{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays¹												
t_{RD1}	FO=1 Routing Delay		1.3		1.5		1.7		2.0		2.8	ns
t_{RD2}	FO=2 Routing Delay		1.8		2.1		2.4		2.8		3.9	ns
t_{RD3}	FO=3 Routing Delay		2.3		2.7		3.0		3.6		5.0	ns
t_{RD4}	FO=4 Routing Delay		2.9		3.3		3.7		4.4		6.1	ns
t_{RD8}	FO=8 Routing Delay		4.9		5.7		6.5		7.6		10.6	ns
Logic Module Sequential Timing²												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HD}^3	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HEN}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t_A	Flip-Flop Clock Input Period	4.8		5.6		6.3		7.5		10.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181		168		154		134		80	MHz

Notes:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.

A40MX02 Timing Characteristics (Nominal 5.0V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CC} = 4.75V$, $T_J = 70^{\circ}C$)

	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays											
t_{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5 ns
t_{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3 ns
Input Module Predicted Routing Delays¹											
t_{IRD1}	FO=1 Routing Delay		2.1		2.4		2.2		3.2		4.5 ns
t_{IRD2}	FO=2 Routing Delay		2.6		3.0		3.4		4.0		5.6 ns
t_{IRD3}	FO=3 Routing Delay		3.1		3.6		4.1		4.8		6.7 ns
t_{IRD4}	FO=4 Routing Delay		3.6		4.2		4.8		5.6		7.8 ns
t_{IRD8}	FO=8 Routing Delay		5.7		6.6		7.5		8.8		12.4 ns
Global Clock Network											
t_{CKH}	Input Low to HIGH	FO = 16	4.6		5.3		6.0		7.0		9.8 ns
		FO = 128	4.6		5.3		6.0		7.0		9.8 ns
t_{CKL}	Input High to LOW	FO = 16	4.8		5.6		6.3		7.4		10.4 ns
		FO = 128	4.8		5.6		6.3		7.4		10.4 ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.1		3.6		5.1 ns
t_{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.01		3.6		5.1 ns
t_{CKSW}	Maximum Skew	FO = 16	0.4		0.5		0.5		0.6		0.8 ns
		FO = 128	0.5		0.6		0.7		0.8		1.2 ns
t_p	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0 ns
		FO = 128	4.8		5.6		6.3		7.5		10.4 ns
f_{MAX}	Maximum Frequency	FO = 16	188		175		160		139		83 MHz
		FO = 128	181		168		154		134		80 MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A40MX02 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, V_{CC} = 4.75V, T_J = 70°C)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t _{DLH}	Data-to-Pad HIGH		3.3		3.8		4.3		5.1		7.2	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.3		4.9		5.8		8.0	ns
t _{ENZL}	Enable Pad Z to LOW		4.7		5.4		6.1		7.2		10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.1	ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF
CMOS Output Module Timing¹												
t _{DLH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.05		8.5	ns
t _{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.0	ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04	ns/pF

Note:

1. Delays based on 35 pF loading

A40MX02 Timing Characteristics (Nominal 3.3V Operation)(Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7	ns
t_{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0	ns
t_{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7	ns
Logic Module Predicted Routing Delays¹												
t_{RD1}	FO=1 Routing Delay		2.0		2.2		2.5		3.0		4.2	ns
t_{RD2}	FO=2 Routing Delay		2.7		3.1		3.5		4.1		5.7	ns
t_{RD3}	FO=3 Routing Delay		3.4		3.9		4.4		5.2		7.3	ns
t_{RD4}	FO=4 Routing Delay		4.2		4.8		5.4		6.3		8.9	ns
t_{RD8}	FO=8 Routing Delay		7.1		8.2		9.2		10.9		15.2	ns
Logic Module Sequential Timing²												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	4.3		4.9		5.6		6.6		9.2		ns
t_{HD}^3	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	4.3		4.9		5.6		6.6		9.2		ns
t_{HEN}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		6.0		7.0		9.8		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		6.0		7.0		9.8		ns
t_A	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz

Notes:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.

A40MX02 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t_{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay		2.9		3.4		3.8		4.5		6.3	ns
t_{IRD2}	FO=2 Routing Delay		3.6		4.2		4.8		5.6		7.8	ns
t_{IRD3}	FO=3 Routing Delay		4.4		5.0		5.7		6.7		9.4	ns
t_{IRD4}	FO=4 Routing Delay		5.1		5.9		6.7		7.8		11.0	ns
t_{IRD8}	FO=8 Routing Delay		8.0		9.26		10.5		12.6		17.3	ns
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO = 16	6.4		7.4		8.3		9.8		13.7	
		FO = 128	6.4		7.4		8.3		9.8		13.7	ns
t_{CKL}	Input HIGH to LOW	FO = 16	6.7		7.8		8.8		10.4		14.5	
		FO = 128	6.7		7.8		8.8		10.4		14.5	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 16	3.1		3.6		4.1		4.8		6.7	
		FO = 128	3.3		3.8		4.3		5.1		7.1	ns
t_{PWL}	Minimum Pulse Width LOW	FO = 16	3.1		3.6		4.1		4.8		6.7	
		FO = 128	3.3		3.8		4.3		5.1		7.1	ns
t_{CKSW}	Maximum Skew	FO = 16	0.6		0.6		0.7		0.8		1.2	
		FO = 128	0.8		0.9		1.0		1.2		1.6	ns
t_P	Minimum Period	FO = 16	6.5		7.5		8.5		10.1		14.1	
		FO = 128	6.8		7.8		8.9		10.4		14.6	ns
f_{MAX}	Maximum Frequency	FO = 16	113		105		96		83		50	
		FO = 128	109		101		92		80		48	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A40MX02 Timing Characteristics (Nominal 3.3V Operation) (continued)(Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}C$)

Parameter Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹											
t_{DLH}	Data-to-Pad HIGH	4.7	5.4	6.1	7.2	10.0	ns				
t_{DHL}	Data-to-Pad LOW	5.6	6.4	7.3	8.6	12.0	ns				
t_{ENZH}	Enable Pad Z to HIGH	5.2	6.0	6.8	8.1	11.3	ns				
t_{ENZL}	Enable Pad Z to LOW	6.6	7.6	8.6	10.1	14.1	ns				
t_{ENHZ}	Enable Pad HIGH to Z	11.1	12.8	14.5	17.1	23.9	ns				
t_{ENLZ}	Enable Pad LOW to Z	8.2	9.5	10.7	12.6	17.7	ns				
d_{TLH}	Delta LOW to HIGH	0.03	0.03	0.04	0.04	0.06	ns/pF				
d_{THL}	Delta HIGH to LOW	0.04	0.04	0.05	0.06	0.08	ns/pF				
CMOS Output Module Timing¹											
t_{DLH}	Data-to-Pad HIGH	5.5	6.4	7.2	8.5	11.9	ns				
t_{DHL}	Data-to-Pad LOW	4.8	5.5	6.2	7.3	10.2	ns				
t_{ENZH}	Enable Pad Z to HIGH	4.7	5.5	6.2	7.3	10.2	ns				
t_{ENZL}	Enable Pad Z to LOW	6.8	7.9	8.9	10.5	14.7	ns				
t_{ENHZ}	Enable Pad HIGH to Z	11.1	12.8	14.5	17.1	23.9	ns				
t_{ENLZ}	Enable Pad LOW to Z	8.2	9.5	10.7	12.6	17.7	ns				
d_{TLH}	Delta LOW to HIGH	0.05	0.05	0.06	0.07	0.10	ns/pF				
d_{THL}	Delta HIGH to LOW	0.03	0.03	0.04	0.04	0.06	ns/pF				

Note:

1. Delays based on 35 pF loading.

A40MX04 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, $V_{CC} = 4.75V$, $T_J = 70^{\circ}C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t_{PD2}	Dual-Module Macros		2.3		3.1		3.5		4.1		5.7	ns
t_{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays¹												
t_{RD1}	FO=1 Routing Delay		1.2		1.6		1.8		2.1		3.0	ns
t_{RD2}	FO=2 Routing Delay		1.9		2.2		2.5		2.9		4.1	ns
t_{RD3}	FO=3 Routing Delay		2.4		2.8		3.2		3.7		5.2	ns
t_{RD4}	FO=4 Routing Delay		2.9		3.4		3.9		4.5		6.3	ns
t_{RD8}	FO=8 Routing Delay		5.0		5.8		6.6		7.8		10.9	ns
Logic Module Sequential Timing²												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HD}^3	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HEN}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t_A	Flip-Flop Clock Input Period	4.8		5.6		6.3		7.5		10.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181		167		154		134		80	MHz

Notes:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer utility from the Designer software to check the hold time for this macro.

A40MX04 Timing Characteristics (Nominal 5.0V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CC} = 4.75V$, $T_J = 70^{\circ}C$)

	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays											
t_{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5 ns
t_{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3 ns
Input Module Predicted Routing Delays¹											
t_{IRD1}	FO=1 Routing Delay		2.1		2.4		2.2		3.2		4.5 ns
t_{IRD2}	FO=2 Routing Delay		2.6		3.0		3.4		4.0		5.6 ns
t_{IRD3}	FO=3 Routing Delay		3.1		3.6		4.1		4.8		6.7 ns
t_{IRD4}	FO=4 Routing Delay		3.6		4.2		4.8		5.6		7.8 ns
t_{IRD8}	FO=8 Routing Delay		5.7		6.6		7.5		8.8		12.4 ns
Global Clock Network											
t_{CKH}	Input LOW to HIGH	FO = 16	4.6		5.3		6.0		7.1		9.9 ns
		FO = 128	4.6		5.3		6.0		7.1		9.9 ns
t_{CKL}	Input HIGH to LOW	FO = 16	4.8		5.6		6.3		7.5		10.4 ns
		FO = 128	4.8		5.6		6.3		7.5		10.4 ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.1		3.6		5.1 ns
t_{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8 ns
		FO = 128	2.4		2.7		3.1		3.6		5.1 ns
t_{CKSW}	Maximum Skew	FO = 16	0.4		0.5		0.5		0.6		0.8 ns
		FO = 128	0.5		0.6		0.7		0.8		1.2 ns
t_p	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.1 ns
		FO = 128	4.8		5.6		6.3		7.5		10.4 ns
f_{MAX}	Maximum Frequency	FO = 16	188		175		160		139		83 MHz
		FO = 128	181		168		154		134		80 MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A40MX04 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, V_{CC} = 4.75V, T_J = 70°C)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t _{DLH}	Data-to-Pad HIGH		3.3		3.8		4.3		5.1		7.2	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.3		4.9		5.8		8.1	ns
t _{ENZL}	Enable Pad Z to LOW		4.7		5.4		6.1		7.2		10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.1	ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.02		0.03		0.03		0.04		0.06	ns/pF
CMOS Output Module Timing¹												
t _{DLH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.1		8.5	ns
t _{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.1	ns
t _{ENLZ}	Enable Pad LOW to Z		5.0		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04	ns/pF

Note:

1. Delays based on 35 pF loading

A40MX04 Timing Characteristics (Nominal 3.3V Operation)(Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7	ns
t_{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0	ns
t_{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7	ns
Logic Module Predicted Routing Delays¹												
t_{RD1}	FO=1 Routing Delay		1.9		2.2		2.5		3.0		4.2	ns
t_{RD2}	FO=2 Routing Delay		2.7		3.1		3.5		4.1		5.7	ns
t_{RD3}	FO=3 Routing Delay		3.4		3.9		4.4		5.2		7.3	ns
t_{RD4}	FO=4 Routing Delay		4.1		4.8		5.4		6.3		8.9	ns
t_{RD8}	FO=8 Routing Delay		7.1		8.1		9.2		10.9		15.2	ns
Logic Module Sequential Timing²												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	4.3		5.0		5.6		6.6		9.2		ns
t_{HD}^3	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	4.3		5.0		5.6		6.6		9.2		ns
t_{HEN}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t_A	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz

Notes:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.

A40MX04 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t_{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay		2.9		3.3		3.8		4.5		6.3	ns
t_{IRD2}	FO=2 Routing Delay		3.6		4.2		4.8		5.6		7.8	ns
t_{IRD3}	FO=3 Routing Delay		4.4		5.0		5.7		6.7		9.4	ns
t_{IRD4}	FO=4 Routing Delay		5.1		5.9		6.7		7.8		11.0	ns
t_{IRD8}	FO=8 Routing Delay		8.0		9.3		10.5		12.4		17.2	ns
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO = 16	6.4		7.4		8.4		9.9		13.8	
		FO = 128	6.4		7.4		8.4		9.9		13.8	ns
t_{CKL}	Input HIGH to LOW	FO = 16	6.8		7.8		8.9		10.4		14.6	
		FO = 128	6.8		7.8		8.9		10.4		14.6	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 16	3.1		3.6		4.1		4.8		6.7	
		FO = 128	3.3		3.8		4.3		5.1		7.1	ns
t_{PWL}	Minimum Pulse Width LOW	FO = 16	3.1		3.6		4.1		4.8		6.7	
		FO = 128	3.3		3.8		4.3		5.1		7.1	ns
t_{CKSW}	Maximum Skew	FO = 16	0.6		0.6		0.7		0.8		1.2	
		FO = 128	0.8		0.9		1.0		1.2		1.6	ns
t_P	Minimum Period	FO = 16	6.5		7.5		8.5		10.1		14.1	
		FO = 128	6.8		7.8		8.9		10.4		14.6	ns
f_{MAX}	Maximum Frequency	FO = 16	113		105		96		83		50	
		FO = 128	109		101		92		80		48	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A40MX04 Timing Characteristics (Nominal 3.3V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CC} = 3.0V$, $T_J = 70^{\circ}C$)

Parameter Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹											
t_{DLH}	Data-to-Pad HIGH	4.7		5.4		6.1		7.2		10.0	ns
t_{DHL}	Data-to-Pad LOW		5.6		6.4		7.3		8.6	12.0	ns
t_{ENZH}	Enable Pad Z to HIGH		5.2		6.0		6.9		8.1	11.3	ns
t_{ENZL}	Enable Pad Z to LOW		6.6		7.6		8.6		10.1	14.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1	23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6	17.7	ns
d_{TLH}	Delta LOW to HIGH		0.03		0.03		0.04		0.04	0.06	ns/pF
d_{THL}	Delta HIGH to LOW		0.04		0.04		0.05		0.06	0.08	ns/pF
CMOS Output Module Timing¹											
t_{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5	11.9	ns
t_{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3	10.2	ns
t_{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3	10.2	ns
t_{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5	14.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1	23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6	17.7	ns
d_{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07	0.10	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04	0.06	ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX09 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays¹						
t_{PD1} Single Module	1.2	1.3	1.5	1.8	2.5	ns
t_{CO} Sequential Clock-to-Q	1.3	1.4	1.6	1.9	2.7	ns
t_{GO} Latch G-to-Q	1.2	1.4	1.6	1.8	2.6	ns
t_{RS} Flip-Flop (Latch) Reset-to-Q	1.2	1.6	1.8	2.1	2.9	ns
Logic Module Predicted Routing Delays²						
t_{RD1} FO=1 Routing Delay	0.7	0.8	0.9	1.0	1.4	ns
t_{RD2} FO=2 Routing Delay	0.9	1.0	1.2	1.4	1.9	ns
t_{RD3} FO=3 Routing Delay	1.2	1.3	1.5	1.7	2.4	ns
t_{RD4} FO=4 Routing Delay	1.4	1.5	1.7	2.0	2.9	ns
t_{RD8} FO=8 Routing Delay	2.3	2.6	2.9	3.4	4.8	ns
Logic Module Sequential Timing^{3, 4}						
t_{SUD} Flip-Flop (Latch) Data Input Set-Up	0.3	0.4	0.4	0.5	0.7	ns
t_{HD} Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{SUENA} Flip-Flop (Latch) Enable Set-Up	0.4	0.5	0.5	0.6	0.8	ns
t_{HEN} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	3.4	3.8	4.3	5.0	7.0	ns
t_{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.5	4.9	5.6	6.6	9.2	ns
t_A Flip-Flop Clock Input Period	3.5	3.8	4.3	5.1	7.1	ns
t_{INH} Input Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{INSU} Input Buffer Latch Set-Up	0.3	0.3	0.4	0.4	0.6	ns
t_{OUTH} Output Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{OUTSU} Output Buffer Latch Set-Up	0.3	0.3	0.4	0.4	0.6	ns
f_{MAX} Flip-Flop (Latch) Clock Frequency	268	244	224	195	117	MHz

Notes:

- For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$ or $t_{PD1} + t_{RD1} + t_{SUD}$ whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX09 Timing Characteristics (Nominal 5.0V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INYH}	Pad-to-Y HIGH		1.0		1.2		1.3		1.6		2.2	ns
t_{INYL}	Pad-to-Y LOW		0.8		0.9		1.0		1.2		1.7	ns
t_{INGH}	G to Y HIGH		1.3		1.4		1.6		1.9		2.7	ns
t_{INGL}	G to Y LOW		1.3		1.4		1.6		1.9		2.7	ns
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay		2.0		2.2		2.5		3.0		4.2	ns
t_{IRD2}	FO=2 Routing Delay		2.3		2.5		2.9		3.4		4.7	ns
t_{IRD3}	FO=3 Routing Delay		2.5		2.8		3.2		3.7		5.2	ns
t_{IRD4}	FO=4 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns
t_{IRD8}	FO=8 Routing Delay		3.7		4.1		4.7		5.5		7.7	ns
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO = 32	2.4		2.7		3.0		3.6		5.0	ns
		FO = 256	2.7		3.0		3.4		4.0		5.5	ns
t_{CKL}	Input HIGH to LOW	FO = 32	3.5		3.9		4.4		5.2		7.3	ns
		FO = 256	3.9		4.3		4.9		5.7		8.0	ns
t_{PWH}	Minimum Pulse Width	FO = 32	1.2		1.4		1.5		1.8		2.5	ns
	HIGH	FO = 256	1.3		1.5		1.7		2.0		2.7	ns
t_{PWL}	Minimum Pulse Width	FO = 32	1.2		1.4		1.5		1.8		2.5	ns
	LOW	FO = 256	1.3		1.5		1.7		2.0		2.7	ns
t_{CKSW}	Maximum Skew	FO = 32	0.3		0.3		0.4		0.5		0.6	ns
		FO = 256	0.3		0.3		0.4		0.5		0.6	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0	ns
		FO = 256	0.0		0.0		0.0		0.0		0.0	ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.3		2.6		3.0		3.5		4.9	ns
		FO = 256	2.2		2.4		3.3		3.9		5.5	ns
t_p	Minimum Period	FO = 32	3.4		3.7		4.0		4.7		7.8	ns
		FO = 256	3.7		4.1		4.5		5.2		8.6	ns
f_{MAX}	Maximum Frequency	FO = 32	296		269		247		215		129	MHz
		FO = 256	268		244		224		195		117	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX09 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		2.5		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{ENZH}	Enable Pad Z to HIGH		2.6		2.9		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t_{GLH}	G-to-Pad HIGH		2.6		2.9		3.3		3.8		5.3	ns
t_{GHL}	G-to-Pad LOW		2.6		2.9		3.3		3.8		5.3	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d_{THL}	Capacity Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		2.9		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t_{GLH}	G-to-Pad HIGH		4.2		4.6		5.2		6.1		8.6	ns
t_{GHL}	G-to-Pad LOW		4.2		4.6		5.2		6.1		8.6	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d_{THL}	Capacity Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF

Note:

1. Delays based on 35 pF loading

A42MX09 Timing Characteristics (Nominal 3.3V Operation)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^\circ C$)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Units
Logic Module Propagation Delays¹						
t _{PD1} Single Module	1.6	1.8	2.1	2.5	3.5	ns
t _{CO} Sequential Clock-to-Q	1.8	2.0	2.3	2.7	3.8	ns
t _{GO} Latch G-to-Q	1.7	1.9	2.1	2.5	3.5	ns
t _{RS} Flip-Flop (Latch) Reset-to-Q	2.0	2.2	2.5	2.9	4.1	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	1.0	1.1	1.2	1.4	2.0	ns
t _{RD2} FO=2 Routing Delay	1.3	1.4	1.6	1.9	2.7	ns
t _{RD3} FO=3 Routing Delay	1.6	1.8	2.0	2.4	3.3	ns
t _{RD4} FO=4 Routing Delay	1.9	2.1	2.4	2.9	4.0	ns
t _{RD8} FO=8 Routing Delay	3.2	3.6	4.1	4.8	6.7	ns
Logic Module Sequential Timing^{3, 4}						
t _{SUD} Flip-Flop (Latch) Data Input Set-Up	0.5	0.5	0.6	0.7	0.9	ns
t _{HD} Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	0.6	0.6	0.7	0.8	1.2	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.7	5.3	6.0	7.0	9.8	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	6.2	6.9	7.8	9.2	12.9	ns
t _A Flip-Flop Clock Input Period	5.0	5.6	6.2	7.1	9.9	ns
t _{INH} Input Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{INSU} Input Buffer Latch Set-Up	0.3	0.3	0.3	0.4	0.6	ns
t _{OUTH} Output Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{OUTSU} Output Buffer Latch Set-Up	0.3	0.3	0.3	0.4	0.6	ns
f _{MAX} Flip-Flop (Latch) Clock Frequency	161	146	135	117	70	MHz

Notes:

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDpr}$, $t_{CO} + t_{RD1} + t_{PDpr}$ or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX09 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INYH}	Pad-to-Y HIGH			1.5		1.6		1.8		2.17		3.0
t_{INYL}	Pad-to-Y LOW			1.2		1.3		1.4		1.7		2.4
t_{INGH}	G to Y HIGH			1.8		2.0		2.3		2.7		3.7
t_{INGL}	G to Y LOW			1.8		2.0		2.3		2.7		3.7
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay			2.8		3.2		3.6		4.2		5.9
t_{IRD2}	FO=2 Routing Delay			3.2		3.5		4.0		4.7		6.6
t_{IRD3}	FO=3 Routing Delay			3.5		3.9		4.4		5.2		7.3
t_{IRD4}	FO=4 Routing Delay			3.9		4.3		4.9		5.7		8.0
t_{IRD8}	FO=8 Routing Delay			5.2		5.8		6.6		7.7		10.8
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO = 32		4.1		4.5		5.1		6.0		8.4
		FO = 256		4.5		5.0		5.6		6.7		9.3
t_{CKL}	Input HIGH to LOW	FO = 32		5.0		5.5		6.2		7.3		10.2
		FO = 256		5.4		6.0		6.8		8.0		11.2
t_{PWH}	Minimum Pulse Width	FO = 32	1.7		1.9		2.1		2.5		3.5	
	HIGH	FO = 256	1.9		2.1		2.3		2.7		3.8	
t_{PWL}	Minimum Pulse Width	FO = 32	1.7		1.9		2.1		2.5		3.5	
	LOW	FO = 256	1.9		2.1		2.3		2.7		3.8	
t_{CKSW}	Maximum Skew	FO = 32	0.4		0.5		0.5		0.6		0.9	
		FO = 256	0.4		0.5		0.5		0.6		0.9	
t_{SUEXT}	Input Latch External	FO = 32	0.0		0.0		0.0		0.0		0.0	
	Set-Up	FO = 256	0.0		0.0		0.0		0.0		0.0	
t_{HEXT}	Input Latch External Hold	FO = 32	3.3		3.7		4.2		4.9		6.9	
		FO = 256	3.7		4.1		4.6		5.5		7.6	
t_P	Minimum Period	FO = 32	5.6		6.2		6.7		7.8		12.9	
		FO = 256	6.1		6.8		7.4		8.5		14.2	
f_{MAX}	Maximum Frequency	FO = 32	177		161		148		129		77	MHz
		FO = 256	161		146		135		117		70	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX09 Timing Characteristics (Nominal 3.3V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.1		7.1	ns
t_{DHL}	Data-to-Pad LOW		4.0		4.5		5.1		6.1		8.3	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t_{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t_{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t_{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.00		0.00		0.00		0.10		0.01	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.09		0.10		0.10		0.10		0.10	ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t_{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t_{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t_{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX16 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, V_{CCA} = 4.75V, T_J = 70°C)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays¹						
t _{PD1} Single Module	1.4	1.5	1.7	2.0	2.8	ns
t _{CO} Sequential Clock-to-Q	1.4	1.6	1.8	2.1	3.0	ns
t _{GO} Latch G-to-Q	1.4	1.5	1.7	2.0	2.8	ns
t _{RS} Flip-Flop (Latch) Reset-to-Q	1.6	1.7	2.0	2.3	3.3	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	0.8	0.9	1.0	1.2	1.6	ns
t _{RD2} FO=2 Routing Delay	1.0	1.2	1.3	1.5	2.1	ns
t _{RD3} FO=3 Routing Delay	1.3	1.4	1.6	1.9	2.7	ns
t _{RD4} FO=4 Routing Delay	1.6	1.7	2.0	2.3	3.2	ns
t _{RD8} FO=8 Routing Delay	2.6	2.9	3.2	3.8	5.3	ns
Logic Module Sequential Timing^{3,4}						
t _{SUD} Flip-Flop (Latch) Data Input Set-Up	0.3	0.4	0.4	0.5	0.7	ns
t _{HD} Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	0.7	0.8	0.9	1.0	1.4	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	3.4	3.8	4.3	5.0	7.1	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.5	5.0	5.6	6.6	9.2	ns
t _A Flip-Flop Clock Input Period	6.8	7.6	8.6	10.1	14.1	ns
t _{INH} Input Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{INSU} Input Buffer Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns
t _{OUTH} Output Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{OUTSU} Output Buffer Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns
f _{MAX} Flip-Flop (Latch) Clock Frequency	215	195	179	156	94	MHz

Notes:

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PD_{lr}}, t_{CO} + t_{RD1} + t_{PD_{lr}} or t_{PD1} + t_{RD1} + t_{SUD}, point and position whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX16 Timing Characteristics (Nominal 5.0V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INYH}	Pad-to-Y HIGH			1.1		1.2		1.3		1.6		2.2
t_{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7
t_{INGH}	G to Y HIGH			1.4		1.6		1.8		2.1		2.9
t_{INGL}	G to Y LOW			1.4		1.6		1.8		2.1		2.9
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay			1.8		2.0		2.3		2.7		4.0
t_{IRD2}	FO=2 Routing Delay			2.1		2.3		2.6		3.1		4.3
t_{IRD3}	FO=3 Routing Delay			2.3		2.6		3.0		3.5		4.9
t_{IRD4}	FO=4 Routing Delay			2.6		3.0		3.3		3.9		5.4
t_{IRD8}	FO=8 Routing Delay			3.6		4.0		4.6		5.4		7.5
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO = 32		2.6		2.9		3.3		3.9		5.4
		FO = 384		2.9		3.2		3.6		4.3		6.0
t_{CKL}	Input HIGH to LOW	FO = 32		3.8		4.2		4.8		5.6		7.8
		FO = 384		4.5		5.0		5.6		6.6		9.2
t_{PWH}	Minimum Pulse Width HIGH	FO = 32	3.2		3.5		4.0		4.7		6.6	
		FO = 384	3.7		4.1		4.6		5.4		7.6	
t_{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6	
		FO = 384	3.7		4.1		4.6		5.4		7.6	
t_{CKSW}	Maximum Skew	FO = 32	0.3		0.4		0.4		0.5		0.7	
		FO = 384	0.3		0.4		0.4		0.5		0.7	
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0	
		FO = 384	0.0		0.0		0.0		0.0		0.0	
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7	
		FO = 384	3.2		3.5		4.0		4.7		6.6	
t_p	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7	
		FO = 384	4.6		5.1		5.6		6.4		10.7	
f_{MAX}	Maximum Frequency	FO = 32	237		215		198		172		103	MHz
		FO = 384	215		195		179		156		94	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX16 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^{\circ}C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH	2.5		2.8		3.2		3.7		5.2		ns
t_{DHL}	Data-to-Pad LOW		3.0		3.3		3.7		4.4		6.1	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.4		4.0		5.6	ns
t_{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.8		4.4		6.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.4		6.0		6.8		8.0		11.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.0		5.6		6.3		7.4		10.4	ns
t_{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t_{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.7		6.3		7.1		8.4		11.9	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.2		3.6		4.0		4.7		6.6	ns
t_{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.4		4.0		5.6	ns
t_{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.8		4.4		6.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.4		6.0		6.8		8.0		11.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.0		5.6		6.3		7.4		10.4	ns
t_{GLH}	G-to-Pad HIGH		5.1		5.6		6.4		7.5		10.5	ns
t_{GHL}	G-to-Pad LOW		5.1		5.6		6.4		7.5		10.5	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.7		6.3		7.1		8.4		11.9	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.03		0.03		0.03		0.04		0.06		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.04		0.05		0.07		ns/pF

Note:

1. Delays based on 35 pF loading

A42MX16 Timing Characteristics (Nominal 3.3V Operation)(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Units
Logic Module Propagation Delays¹						
t _{PD1} Single Module	1.9	2.1	2.4	2.8	4.0	ns
t _{CO} Sequential Clock-to-Q	2.0	2.2	2.5	3.0	4.2	ns
t _{GO} Latch G-to-Q	1.9	2.1	2.4	2.8	4.0	ns
t _{RS} Flip-Flop (Latch) Reset-to-Q	2.2	2.4	2.8	3.3	4.6	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	1.1	1.2	1.4	1.6	2.3	ns
t _{RD2} FO=2 Routing Delay	1.5	1.6	1.8	2.1	3.0	ns
t _{RD3} FO=3 Routing Delay	1.8	2.0	2.3	2.7	3.8	ns
t _{RD4} FO=4 Routing Delay	2.2	2.4	2.7	3.2	4.5	ns
t _{RD8} FO=8 Routing Delay	3.6	4.0	4.5	5.3	7.5	ns
Logic Module Sequential Timing^{3, 4}						
t _{SUD} Flip-Flop (Latch) Data Input Set-Up	0.5	0.5	0.6	0.7	0.9	ns
t _{HD} Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	1.0	1.1	1.2	1.4	2.0	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.8	5.3	6.0	7.1	9.9	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	6.2	6.9	7.9	9.2	12.9	ns
t _A Flip-Flop Clock Input Period	9.5	10.6	12.0	14.1	19.8	ns
t _{INH} Input Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{INSU} Input Buffer Latch Set-Up	0.7	0.8	0.9	1.01	1.4	ns
t _{OUTH} Output Buffer Latch Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{OUTSU} Output Buffer Latch Set-Up	0.7	0.8	0.89	1.01	1.4	ns
f _{MAX} Flip-Flop (Latch) Clock Frequency	129	117	108	94	56	MHz

Notes:

1. For dual-module macros use t_{PD1} + t_{RD1} + t_{pated}, to + t_{RD1} + t_{pated}, or t_{PD1} + t_{RD1} + t_{usk}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX16 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units	
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH		1.5		1.6		1.9		2.2		3.1	ns	
t_{INYL}	Pad-to-Y LOW		1.1		1.3		1.4		1.7		2.4	ns	
t_{INGH}	G to Y HIGH		2.0		2.2		2.5		2.9		4.1	ns	
t_{INGL}	G to Y LOW		2.0		2.2		2.5		2.9		4.1	ns	
Input Module Predicted Routing Delays¹													
t_{IRD1}	FO=1 Routing Delay		2.6		2.9		3.2		3.8		5.3	ns	
t_{IRD2}	FO=2 Routing Delay		2.9		3.2		3.7		4.3		6.1	ns	
t_{IRD3}	FO=3 Routing Delay		3.3		3.6		4.1		4.9		6.8	ns	
t_{IRD4}	FO=4 Routing Delay		3.6		4.0		4.6		5.4		7.6	ns	
t_{IRD8}	FO=8 Routing Delay		5.1		5.6		6.4		7.5		10.5	ns	
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32	4.4		4.8		5.5		6.5		9.0	ns	
		FO = 384	4.8		5.3		6.0		7.1		9.9	ns	
t_{CKL}	Input HIGH to LOW	FO = 32	5.3		5.9		6.7		7.8		11.0	ns	
		FO = 384	6.2		6.9		7.9		9.2		12.9	ns	
t_{PWH}	Minimum Pulse Width	FO = 32	5.7		6.3		7.1		8.4		11.8	ns	
	HIGH	FO = 384	6.6		7.4		8.3		9.8		13.7	ns	
t_{PWL}	Minimum Pulse Width	FO = 32	5.3		5.9		6.7		7.8		11.0	ns	
	LOW	FO = 384	6.2		6.9		7.9		9.2		12.9	ns	
t_{CKSW}	Maximum Skew	FO = 32	0.5		0.5		0.6		0.7		1.0	ns	
		FO = 384	2.2		2.4		2.7		3.2		4.5	ns	
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0	ns	
		FO = 384	0.0		0.0		0.0		0.0		0.0	ns	
t_{HEXT}	Input Latch External Hold	FO = 32	3.9		4.3		4.9		5.7		8.0	ns	
		FO = 384	4.5		4.9		5.6		6.6		9.2	ns	
t_P	Minimum Period	FO = 32	7.0		7.8		8.4		9.7		16.2	ns	
		FO = 384	7.7		8.6		9.3		10.7		17.8	ns	
f_{MAX}	Maximum Frequency	FO = 32		142		129		119		103		62	MHz
		FO = 384		129		117		108		94		56	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX16 Timing Characteristics (Nominal 3.3V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.5		3.9		4.4		5.2		7.3	ns
t_{DHL}	Data-to-Pad LOW		4.1		4.6		5.2		6.1		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH		3.8		4.2		4.8		5.6		7.8	ns
t_{ENZL}	Enable Pad Z to LOW		4.2		4.6		5.3		6.2		8.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.6		8.4		9.5		11.2		15.7	ns
t_{ENLZ}	Enable Pad LOW to Z		7.0		7.8		8.8		10.4		14.5	ns
t_{GLH}	G-to-Pad HIGH		4.8		5.3		6.0		7.2		10.0	ns
t_{GHL}	G-to-Pad LOW		4.8		5.3		6.0		7.2		10.0	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		4.5		5.0		5.6		6.6		9.3	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t_{ENZH}	Enable Pad Z to HIGH		3.8		4.2		4.8		5.6		7.8	ns
t_{ENZL}	Enable Pad Z to LOW		4.2		4.6		5.3		6.2		8.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.6		8.4		9.5		11.2		15.7	ns
t_{ENLZ}	Enable Pad LOW to Z		7.0		7.8		8.8		10.4		14.5	ns
t_{GLH}	G-to-Pad HIGH		7.1		7.9		8.9		10.5		14.7	ns
t_{GHL}	G-to-Pad LOW		7.1		7.9		8.9		10.5		14.7	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX24 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, V_{CCA} = 4.75V, T_J = 70°C)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Combinatorial Functions¹						
t _{PD} Internal Array Module Delay	1.2	1.3	1.5	1.8	2.5	ns
t _{PDD} Internal Decode Module Delay	1.4	1.6	1.8	2.1	3.0	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	0.8	0.9	1.0	1.2	1.7	ns
t _{RD2} FO=2 Routing Delay	1.0	1.2	1.3	1.5	2.1	ns
t _{RD3} FO=3 Routing Delay	1.3	1.4	1.6	1.9	2.6	ns
t _{RD4} FO=4 Routing Delay	1.5	1.7	1.9	2.2	3.1	ns
t _{RD5} FO=8 Routing Delay	2.4	2.7	3.0	3.6	5.0	ns
Logic Module Sequential Timing^{3, 4}						
t _{CO} Flip-Flop Clock-to-Output	1.3	1.4	1.6	1.9	2.7	ns
t _{GO} Latch Gate-to-Output	1.2	1.3	1.5	1.8	2.5	ns
t _{SUD} Flip-Flop (Latch) Set-Up Time	0.3	0.4	0.4	0.5	0.7	ns
t _{HD} Flip-Flop (Latch) Hold Time	0.0	0.0	0.0	0.0	0.0	ns
t _{RO} Flip-Flop (Latch) Reset-to-Output	1.4	1.6	1.8	2.1	2.9	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	0.4	0.5	0.5	0.6	0.8	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	3.3	3.7	4.2	4.9	6.9	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.4	4.8	5.3	6.5	9.0	ns

Notes:

1. For dual-module macros, use t_{PPD1} + t_{RD1} + t_{PD_{lr}}, t_{CO} + t_{RD1} + t_{PD_{lr}} or t_{PPD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX24 Timing Characteristics (Nominal 5.0V Operation) (continued)(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed			
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units	
Input Module Propagation Delays													
t_{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1	ns	
t_{INGO}	Input Latch Gate-to-Output			1.3		1.4		1.6		1.9		2.6	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns	
t_{INSU}	Input Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns	
t_{ILA}	Latch Active Pulse Width	4.7		5.2		5.9		6.9		9.7		ns	
Input Module Predicted Routing Delays¹													
t_{IRD1}	FO=1 Routing Delay		1.8		2.0		2.3		2.7		3.8	ns	
t_{IRD2}	FO=2 Routing Delay			2.1		2.3		2.6		3.1		4.3	ns
t_{IRD3}	FO=3 Routing Delay		2.3		2.5		2.9		3.4		4.8	ns	
t_{IRD4}	FO=4 Routing Delay			2.5		2.8		3.2		3.7		5.2	ns
t_{IRD8}	FO=8 Routing Delay		3.4		3.8		4.3		5.1		7.1	ns	
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO=32	2.6		2.9		3.3		3.9		5.4	ns	
		FO=486	2.9		3.2		3.6		4.3		5.9	ns	
t_{CKL}	Input HIGH to LOW	FO=32	3.7		4.1		4.6		5.4		7.6	ns	
		FO=486	4.3		4.7		5.4		6.3		8.8	ns	
t_{PWH}	Minimum Pulse Width HIGH	FO=32	2.2		2.4		2.7		3.2		4.5	ns	
		FO=486	2.4		2.6		3.0		3.5		4.9	ns	
t_{PWL}	Minimum Pulse Width LOW	FO=32	2.2		2.4		2.7		3.2		4.5	ns	
		FO=486	2.4		2.6		3.0		3.5		4.9	ns	
t_{CKSW}	Maximum Skew	FO=32	0.5		0.6		0.7		0.8		1.1	ns	
		FO=486	0.5		0.6		0.7		0.8		1.1	ns	
t_{SUEXT}	Input Latch External Set-Up	FO=32	0.0		0.0		0.0		0.0		0.0	ns	
		FO=486	0.0		0.0		0.0		0.0		0.0	ns	
t_{HEXT}	Input Latch External Hold	FO=32	2.8		3.1		3.5		4.1		5.7	ns	
		FO=486	3.3		3.7		4.2		4.9		6.9	ns	
t_p	Minimum Period ($1/f_{MAX}$)	FO=32	4.7		5.2		5.7		6.5		10.9	ns	
		FO=486	5.1		5.7		6.2		7.1		11.9	ns	
f_{MAX}	Maximum Datapath Frequency	FO=32	210		191		176		153		92	MHz	
		FO=486	193		175		161		140		84	MHz	

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX24 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t_{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.9	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t_{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t_{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t_{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.6		6.1		6.9		8.1		11.4	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.1		3.5		3.9		4.6		6.4	ns
t_{DHL}	Data-to-Pad LOW		2.4		2.6		3.0		3.5		4.9	ns
t_{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t_{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.8	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t_{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t_{GLH}	G-to-Pad HIGH		4.9		5.4		6.2		7.2		10.1	ns
t_{GHL}	G-to-Pad LOW		4.9		5.4		6.2		7.2		10.1	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.5		6.1		6.9		8.1		11.3	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX24 Timing Characteristics (Nominal 3.3V Operation)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Min. Max.	Units
Logic Module Combinatorial Functions¹						
t_{PD} Internal Array Module Delay	2.0	1.8	2.1	2.5	3.4	ns
t_{PDD} Internal Decode Module Delay	1.1	2.2	2.5	3.0	4.2	ns
Logic Module Predicted Routing Delays²						
t_{RD1} FO=1 Routing Delay	1.7	1.3	1.4	1.7	2.3	ns
t_{RD2} FO=2 Routing Delay	2.0	1.6	1.8	2.1	3.0	ns
t_{RD3} FO=3 Routing Delay	1.1	2.0	2.2	2.6	3.7	ns
t_{RD4} FO=4 Routing Delay	1.5	2.3	2.6	3.1	4.3	ns
t_{RD5} FO=8 Routing Delay	1.8	3.7	4.2	5.0	7.0	ns
Logic Module Sequential Timing^{3, 4}						
t_{CO} Flip-Flop Clock-to-Output	2.1	2.0	2.3	2.7	3.7	ns
t_{GO} Latch Gate-to-Output	3.4	1.9	2.1	2.5	3.4	ns
t_{SUD} Flip-Flop (Latch) Set-Up Time	0.4	0.5	0.6	0.7	0.9	ns
t_{HD} Flip-Flop (Latch) Hold Time	0.0	0.0	0.0	0.0	0.0	ns
t_{RO} Flip-Flop (Latch) Reset-to-Output	2.0	2.2	2.5	2.9	4.1	ns
t_{SUENA} Flip-Flop (Latch) Enable Set-Up	0.6	0.6	0.7	0.8	1.2	ns
t_{HENNA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t_{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.6	5.2	5.8	6.9	9.6	ns
t_{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	6.1	6.8	7.7	9.0	12.6	ns

Notes:

1. For dual-module macros, use $t_{PDI} + t_{RD1} + t_{PDR}$, $t_{CO} + t_{RD1} + t_{PDR}$, or $t_{PDI} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX24 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0	ns
t_{INGO}	Input Latch Gate-to-Output			1.8		1.9		2.2		2.6		3.6 ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay		2.6		2.9		3.2		3.8		5.3	ns
t_{IRD2}	FO=2 Routing Delay			2.9		3.2		3.6		4.3		6.0 ns
t_{IRD3}	FO=3 Routing Delay		3.2		3.6		4.0		4.8		6.6	ns
t_{IRD4}	FO=4 Routing Delay			3.5		3.9		4.4		5.2		7.3 ns
t_{IRD8}	FO=8 Routing Delay		4.8		5.3		6.1		7.1		10.0	ns
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO=32	4.4		4.8		5.5		6.5		9.1	ns
		FO=486	4.8		5.3		6.0		7.1		10.0	ns
t_{CKL}	Input HIGH to LOW	FO=32	5.1		5.7		6.4		7.6		10.6	ns
		FO=486	6.0		6.6		7.5		8.8		12.4	ns
t_{PWH}	Minimum Pulse Width HIGH	FO=32	3.0		3.3		3.8		4.5		6.3	ns
		FO=486	3.3		3.7		4.2		4.9		6.9	ns
t_{PWL}	Minimum Pulse Width LOW	FO=32	3.0		3.4		3.8		4.5		6.3	ns
		FO=486	3.3		3.7		4.2		4.9		6.9	ns
t_{CKSW}	Maximum Skew	FO=32	0.8		0.8		1.0		1.1		1.6	ns
		FO=486	0.8		0.8		1.0		1.1		1.6	ns
t_{SUEXT}	Input Latch External Set-Up	FO=32	0.0		0.0		0.0		0.0		0.0	ns
		FO=486	0.0		0.0		0.0		0.0		0.0	ns
t_{HEXT}	Input Latch External Hold	FO=32	3.9		4.3		4.9		5.7		8.1	ns
		FO=486	4.6		5.2		5.8		6.9		9.6	ns
t_P	Minimum Period ($1/f_{MAX}$)	FO=32	7.8		8.7		9.5		10.8		18.2	ns
		FO=486	8.6		9.5		10.4		11.9		19.9	ns
f_{MAX}	Maximum Datapath Frequency	FO=32	126		115		106		92		55	MHz
		FO=486	116		105		97		84		50	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX24 Timing Characteristics (Nominal 3.3V Operation) (continued)(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.0		7.1	ns
t_{DHL}	Data-to-Pad LOW		4.0		4.4		5.0		5.9		8.3	ns
t_{ENZH}	Enable Pad Z to HIGH		3.6		4.0		4.5		5.3		7.4	ns
t_{ENZL}	Enable Pad Z to LOW		3.9		4.4		5.0		5.8		8.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.2		8.0		9.1		10.7		14.9	ns
t_{ENLZ}	Enable Pad LOW to Z		6.7		7.5		8.5		9.9		13.9	ns
t_{GLH}	G-to-Pad HIGH		4.8		5.3		6.0		7.2		10.0	ns
t_{GHL}	G-to-Pad LOW		4.8		5.3		6.0		7.2		10.0	ns
t_{LSU}	I/O Latch Output Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.7		8.5		9.6		11.3		15.9	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		14.8		16.5		18.7		22.0		30.8	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.05		0.05		0.06		0.07		0.10		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.05		0.06		0.08		ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		4.8		5.3		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW		3.5		3.9		4.1		4.9		6.8	ns
t_{ENZH}	Enable Pad Z to HIGH		3.6		4.0		4.5		5.3		7.4	ns
t_{ENZL}	Enable Pad Z to LOW		3.4		4.0		5.0		5.8		8.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.2		8.0		9.0		10.7		14.9	ns
t_{ENLZ}	Enable Pad LOW to Z		6.7		7.5		8.5		9.9		13.9	ns
t_{GLH}	G-to-Pad HIGH		6.8		7.6		8.6		10.1		14.2	ns
t_{GHL}	G-to-Pad LOW		6.8		7.6		8.6		10.1		14.2	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.7		8.5		9.6		11.3		15.9	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		14.8		16.5		18.7		22.0		30.8	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.05		0.05		0.06		0.07		0.10		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.04		0.04		0.05		0.06		0.08		ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX36 Timing Characteristics (Nominal 5.0V Operation)

(Worst-Case Commercial Conditions, V_{CCA} = 4.75V, T_J = 70°C)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Combinatorial Functions¹						
t _{PD} Internal Array Module Delay	1.3	1.5	1.7	2.0	2.7	ns
t _{PDD} Internal Decode Module Delay	1.6	1.8	2.0	2.4	3.3	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	0.9	1.0	1.2	1.4	2.0	ns
t _{RD2} FO=2 Routing Delay	1.3	1.4	1.6	1.9	2.7	ns
t _{RD3} FO=3 Routing Delay	1.6	1.8	2.0	2.4	3.4	ns
t _{RD4} FO=4 Routing Delay	2.0	2.2	2.5	2.9	4.1	ns
t _{RD5} FO=8 Routing Delay	3.3	3.7	4.2	4.9	6.9	ns
t _{RDD} Decode-to-Output Routing Delay	0.3	0.4	0.4	0.5	0.7	ns
Logic Module Sequential Timing^{3, 4}						
t _{CO} Flip-Flop Clock-to-Output	1.3	1.4	1.6	1.9	2.7	ns
t _{GO} Latch Gate-to-Output	1.3	1.4	1.6	1.9	2.7	ns
t _{SUD} Flip-Flop (Latch) Set-Up Time	0.3	0.3	0.4	0.5	0.7	ns
t _{HD} Flip-Flop (Latch) Hold Time	0.0	0.0	0.0	0.0	0.0	ns
t _{RO} Flip-Flop (Latch) Reset-to-Output	1.6	1.7	2.0	2.3	3.2	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	0.7	0.8	0.9	1.0	1.4	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	3.3	3.7	4.2	4.9	6.9	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.4	4.8	5.5	6.4	9.0	ns

Notes:

- For dual-module macros, use $t_{PDI} + t_{RD1} + t_{PDR}$, $t_{CO} + t_{RD1} + t_{PDR}$ or $t_{PDI} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX36 Timing Characteristics (Nominal 5.0V Operation) (continued)(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

Logic Module Timing		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{WC}	Write Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{RCKHL}	Clock HIGH/LOW Time	3.4		3.8		4.3		5.0		7.0		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.6		0.7		0.8		0.9		1.3		ns
t_{RENH}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	2.8		3.1		3.5		4.1		5.7		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t_{RPD}	Asynchronous Access Time		8.1		9.0		10.2		12.0		16.8	ns
t_{RDADV}	Read Address Valid	8.8		9.8		11.1		13.0		18.2		ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSUA}	Read Enable Set-Up to Address Valid	0.6		0.7		0.8		0.9		1.3		ns
t_{RENHA}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{DOH}	Data Out Hold Time		1.2		1.3		1.5		1.8		2.5	ns

A42MX36 Timing Characteristics (Nominal 5.0V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units	
Input Module Propagation Delays													
t_{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1	ns	
t_{INGO}	Input Latch Gate-to-Output			1.4		1.6		1.8		2.1		2.9	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns	
t_{INSU}	Input Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns	
t_{ILA}	Latch Active Pulse Width	4.7		5.2		5.9		6.9		9.7		ns	
Input Module Predicted Routing Delays¹													
t_{IRD1}	FO=1 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns	
t_{IRD2}	FO=2 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns	
t_{IRD3}	FO=3 Routing Delay		2.6		2.9		3.3		3.9		5.5	ns	
t_{IRD4}	FO=4 Routing Delay		3.0		3.3		3.8		4.4		6.2	ns	
t_{IRD8}	FO=8 Routing Delay		4.3		4.8		5.5		6.4		9.0	ns	
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO=32	2.7		3.0		3.4		4.0		5.6	ns	
		FO=635	3.0		3.3		3.8		4.4		6.2	ns	
t_{CKL}	Input HIGH to LOW	FO=32	3.8		4.2		4.8		5.6		7.8	ns	
		FO=635	4.9		5.4		6.1		7.2		10.1	ns	
t_{PWH}	Minimum Pulse Width HIGH	FO=32	1.8		2.0		2.2		2.6		3.6	ns	
		FO=635	2.0		2.2		2.5		2.9		4.1	ns	
t_{PWL}	Minimum Pulse Width LOW	FO=32	1.8		2.0		2.2		2.6		3.6	ns	
		FO=635	2.0		2.2		2.5		2.9		4.1	ns	
t_{CKSW}	Maximum Skew	FO=32	0.8		0.8		0.9		1.0		1.4	ns	
		FO=635	0.8		0.8		0.9		1.0		1.4	ns	
t_{SUEXT}	Input Latch External Set-Up	FO=32	0.0		0.0		0.0		0.0		0.0	ns	
		FO=635	0.0		0.0		0.0		0.0		0.0	ns	
t_{HEXT}	Input Latch External Hold	FO=32	2.8		3.2		3.6		4.2		5.9	ns	
		FO=635	3.3		3.7		4.2		4.9		6.9	ns	
t_P	Minimum Period ($1/f_{MAX}$)	FO=32	5.5		6.1		6.6		7.6		12.7	ns	
		FO=635	6.0		6.6		7.2		8.3		13.8	ns	
f_{MAX}	Maximum Datapath Frequency	FO=32	180		164		151		131		79	MHz	
		FO=635	166		151		139		121		73	MHz	

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX36 Timing Characteristics (Nominal 5.0V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 4.75V$, $T_J = 70^\circ C$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		2.6		2.8		3.2		3.8		5.3	ns
t_{DHL}	Data-to-Pad LOW		3.0		3.3		3.7		4.4		6.2	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t_{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t_{GLH}	G-to-Pad HIGH		2.9		3.3		3.7		4.4		6.1	ns
t_{GHL}	G-to-Pad LOW		2.9		3.3		3.7		4.4		6.1	ns
t_{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.07		0.08		0.09		0.10		0.10		0.14 ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.07		0.08		0.09		0.10		0.10		0.14 ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.5		3.9		4.5		5.2		7.3	ns
t_{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.3		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.3		5.8		6.6		7.8		10.9	ns
t_{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t_{GLH}	G-to-Pad HIGH		5.0		5.6		6.3		7.5		10.4	ns
t_{GHL}	G-to-Pad LOW		5.0		5.6		6.3		7.5		10.4	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.07		0.08		0.09		0.10		0.10		0.14 ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.07		0.08		0.09		0.10		0.10		0.14 ns/pF

Note:

1. Delays based on 35 pF loading.

A42MX36 Timing Characteristics (Nominal 3.3V Operation)

(Worst-Case Commercial Conditions, V_{CCA} = 3.0V, T_J = 70°C)

Parameter Description	'-3' Speed	'-2' Speed	'-1' Speed	'Std' Speed	'-F' Speed	
Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Combinatorial Functions¹						
t _{PD} Internal Array Module Delay	1.9	2.1	2.3	2.7	3.8	ns
t _{PDD} Internal Decode Module Delay	2.2	2.5	2.8	3.3	4.7	ns
Logic Module Predicted Routing Delays²						
t _{RD1} FO=1 Routing Delay	1.3	1.5	1.7	2.0	2.7	ns
t _{RD2} FO=2 Routing Delay	1.8	2.0	2.3	2.7	3.7	ns
t _{RD3} FO=3 Routing Delay	2.3	2.5	2.8	3.4	4.7	ns
t _{RD4} FO=4 Routing Delay	2.8	3.1	3.5	4.1	5.7	ns
t _{RD5} FO=8 Routing Delay	4.6	5.2	5.8	6.9	9.6	ns
t _{RDD} Decode-to-Output Routing Delay	0.5	0.5	0.6	0.7	1.0	ns
Logic Module Sequential Timing^{3, 4}						
t _{CO} Flip-Flop Clock-to-Output	1.8	2.0	2.3	2.7	3.7	ns
t _{GO} Latch Gate-to-Output	1.8	2.0	2.3	2.7	3.7	ns
t _{SUD} Flip-Flop (Latch) Set-Up Time	0.4	0.5	0.6	0.7	0.9	ns
t _{HD} Flip-Flop (Latch) Hold Time	0.0	0.0	0.0	0.0	0.0	ns
t _{RO} Flip-Flop (Latch) Reset-to-Output	2.2	2.4	2.7	3.2	4.5	ns
t _{SUENA} Flip-Flop (Latch) Enable Set-Up	1.0	1.1	1.2	1.4	2.0	ns
t _{HENA} Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.6	5.2	5.8	6.9	9.6	ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	6.1	6.8	7.7	9.0	12.6	ns

Notes:

- For dual-module macros, use $t_{PDI} + t_{RD1} + t_{PDR}$, $t_{CO} + t_{RD1} + t_{PDR}$ or $t_{PDI} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
- Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A42MX36 Timing Characteristics (Nominal 3.3V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

Logic Module Timing		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'-F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	9.5		10.5		11.9		14.0		19.6		ns
t_{WC}	Write Cycle Time	9.5		10.5		11.9		14.0		19.6		ns
t_{RCKHL}	Clock HIGH/LOW Time	4.8		5.3		6.0		7.0		9.8		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		4.8		5.3		6.0		7.0		9.8	ns
t_{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t_{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t_{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t_{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t_{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t_{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns

A42MX36 Timing Characteristics (Nominal 3.3V Operation) (continued)

 (Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}C$)

Parameter Description		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t_{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns
Input Module Predicted Routing Delays¹												
t_{IRD1}	FO=1 Routing Delay		2.8		3.1		3.5		4.1		5.7	ns
t_{IRD2}	FO=2 Routing Delay		3.2		3.5		4.1		4.8		6.7	ns
t_{IRD3}	FO=3 Routing Delay		3.7		4.1		4.7		5.5		7.7	ns
t_{IRD4}	FO=4 Routing Delay		4.2		4.6		5.3		6.2		8.7	ns
t_{IRD8}	FO=8 Routing Delay		6.1		6.8		7.7		9.0		12.6	ns
Global Clock Network												
t_{CKH}	Input LOW to HIGH	FO=32	4.6		5.1		5.7		6.7		9.3	ns
		FO=635	5.0		5.6		6.3		7.4		10.3	ns
t_{CKL}	Input HIGH to LOW	FO=32	5.3		5.9		6.7		7.8		11.0	ns
		FO=635	6.8		7.6		8.6		10.1		14.1	ns
t_{PWH}	Minimum Pulse Width HIGH	FO=32	2.5		2.7		3.1		3.6		5.1	ns
		FO=635	2.8		3.1		3.5		4.1		5.7	ns
t_{PWL}	Minimum Pulse Width LOW	FO=32	2.5		2.7		3.1		3.6		5.1	ns
		FO=635	2.8		3.1		3.5		4.1		5.7	ns
t_{CKSW}	Maximum Skew	FO=32	1.0		1.2		1.3		1.5		2.2	ns
		FO=635	1.0		1.2		1.3		1.5		2.2	ns
t_{SUEXT}	Input Latch External Set-Up	FO=32	0.0		0.0		0.0		0.0		0.0	ns
		FO=635	0.0		0.0		0.0		0.0		0.0	ns
t_{HEXT}	Input Latch External Hold	FO=32	4.0		4.4		5.0		5.9		8.2	ns
		FO=635	4.6		5.2		5.9		6.9		9.6	ns
t_p	Minimum Period ($1/f_{MAX}$)	FO=32	9.2		10.2		11.1		12.7		21.2	ns
		FO=635	9.9		11.0		12.0		13.8		23.0	ns
f_{MAX}	Maximum Datapath Frequency	FO=32	108		98		90		79		47	MHz
		FO=635	100		91		83		73		44	MHz

Note:

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

A42MX36 Timing Characteristics (Nominal 3.3V Operation) (continued)

(Worst-Case Commercial Conditions, $V_{CCA} = 3.0V$, $T_J = 70^{\circ}\text{C}$)

		'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		'F' Speed		
Parameter Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		3.6		4.0		4.5		5.3		7.4	ns
t_{DHL}	Data-to-Pad LOW			4.2		4.6		5.2		6.2		8.6 ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.2		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.34		8.2		9.3		10.9		15.3	ns
t_{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH		4.9		5.5		6.2		7.3		10.2	ns
t_{GHL}	G-to-Pad LOW		4.9		5.5		6.2		7.3		10.2	ns
t_{LSU}	I/O Latch Output Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.10		0.11		0.12		0.14		0.20		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.10		0.11		0.12		0.14		0.20		ns/pF
CMOS Output Module Timing¹												
t_{DLH}	Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t_{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t_{GHL}	G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d_{TLH}	Capacitive Loading, LOW to HIGH	0.10		0.11		0.12		0.14		0.20		ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW	0.10		0.11		0.12		0.14		0.20		ns/pF

Note:

1. Delays based on 35 pF loading.

Pin Descriptions

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/O Diagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND Ground

Input LOW supply voltage.

I/O Input/Output

Input, output, tristate or bi-directional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/Os pins are configured by the Designer software as shown in [Table 8](#).

Table 8 • Configuration of Unused I/Os

Device	Configuration
A40MX02, A40MX04	Pulled LOW
A42MX09, A42MX16	Pulled LOW
A42MX24, A42MX36	Tristated

In all cases, it is recommended to tie all unused MX I/O pins to LOW on the board. This applies to all dual-purpose pins when configured as I/Os as well.

LP Low Power Mode

Controls the low power mode of all 42MX devices. The device is placed in the low power mode by connecting the LP pin to logic HIGH. In low power mode, all I/Os are tristated, all input buffers are turned OFF, and the core of the device is turned OFF. To exit the low power mode, the LP pin must be set LOW. The device enters the low power mode 800ns after the LP pin is driven to a logic HIGH. It will resume normal operation in 200μs after the LP pin is driven to a logic LOW.

MODE Mode

Controls the use of multifunction pins (DCLK, PRA, PRB, SDI, TDO). The MODE pin is held HIGH to provide verification capability. The MODE pin should be terminated to GND through a 10kΩ resistor so that the MODE pin can be pulled HIGH when required.

NC No Connection

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

PRA, I/O

PRB, I/O Probe A/B

The Probe pin is used to output data from any user-defined design node within the device. Each diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. The Probe pin is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

QCLKA/B/C/D, I/O Quadrant Clock

Quadrant clock inputs for A42MX36 devices. When not used as a register control signal, these pins can function as user I/Os.

SDI, I/O Serial Data Input

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDO, I/O Serial Data Output

Serial data output for diagnostic probe and device programming. SDO is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW. SDO is available for 42MX devices only.

When Silicon Explorer II is being used, SDO will act as an output while the "checksum" command is run. It will return to user I/O when "checksum" is complete.

TCK, I/O Test Clock

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a $10\text{k}\Omega$ pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

V_{CC} Supply Voltage

Input supply voltage for 40MX devices

V_{CCA} Supply Voltage

Supply voltage for array in 42MX devices

V_{CCI} Supply Voltage

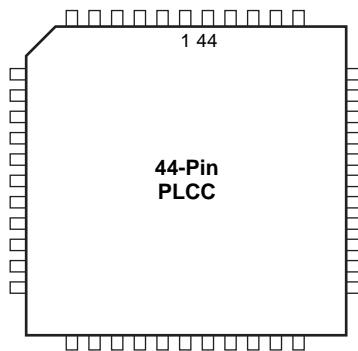
Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Package Pin Assignments

44-Pin PLCC

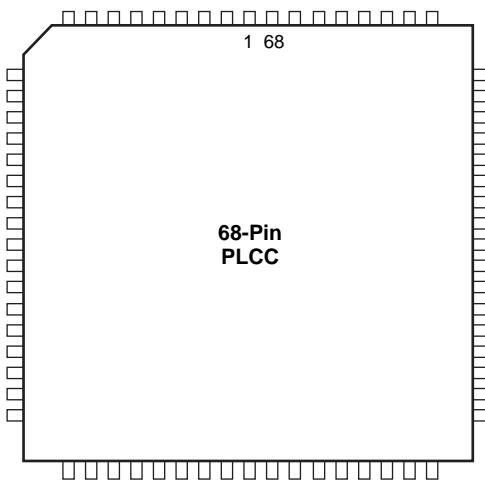


44-pin PLCC

Pin Number	A40MX02 Function	A40MX04 Function	Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O	23	I/O	I/O
2	I/O	I/O	24	I/O	I/O
3	V _{CC}	V _{CC}	25	V _{CC}	V _{CC}
4	I/O	I/O	26	I/O	I/O
5	I/O	I/O	27	I/O	I/O
6	I/O	I/O	28	I/O	I/O
7	I/O	I/O	29	I/O	I/O
8	I/O	I/O	30	I/O	I/O
9	I/O	I/O	31	I/O	I/O
10	GND	GND	32	GND	GND
11	I/O	I/O	33	CLK, I/O	CLK, I/O
12	I/O	I/O	34	MODE	MODE
13	I/O	I/O	35	V _{CC}	V _{CC}
14	V _{CC}	V _{CC}	36	SDI, I/O	SDI, I/O
15	I/O	I/O	37	DCLK, I/O	DCLK, I/O
16	V _{CC}	V _{CC}	38	PRA, I/O	PRA, I/O
17	I/O	I/O	39	PRB, I/O	PRB, I/O
18	I/O	I/O	40	I/O	I/O
19	I/O	I/O	41	I/O	I/O
20	I/O	I/O	42	I/O	I/O
21	GND	GND	43	GND	GND
22	I/O	I/O	44	I/O	I/O

Package Pin Assignments

68-Pin PLCC

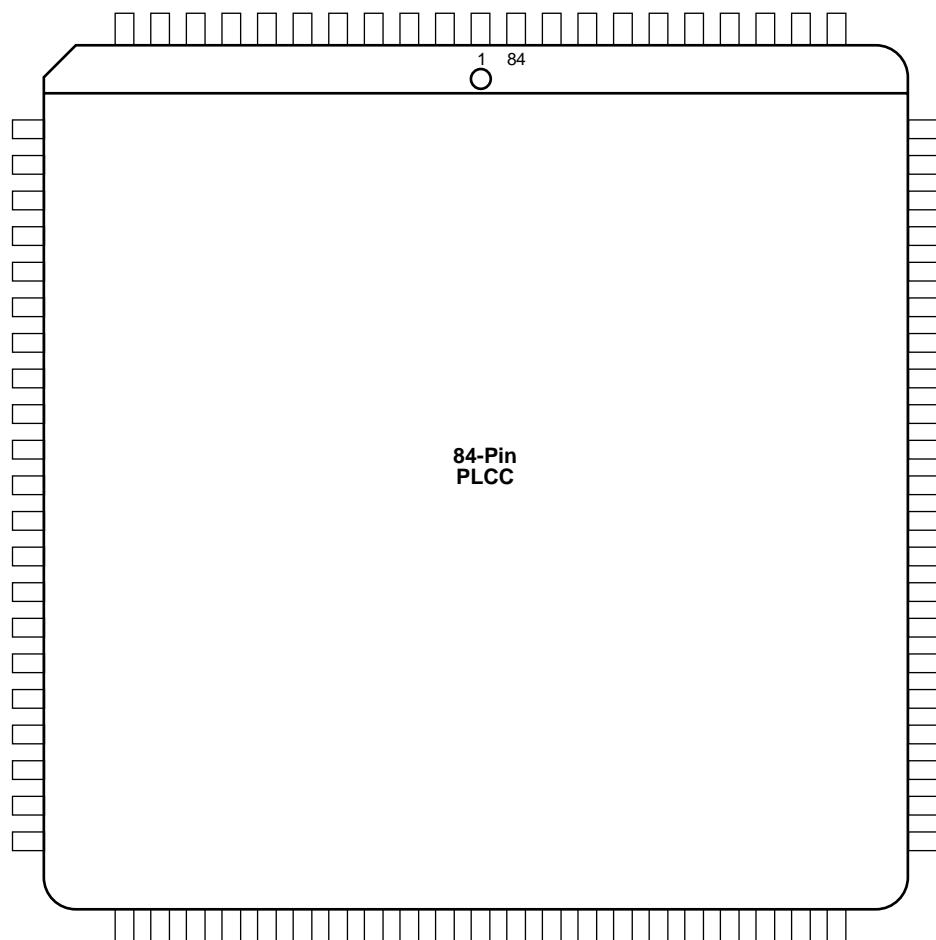


68-Pin PLCC

Pin Number	A40MX02 Function	A40MX04 Function	Pin Number	A40MX02 Function	A40MX04 Function	Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O	24	I/O	I/O	47	I/O	I/O
2	I/O	I/O	25	V _{CC}	V _{CC}	48	I/O	I/O
3	I/O	I/O	26	I/O	I/O	49	GND	GND
4	V _{CC}	V _{CC}	27	I/O	I/O	50	I/O	I/O
5	I/O	I/O	28	I/O	I/O	51	I/O	I/O
6	I/O	I/O	29	I/O	I/O	52	CLK, I/O	CLK, I/O
7	I/O	I/O	30	I/O	I/O	53	I/O	I/O
8	I/O	I/O	31	I/O	I/O	54	MODE	MODE
9	I/O	I/O	32	GND	GND	55	V _{CC}	V _{CC}
10	I/O	I/O	33	I/O	I/O	56	SDI, I/O	SDI, I/O
11	I/O	I/O	34	I/O	I/O	57	DCLK, I/O	DCLK, I/O
12	I/O	I/O	35	I/O	I/O	58	PRA, I/O	PRA, I/O
13	I/O	I/O	36	I/O	I/O	59	PRB, I/O	PRB, I/O
14	GND	GND	37	I/O	I/O	60	I/O	I/O
15	GND	GND	38	V _{CC}	V _{CC}	61	I/O	I/O
16	I/O	I/O	39	I/O	I/O	62	I/O	I/O
17	I/O	I/O	40	I/O	I/O	63	I/O	I/O
18	I/O	I/O	41	I/O	I/O	64	I/O	I/O
19	I/O	I/O	42	I/O	I/O	65	I/O	I/O
20	I/O	I/O	43	I/O	I/O	66	GND	GND
21	V _{CC}	V _{CC}	44	I/O	I/O	67	I/O	I/O
22	I/O	I/O	45	I/O	I/O	68	I/O	I/O
23	I/O	I/O	46	I/O	I/O			

Package Pin Assignments (continued)

84-Pin PLCC

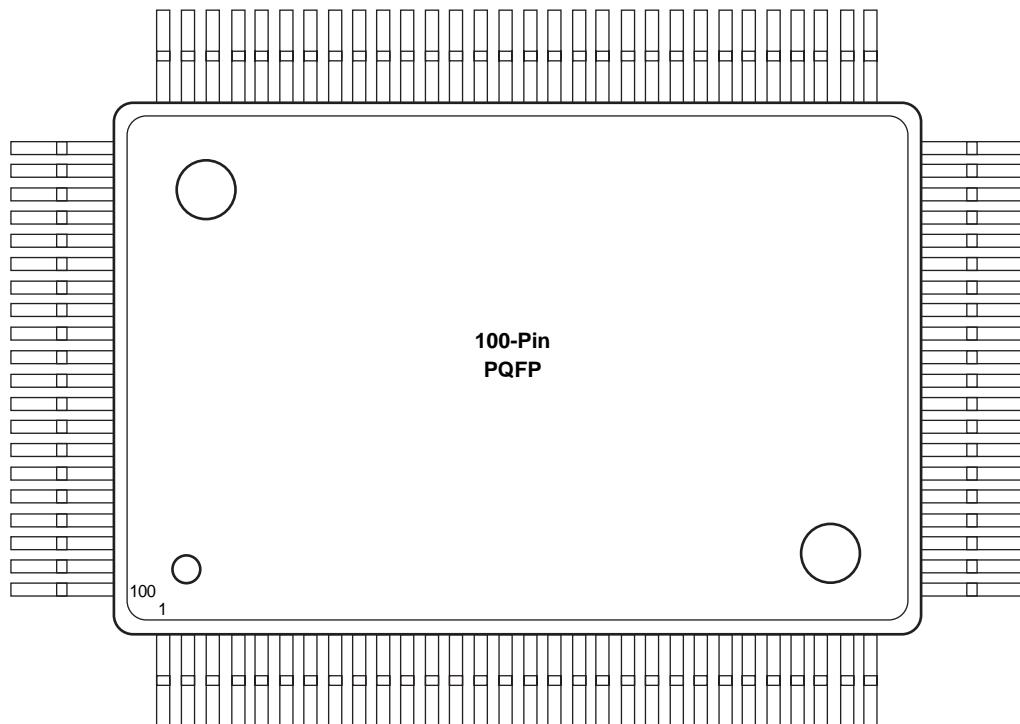


84-Pin PLCC

Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function	Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O	I/O	43	I/O	V _{CCA}	V _{CCA}	V _{CCA}
2	I/O	CLKB, I/O	CLKB, I/O	CLKB, I/O	44	I/O	I/O	I/O	WD, I/O
3	I/O	I/O	I/O	I/O	45	I/O	I/O	I/O	WD, I/O
4	V _{CC}	PRB, I/O	PRB, I/O	PRB, I/O	46	V _{CC}	I/O	I/O	WD, I/O
5	I/O	I/O	I/O	WD, I/O	47	I/O	I/O	I/O	WD, I/O
6	I/O	GND	GND	GND	48	I/O	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O	49	I/O	GND	GND	GND
8	I/O	I/O	I/O	WD, I/O	50	I/O	I/O	I/O	WD, I/O
9	I/O	I/O	I/O	WD, I/O	51	I/O	I/O	I/O	WD, I/O
10	I/O	DCLK, I/O	DCLK, I/O	DCLK, I/O	52	I/O	SDO, I/O	SDO, I/O	SDO, TDO, I/O
11	I/O	I/O	I/O	I/O	53	I/O	I/O	I/O	I/O
12	NC	MODE	MODE	MODE	54	I/O	I/O	I/O	I/O
13	I/O	I/O	I/O	I/O	55	I/O	I/O	I/O	I/O
14	I/O	I/O	I/O	I/O	56	I/O	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O	57	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O	58	I/O	I/O	I/O	I/O
17	I/O	I/O	I/O	I/O	59	I/O	I/O	I/O	I/O
18	GND	I/O	I/O	I/O	60	GND	I/O	I/O	I/O
19	GND	I/O	I/O	I/O	61	GND	I/O	I/O	I/O
20	I/O	I/O	I/O	I/O	62	I/O	I/O	I/O	TCK, I/O
21	I/O	I/O	I/O	I/O	63	I/O	LP	LP	LP
22	I/O	V _{CCA}	V _{CCI}	V _{CCI}	64	CLK, I/O	V _{CCA}	V _{CCA}	V _{CCA}
23	I/O	V _{CCI}	V _{CCA}	V _{CCA}	65	I/O	V _{CCI}	V _{CCI}	V _{CCI}
24	I/O	I/O	I/O	I/O	66	MODE	I/O	I/O	I/O
25	V _{CC}	I/O	I/O	I/O	67	V _{CC}	I/O	I/O	I/O
26	V _{CC}	I/O	I/O	I/O	68	V _{CC}	I/O	I/O	I/O
27	I/O	I/O	I/O	I/O	69	I/O	I/O	I/O	I/O
28	I/O	GND	GND	GND	70	I/O	GND	GND	GND
29	I/O	I/O	I/O	I/O	71	I/O	I/O	I/O	I/O
30	I/O	I/O	I/O	I/O	72	SDI, I/O	I/O	I/O	I/O
31	I/O	I/O	I/O	I/O	73	DCLK, I/O	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O	74	PRA, I/O	I/O	I/O	I/O
33	V _{CC}	I/O	I/O	I/O	75	PRB, I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	TMS, I/O	76	I/O	SDI, I/O	SDI, I/O	SDI, I/O
35	I/O	I/O	I/O	TDI, I/O	77	I/O	I/O	I/O	I/O
36	I/O	I/O	I/O	WD, I/O	78	I/O	I/O	I/O	WD, I/O
37	I/O	I/O	I/O	I/O	79	I/O	I/O	I/O	WD, I/O
38	I/O	I/O	I/O	WD, I/O	80	I/O	I/O	I/O	WD, I/O
39	I/O	I/O	I/O	WD, I/O	81	I/O	PRA, I/O	PRA, I/O	PRA, I/O
40	GND	I/O	I/O	I/O	82	GND	I/O	I/O	I/O
41	I/O	I/O	I/O	I/O	83	I/O	CLKA, I/O	CLKA, I/O	CLKA, I/O
42	I/O	I/O	I/O	I/O	84	I/O	V _{CCA}	V _{CCA}	V _{CCA}

Package Pin Assignments (continued)

100-Pin PQFP Package (Top View)



100-Pin PQFP

Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function	Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
1	NC	NC	I/O	I/O	40	I/O	I/O	V _{CCA}	V _{CCA}
2	NC	NC	DCLK, I/O	DCLK, I/O	41	I/O	I/O	I/O	I/O
3	NC	NC	I/O	I/O	42	I/O	I/O	I/O	I/O
4	NC	NC	MODE	MODE	43	V _{CC}	V _{CC}	I/O	I/O
5	NC	NC	I/O	I/O	44	V _{CC}	V _{CC}	I/O	I/O
6	PRB, I/O	PRB, I/O	I/O	I/O	45	I/O	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O	46	I/O	I/O	GND	GND
8	I/O	I/O	I/O	I/O	47	I/O	I/O	I/O	I/O
9	I/O	I/O	GND	GND	48	NC	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O	49	NC	I/O	I/O	I/O
11	I/O	I/O	I/O	I/O	50	NC	I/O	I/O	I/O
12	I/O	I/O	I/O	I/O	51	NC	NC	I/O	I/O
13	GND	GND	I/O	I/O	52	NC	NC	SDO, I/O	SDO, I/O
14	I/O	I/O	I/O	I/O	53	NC	NC	I/O	I/O
15	I/O	I/O	I/O	I/O	54	NC	NC	I/O	I/O
16	I/O	I/O	V _{CCA}	V _{CCA}	55	NC	NC	I/O	I/O
17	I/O	I/O	V _{CCI}	V _{CCA}	56	V _{CC}	V _{CC}	I/O	I/O
18	I/O	I/O	I/O	I/O	57	I/O	I/O	GND	GND
19	V _{CC}	V _{CC}	I/O	I/O	58	I/O	I/O	I/O	I/O
20	I/O	I/O	I/O	I/O	59	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O	60	I/O	I/O	I/O	I/O
22	I/O	I/O	GND	GND	61	I/O	I/O	I/O	I/O
23	I/O	I/O	I/O	I/O	62	I/O	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O	63	GND	GND	I/O	I/O
25	I/O	I/O	I/O	I/O	64	I/O	I/O	LP	LP
26	I/O	I/O	I/O	I/O	65	I/O	I/O	V _{CCA}	V _{CCA}
27	NC	NC	I/O	I/O	66	I/O	I/O	V _{CCI}	V _{CCI}
28	NC	NC	I/O	I/O	67	I/O	I/O	V _{CCA}	V _{CCA}
29	NC	NC	I/O	I/O	68	I/O	I/O	I/O	I/O
30	NC	NC	I/O	I/O	69	V _{CC}	V _{CC}	I/O	I/O
31	NC	I/O	I/O	I/O	70	I/O	I/O	I/O	I/O
32	NC	I/O	I/O	I/O	71	I/O	I/O	I/O	I/O
33	NC	I/O	I/O	I/O	72	I/O	I/O	GND	GND
34	I/O	I/O	GND	GND	73	I/O	I/O	I/O	I/O
35	I/O	I/O	I/O	I/O	74	I/O	I/O	I/O	I/O
36	GND	GND	I/O	I/O	75	I/O	I/O	I/O	I/O
37	GND	GND	I/O	I/O	76	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	I/O	77	NC	NC	I/O	I/O
39	I/O	I/O	I/O	I/O	78	NC	NC	I/O	I/O

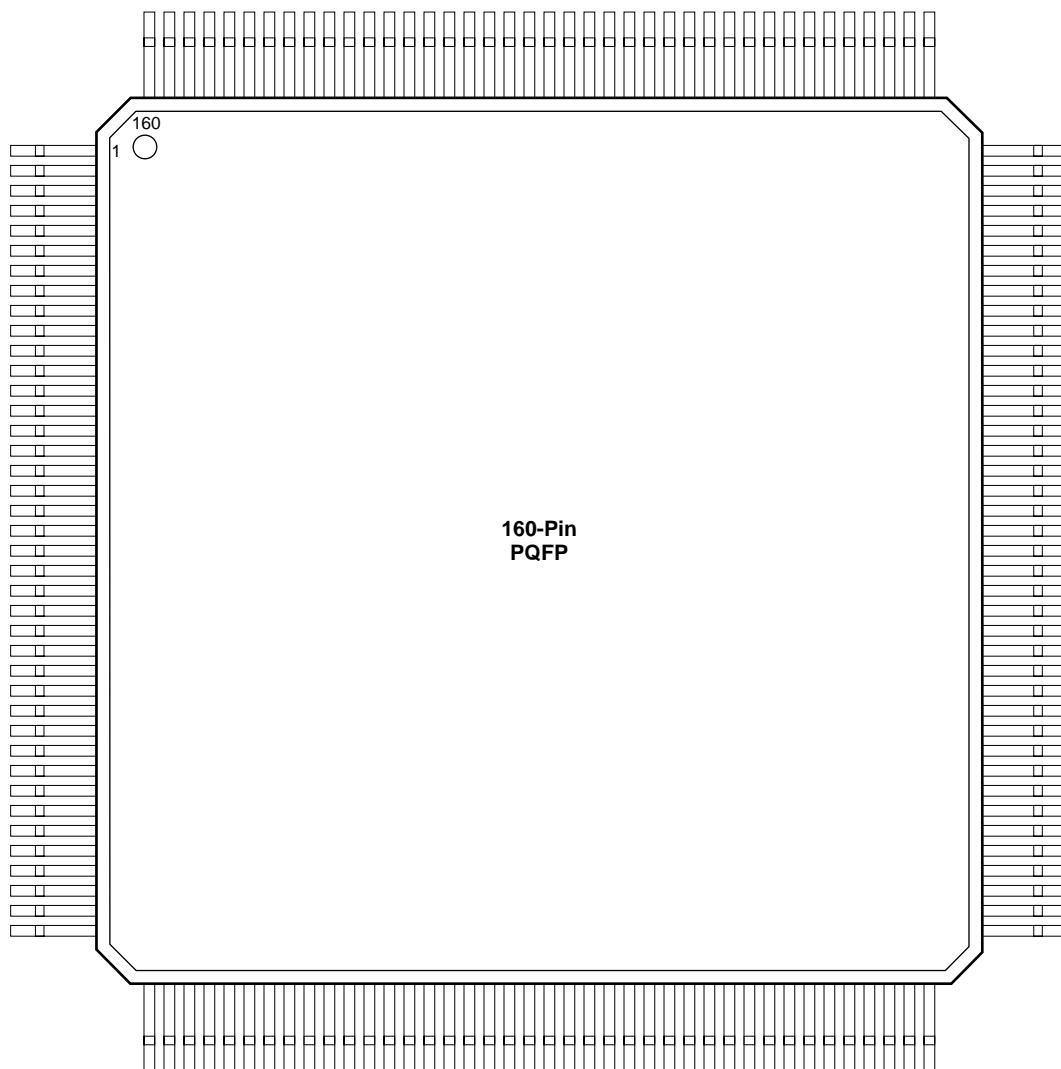
100-Pin PQFP (Continued)

Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O

Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
90	CLK, I/O	CLK, I/O	V _{CCA}	V _{CCA}
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O
93	V _{CC}	V _{CC}	I/O	I/O
94	V _{CC}	V _{CC}	PRB, I/O	PRB, I/O
95	NC	I/O	I/O	I/O
96	NC	I/O	GND	GND
97	NC	I/O	I/O	I/O
98	SDI, I/O	SDI, I/O	I/O	I/O
99	DCLK, I/O	DCLK, I/O	I/O	I/O
100	PRA, I/O	PRA, I/O	I/O	I/O

Package Pin Assignments (continued)

160-Pin PQFP Package (Top View)



160-Pin PQFP

Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O
2	DCLK, I/O	DCLK, I/O	DCLK, I/O
3	NC	I/O	I/O
4	I/O	I/O	WD, I/O
5	I/O	I/O	WD, I/O
6	NC	V _{CCI}	V _{CCI}
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	NC	I/O	I/O
11	GND	GND	GND
12	NC	I/O	I/O
13	I/O	I/O	WD, I/O
14	I/O	I/O	WD, I/O
15	I/O	I/O	I/O
16	PRB, I/O	PRB, I/O	PRB, I/O
17	I/O	I/O	I/O
18	CLKB, I/O	CLKB, I/O	CLKB, I/O
19	I/O	I/O	I/O
20	V _{CCA}	V _{CCA}	V _{CCA}
21	CLKA, I/O	CLKA, I/O	CLKA, I/O
22	I/O	I/O	I/O
23	PRA, I/O	PRA, I/O	PRA, I/O
24	NC	I/O	WD, I/O
25	I/O	I/O	WD, I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	NC	I/O	I/O
29	I/O	I/O	WD, I/O
30	GND	GND	GND
31	NC	I/O	WD, I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	V _{CCI}	V _{CCI}
36	I/O	I/O	WD, I/O
37	I/O	I/O	WD, I/O
38	SDI, I/O	SDI, I/O	SDI, I/O
39	I/O	I/O	I/O
40	GND	GND	GND

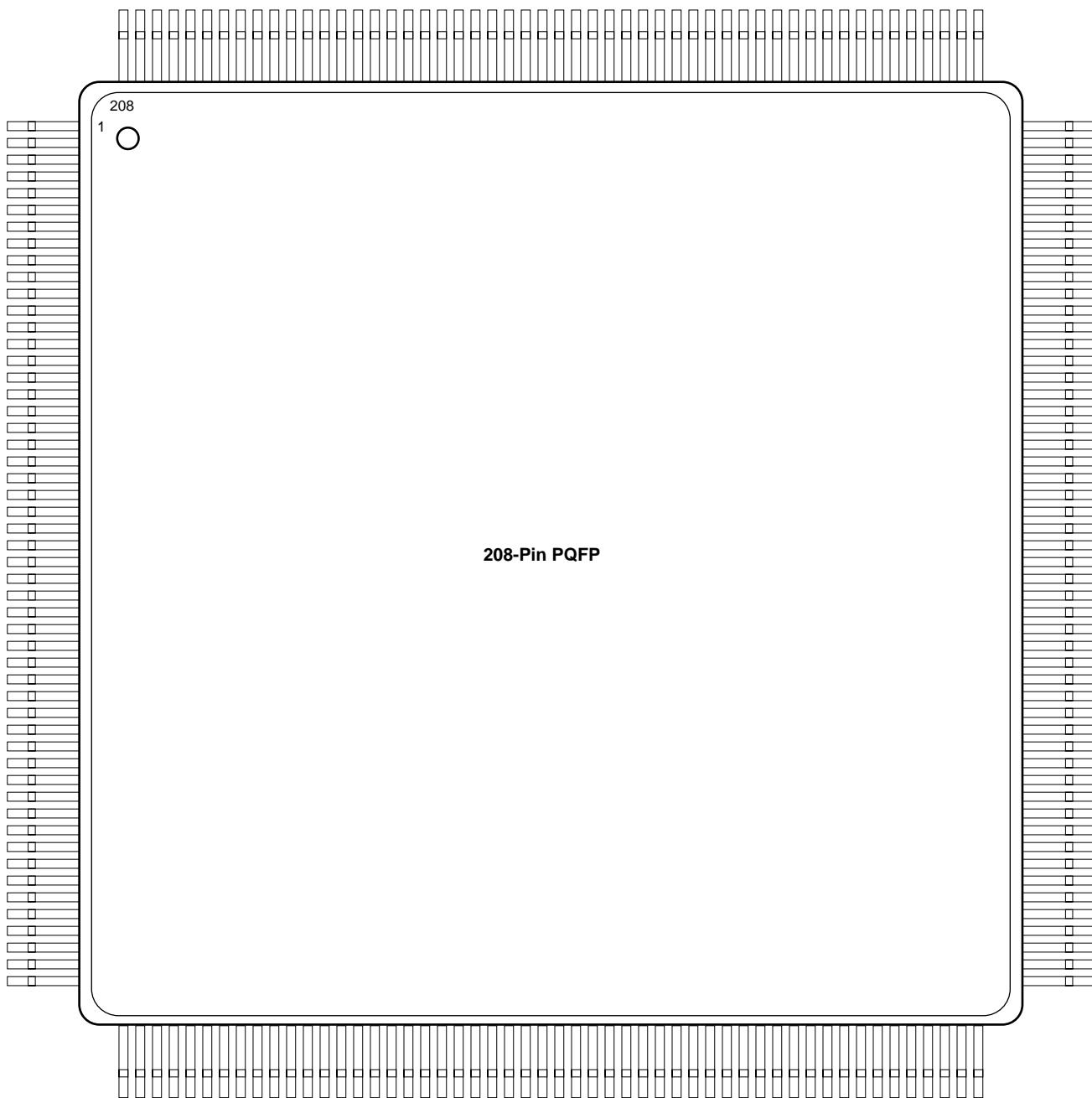
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	GND	GND	GND
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	NC	I/O	I/O
53	I/O	I/O	I/O
54	NC	V _{CCA}	V _{CCA}
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	V _{CCA}	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}	V _{CCI}
59	GND	GND	GND
60	V _{CCA}	V _{CCA}	V _{CCA}
61	LP	LP	LP
62	I/O	I/O	TCK, I/O
63	I/O	I/O	I/O
64	GND	GND	GND
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	I/O	I/O	I/O
69	GND	GND	GND
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	NC	I/O	I/O
76	I/O	I/O	I/O
77	NC	I/O	I/O
78	I/O	I/O	I/O
79	NC	I/O	I/O
80	GND	GND	GND

160-Pin PQFP (Continued)

Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function	Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
81	I/O	I/O	I/O	121	I/O	I/O	I/O
82	SDO, I/O	SDO, I/O	SDO, TDO, I/O	122	I/O	I/O	I/O
83	I/O	I/O	WD, I/O	123	I/O	I/O	I/O
84	I/O	I/O	WD, I/O	124	NC	I/O	I/O
85	I/O	I/O	I/O	125	GND	GND	GND
86	NC	V _{CCI}	V _{CCI}	126	I/O	I/O	I/O
87	I/O	I/O	I/O	127	I/O	I/O	I/O
88	I/O	I/O	WD, I/O	128	I/O	I/O	I/O
89	GND	GND	GND	129	NC	I/O	I/O
90	NC	I/O	I/O	130	GND	GND	GND
91	I/O	I/O	I/O	131	I/O	I/O	I/O
92	I/O	I/O	I/O	132	I/O	I/O	I/O
93	I/O	I/O	I/O	133	I/O	I/O	I/O
94	I/O	I/O	I/O	134	I/O	I/O	I/O
95	I/O	I/O	I/O	135	NC	V _{CCA}	V _{CCA}
96	I/O	I/O	WD, I/O	136	I/O	I/O	I/O
97	I/O	I/O	I/O	137	I/O	I/O	I/O
98	V _{CCA}	V _{CCA}	V _{CCA}	138	NC	V _{CCA}	V _{CCA}
99	GND	GND	GND	139	V _{CCI}	V _{CCI}	V _{CCI}
100	NC	I/O	I/O	140	GND	GND	GND
101	I/O	I/O	I/O	141	NC	I/O	I/O
102	I/O	I/O	I/O	142	I/O	I/O	I/O
103	NC	I/O	I/O	143	I/O	I/O	I/O
104	I/O	I/O	I/O	144	I/O	I/O	I/O
105	I/O	I/O	I/O	145	GND	GND	GND
106	I/O	I/O	WD, I/O	146	NC	I/O	I/O
107	I/O	I/O	WD, I/O	147	I/O	I/O	I/O
108	I/O	I/O	I/O	148	I/O	I/O	I/O
109	GND	GND	GND	149	I/O	I/O	I/O
110	NC	I/O	I/O	150	NC	V _{CCA}	V _{CCA}
111	I/O	I/O	WD, I/O	151	NC	I/O	I/O
112	I/O	I/O	WD, I/O	152	NC	I/O	I/O
113	I/O	I/O	I/O	153	NC	I/O	I/O
114	NC	V _{CCI}	V _{CCI}	154	NC	I/O	I/O
115	I/O	I/O	WD, I/O	155	GND	GND	GND
116	NC	I/O	WD, I/O	156	I/O	I/O	I/O
117	I/O	I/O	I/O	157	I/O	I/O	I/O
118	I/O	I/O	TDI, I/O	158	I/O	I/O	I/O
119	I/O	I/O	TMS, I/O	159	MODE	MODE	MODE
120	GND	GND	GND	160	GND	GND	GND

Package Pin Assignments (continued)

208-Pin PQFP Package (Top View)



208-Pin PQFP

Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
1	GND	GND	GND	43	NC	I/O	I/O
2	NC	V _{CCA}	V _{CCA}	44	I/O	I/O	I/O
3	MODE	MODE	MODE	45	I/O	I/O	I/O
4	I/O	I/O	I/O	46	I/O	I/O	I/O
5	I/O	I/O	I/O	47	I/O	I/O	I/O
6	I/O	I/O	I/O	48	I/O	I/O	I/O
7	I/O	I/O	I/O	49	I/O	I/O	I/O
8	I/O	I/O	I/O	50	NC	I/O	I/O
9	NC	I/O	I/O	51	NC	I/O	I/O
10	NC	I/O	I/O	52	GND	GND	GND
11	NC	I/O	I/O	53	GND	GND	GND
12	I/O	I/O	I/O	54	I/O	TMS, I/O	TMS, I/O
13	I/O	I/O	I/O	55	I/O	TDI, I/O	TDI, I/O
14	I/O	I/O	I/O	56	I/O	I/O	I/O
15	I/O	I/O	I/O	57	I/O	WD, I/O	WD, I/O
16	NC	I/O	I/O	58	I/O	WD, I/O	WD, I/O
17	V _{CCA}	V _{CCA}	V _{CCA}	59	I/O	I/O	I/O
18	I/O	I/O	I/O	60	V _{CCI}	V _{CCI}	V _{CCI}
19	I/O	I/O	I/O	61	NC	I/O	I/O
20	I/O	I/O	I/O	62	NC	I/O	I/O
21	I/O	I/O	I/O	63	I/O	I/O	I/O
22	GND	GND	GND	64	I/O	I/O	I/O
23	I/O	I/O	I/O	65	I/O	I/O	QCLKA, I/O
24	I/O	I/O	I/O	66	I/O	WD, I/O	WD, I/O
25	I/O	I/O	I/O	67	NC	WD, I/O	WD, I/O
26	I/O	I/O	I/O	68	NC	I/O	I/O
27	GND	GND	GND	69	I/O	I/O	I/O
28	V _{CCI}	V _{CCI}	V _{CCI}	70	I/O	WD, I/O	WD, I/O
29	V _{CCA}	V _{CCA}	V _{CCA}	71	I/O	WD, I/O	WD, I/O
30	I/O	I/O	I/O	72	I/O	I/O	I/O
31	I/O	I/O	I/O	73	I/O	I/O	I/O
32	V _{CCA}	V _{CCA}	V _{CCA}	74	I/O	I/O	I/O
33	I/O	I/O	I/O	75	I/O	I/O	I/O
34	I/O	I/O	I/O	76	I/O	I/O	I/O
35	I/O	I/O	I/O	77	I/O	I/O	I/O
36	I/O	I/O	I/O	78	GND	GND	GND
37	I/O	I/O	I/O	79	V _{CCA}	V _{CCA}	V _{CCA}
38	I/O	I/O	I/O	80	NC	V _{CCI}	V _{CCI}
39	I/O	I/O	I/O	81	I/O	I/O	I/O
40	I/O	I/O	I/O	82	I/O	I/O	I/O
41	NC	I/O	I/O	83	I/O	I/O	I/O
42	NC	I/O	I/O	84	I/O	I/O	I/O

208-Pin PQFP (Continued)

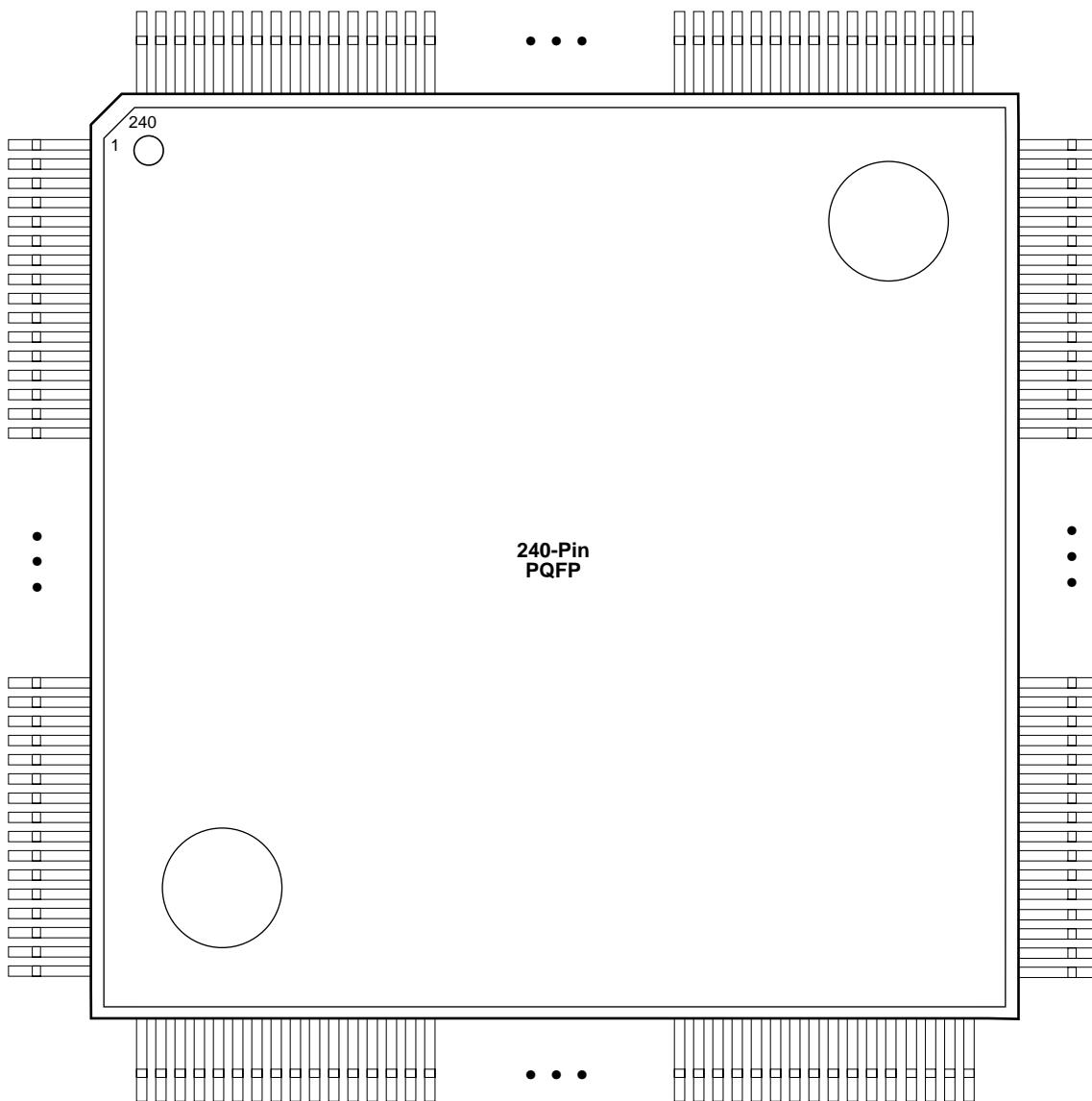
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
85	I/O	WD, I/O	WD, I/O	127	I/O	I/O	I/O
86	I/O	WD, I/O	WD, I/O	128	I/O	TCK, I/O	TCK, I/O
87	I/O	I/O	I/O	129	LP	LP	LP
88	I/O	I/O	I/O	130	V _{CCA}	V _{CCA}	V _{CCA}
89	NC	I/O	I/O	131	GND	GND	GND
90	NC	I/O	I/O	132	V _{CCI}	V _{CCI}	V _{CCI}
91	I/O	I/O	QCLKB, I/O	133	V _{CCA}	V _{CCA}	V _{CCA}
92	I/O	I/O	I/O	134	I/O	I/O	I/O
93	I/O	WD, I/O	WD, I/O	135	I/O	I/O	I/O
94	I/O	WD, I/O	WD, I/O	136	V _{CCA}	V _{CCA}	V _{CCA}
95	NC	I/O	I/O	137	I/O	I/O	I/O
96	NC	I/O	I/O	138	I/O	I/O	I/O
97	NC	I/O	I/O	139	I/O	I/O	I/O
98	V _{CCI}	V _{CCI}	V _{CCI}	140	I/O	I/O	I/O
99	I/O	I/O	I/O	141	NC	I/O	I/O
100	I/O	WD, I/O	WD, I/O	142	I/O	I/O	I/O
101	I/O	WD, I/O	WD, I/O	143	I/O	I/O	I/O
102	I/O	I/O	I/O	144	I/O	I/O	I/O
103	SDO, I/O	SDO, TDO, I/O	SDO, TDO, I/O	145	I/O	I/O	I/O
104	I/O	I/O	I/O	146	NC	I/O	I/O
105	GND	GND	GND	147	NC	I/O	I/O
106	NC	V _{CCA}	V _{CCA}	148	NC	I/O	I/O
107	I/O	I/O	I/O	149	NC	I/O	I/O
108	I/O	I/O	I/O	150	GND	GND	GND
109	I/O	I/O	I/O	151	I/O	I/O	I/O
110	I/O	I/O	I/O	152	I/O	I/O	I/O
111	I/O	I/O	I/O	153	I/O	I/O	I/O
112	NC	I/O	I/O	154	I/O	I/O	I/O
113	NC	I/O	I/O	155	I/O	I/O	I/O
114	NC	I/O	I/O	156	I/O	I/O	I/O
115	NC	I/O	I/O	157	GND	GND	GND
116	I/O	I/O	I/O	158	I/O	I/O	I/O
117	I/O	I/O	I/O	159	SDI, I/O	SDI, I/O	SDI, I/O
118	I/O	I/O	I/O	160	I/O	I/O	I/O
119	I/O	I/O	I/O	161	I/O	WD, I/O	WD, I/O
120	I/O	I/O	I/O	162	I/O	WD, I/O	WD, I/O
121	I/O	I/O	I/O	163	I/O	I/O	I/O
122	I/O	I/O	I/O	164	V _{CCI}	V _{CCI}	V _{CCI}
123	I/O	I/O	I/O	165	NC	I/O	I/O
124	I/O	I/O	I/O	166	NC	I/O	I/O
125	I/O	I/O	I/O	167	I/O	I/O	I/O
126	GND	GND	GND	168	I/O	WD, I/O	WD, I/O

208-Pin PQFP (Continued)

Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function	Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
169	I/O	WD, I/O	WD, I/O	189	I/O	I/O	I/O
170	I/O	I/O	I/O	190	I/O	WD, I/O	WD, I/O
171	NC	I/O	QCLKD, I/O	191	I/O	WD, I/O	WD, I/O
172	I/O	I/O	I/O	192	I/O	I/O	I/O
173	I/O	I/O	I/O	193	NC	I/O	I/O
174	I/O	I/O	I/O	194	NC	WD, I/O	WD, I/O
175	I/O	I/O	I/O	195	NC	WD, I/O	WD, I/O
176	I/O	WD, I/O	WD, I/O	196	I/O	I/O	QCLKC, I/O
177	I/O	WD, I/O	WD, I/O	197	NC	I/O	I/O
178	PRA, I/O	PRA, I/O	PRA, I/O	198	I/O	I/O	I/O
179	I/O	I/O	I/O	199	I/O	I/O	I/O
180	CLKA, I/O	CLKA, I/O	CLKA, I/O	200	I/O	I/O	I/O
181	NC	I/O	I/O	201	NC	I/O	I/O
182	NC	V _{CCI}	V _{CCI}	202	V _{CCI}	V _{CCI}	V _{CCI}
183	V _{CCA}	V _{CCA}	V _{CCA}	203	I/O	WD, I/O	WD, I/O
184	GND	GND	GND	204	I/O	WD, I/O	WD, I/O
185	I/O	I/O	I/O	205	I/O	I/O	I/O
186	CLKB, I/O	CLKB, I/O	CLKB, I/O	206	I/O	I/O	I/O
187	I/O	I/O	I/O	207	DCLK, I/O	DCLK, I/O	DCLK, I/O
188	PRB, I/O	PRB, I/O	PRB, I/O	208	I/O	I/O	I/O

Package Pin Assignments (continued)

240-Pin PQFP Package (Top View)



240-Pin PQFP

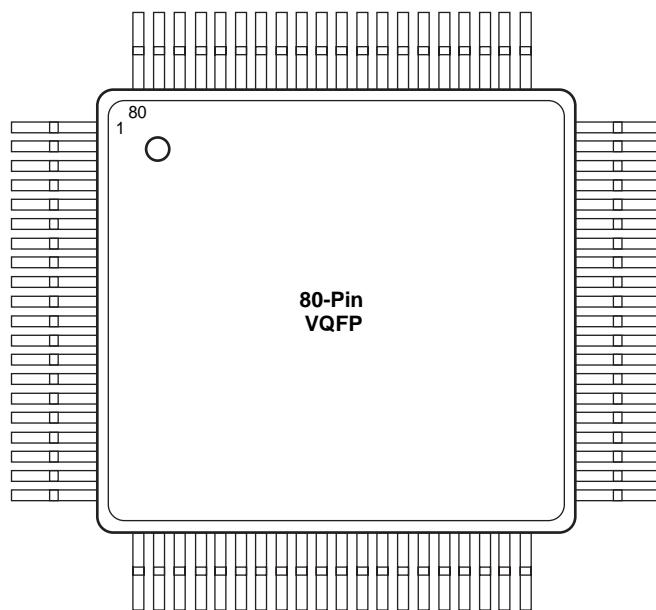
Pin Number	A42MX36 Function						
1	I/O	41	I/O	81	I/O	121	GND
2	DCLK, I/O	42	I/O	82	I/O	122	I/O
3	I/O	43	I/O	83	I/O	123	SDO, TDO, I/O
4	I/O	44	I/O	84	I/O	124	I/O
5	I/O	45	QCLKD, I/O	85	V _{CCA}	125	WD, I/O
6	WD, I/O	46	I/O	86	I/O	126	WD, I/O
7	WD, I/O	47	WD, I/O	87	I/O	127	I/O
8	V _{CCI}	48	WD, I/O	88	V _{CCA}	128	V _{CCI}
9	I/O	49	I/O	89	V _{CCI}	129	I/O
10	I/O	50	I/O	90	V _{CCA}	130	I/O
11	I/O	51	I/O	91	LP	131	I/O
12	I/O	52	V _{CCI}	92	TCK, I/O	132	WD, I/O
13	I/O	53	I/O	93	I/O	133	WD, I/O
14	I/O	54	WD, I/O	94	GND	134	I/O
15	QCLKC, I/O	55	WD, I/O	95	I/O	135	QCLKB, I/O
16	I/O	56	I/O	96	I/O	136	I/O
17	WD, I/O	57	SDI, I/O	97	I/O	137	I/O
18	WD, I/O	58	I/O	98	I/O	138	I/O
19	I/O	59	V _{CCA}	99	I/O	139	I/O
20	I/O	60	GND	100	I/O	140	I/O
21	WD, I/O	61	GND	101	I/O	141	I/O
22	WD, I/O	62	I/O	102	I/O	142	WD, I/O
23	I/O	63	I/O	103	I/O	143	WD, I/O
24	PRB, I/O	64	I/O	104	I/O	144	I/O
25	I/O	65	I/O	105	I/O	145	I/O
26	CLKB, I/O	66	I/O	106	I/O	146	I/O
27	I/O	67	I/O	107	I/O	147	I/O
28	GND	68	I/O	108	V _{CCI}	148	I/O
29	V _{CCA}	69	I/O	109	I/O	149	I/O
30	V _{CCI}	70	I/O	110	I/O	150	V _{CCI}
31	I/O	71	V _{CCI}	111	I/O	151	V _{CCA}
32	CLKA, I/O	72	I/O	112	I/O	152	GND
33	I/O	73	I/O	113	I/O	153	I/O
34	PRA, I/O	74	I/O	114	I/O	154	I/O
35	I/O	75	I/O	115	I/O	155	I/O
36	I/O	76	I/O	116	I/O	156	I/O
37	WD, I/O	77	I/O	117	I/O	157	I/O
38	WD, I/O	78	I/O	118	V _{CCA}	158	I/O
39	I/O	79	I/O	119	GND	159	WD, I/O
40	I/O	80	I/O	120	GND	160	WD, I/O

240-Pin PQFP (Continued)

Pin Number	A42MX36 Function						
161	I/O	181	V _{CCA}	201	I/O	221	I/O
162	I/O	182	GND	202	I/O	222	I/O
163	WD, I/O	183	I/O	203	I/O	223	I/O
164	WD, I/O	184	I/O	204	I/O	224	I/O
165	I/O	185	I/O	205	I/O	225	I/O
166	QCLKA, I/O	186	I/O	206	V _{CCA}	226	I/O
167	I/O	187	I/O	207	I/O	227	V _{CCI}
168	I/O	188	I/O	208	I/O	228	I/O
169	I/O	189	I/O	209	V _{CCA}	229	I/O
170	I/O	190	I/O	210	V _{CCI}	230	I/O
171	I/O	191	I/O	211	I/O	231	I/O
172	V _{CCI}	192	V _{CCI}	212	I/O	232	I/O
173	I/O	193	I/O	213	I/O	233	I/O
174	WD, I/O	194	I/O	214	I/O	234	I/O
175	WD, I/O	195	I/O	215	I/O	235	I/O
176	I/O	196	I/O	216	I/O	236	I/O
177	I/O	197	I/O	217	I/O	237	GND
178	TDI, I/O	198	I/O	218	I/O	238	MODE
179	TMS, I/O	199	I/O	219	V _{CCA}	239	V _{CCA}
180	GND	200	I/O	220	I/O	240	GND

Package Pin Assignments (continued)

80-Pin VQFP

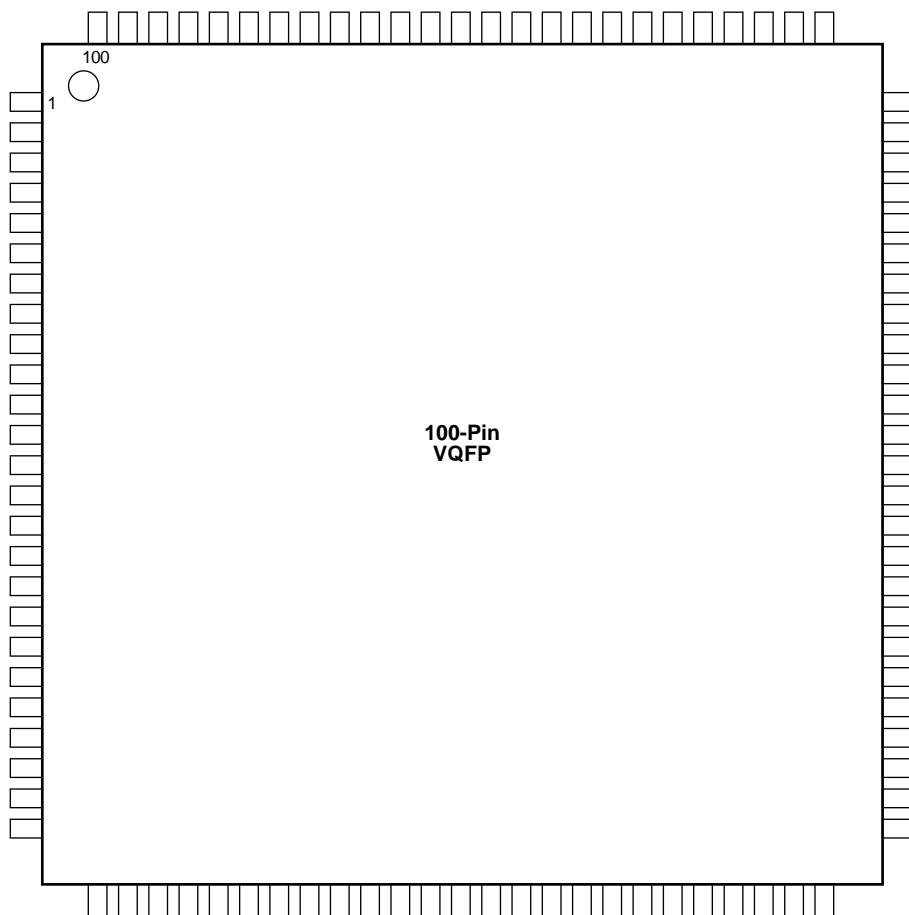


80-Pin VQFP

Pin Number	A40MX02 Function	A40MX04 Function	Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O	41	NC	I/O
2	NC	I/O	42	NC	I/O
3	NC	I/O	43	NC	I/O
4	NC	I/O	44	I/O	I/O
5	I/O	I/O	45	I/O	I/O
6	I/O	I/O	46	I/O	I/O
7	GND	GND	47	GND	GND
8	I/O	I/O	48	I/O	I/O
9	I/O	I/O	49	I/O	I/O
10	I/O	I/O	50	CLK, I/O	CLK, I/O
11	I/O	I/O	51	I/O	I/O
12	I/O	I/O	52	MODE	MODE
13	V _{CC}	V _{CC}	53	V _{CC}	V _{CC}
14	I/O	I/O	54	NC	I/O
15	I/O	I/O	55	NC	I/O
16	I/O	I/O	56	NC	I/O
17	NC	I/O	57	SDI, I/O	SDI, I/O
18	NC	I/O	58	DCLK, I/O	DCLK, I/O
19	NC	I/O	59	PRA, I/O	PRA, I/O
20	V _{CC}	V _{CC}	60	NC	NC
21	I/O	I/O	61	PRB, I/O	PRB, I/O
22	I/O	I/O	62	I/O	I/O
23	I/O	I/O	63	I/O	I/O
24	I/O	I/O	64	I/O	I/O
25	I/O	I/O	65	I/O	I/O
26	I/O	I/O	66	I/O	I/O
27	GND	GND	67	I/O	I/O
28	I/O	I/O	68	GND	GND
29	I/O	I/O	69	I/O	I/O
30	I/O	I/O	70	I/O	I/O
31	I/O	I/O	71	I/O	I/O
32	I/O	I/O	72	I/O	I/O
33	V _{CC}	V _{CC}	73	I/O	I/O
34	I/O	I/O	74	V _{CC}	V _{CC}
35	I/O	I/O	75	I/O	I/O
36	I/O	I/O	76	I/O	I/O
37	I/O	I/O	77	I/O	I/O
38	I/O	I/O	78	I/O	I/O
39	I/O	I/O	79	I/O	I/O
40	I/O	I/O	80	I/O	I/O

Package Pin Assignments (continued)

100-Pin VQFP Package (Top View)

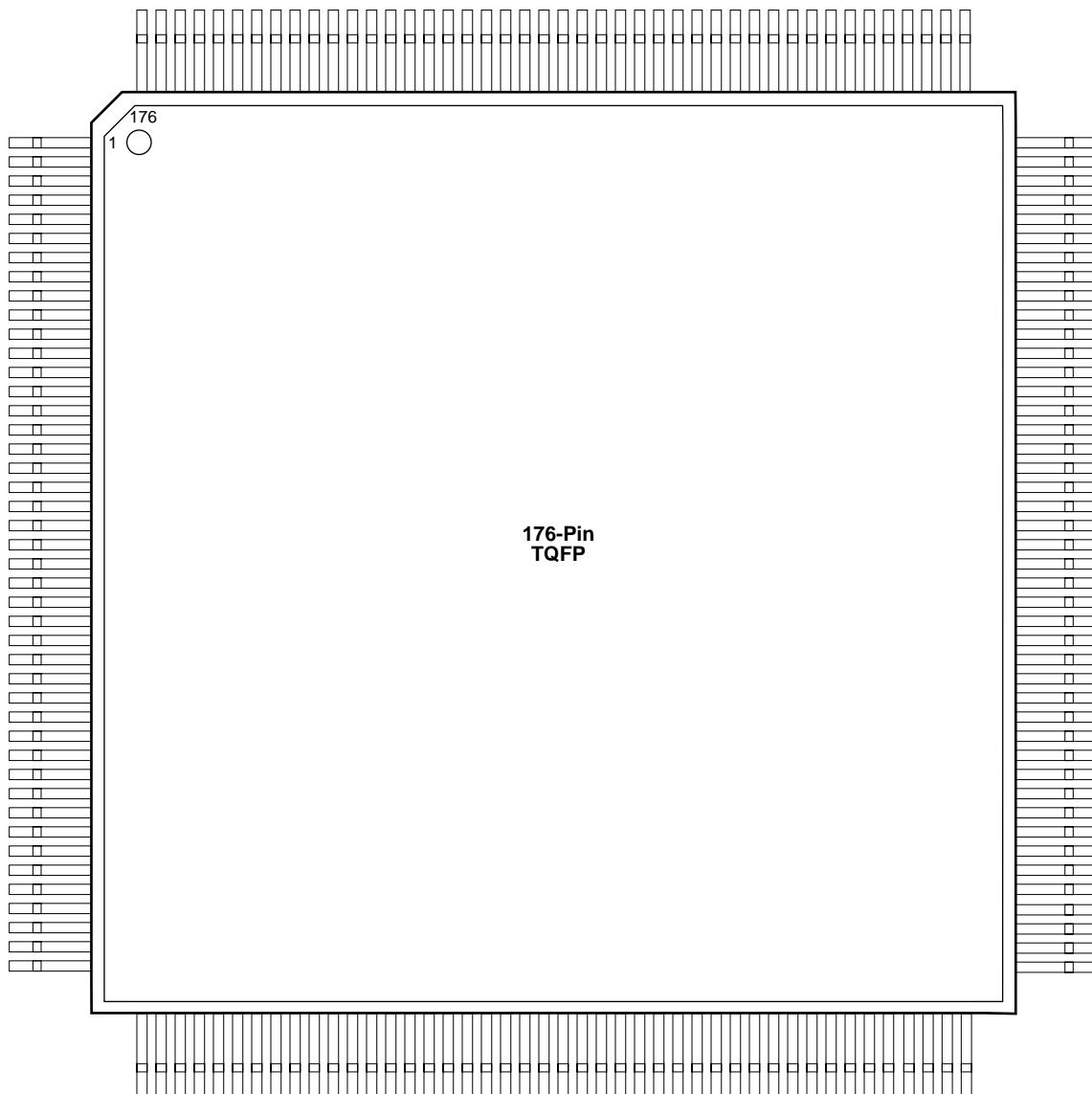


100-Pin VQFP Package

Pin Number	A42MX09 Function	A42MX16 Function	Pin Number	A42MX09 Function	A42MX16 Function
1	I/O	I/O	51	I/O	I/O
2	MODE	MODE	52	I/O	I/O
3	I/O	I/O	53	I/O	I/O
4	I/O	I/O	54	I/O	I/O
5	I/O	I/O	55	GND	GND
6	I/O	I/O	56	I/O	I/O
7	GND	GND	57	I/O	I/O
8	I/O	I/O	58	I/O	I/O
9	I/O	I/O	59	I/O	I/O
10	I/O	I/O	60	I/O	I/O
11	I/O	I/O	61	I/O	I/O
12	I/O	I/O	62	LP	LP
13	I/O	I/O	63	V _{CCA}	V _{CCA}
14	V _{CCA}	NC	64	V _{CCI}	V _{CCI}
15	V _{CCI}	V _{CCI}	65	V _{CCA}	V _{CCA}
16	I/O	I/O	66	I/O	I/O
17	I/O	I/O	67	I/O	I/O
18	I/O	I/O	68	I/O	I/O
19	I/O	I/O	69	I/O	I/O
20	GND	GND	70	GND	GND
21	I/O	I/O	71	I/O	I/O
22	I/O	I/O	72	I/O	I/O
23	I/O	I/O	73	I/O	I/O
24	I/O	I/O	74	I/O	I/O
25	I/O	I/O	75	I/O	I/O
26	I/O	I/O	76	I/O	I/O
27	I/O	I/O	77	SDI, I/O	SDI, I/O
28	I/O	I/O	78	I/O	I/O
29	I/O	I/O	79	I/O	I/O
30	I/O	I/O	80	I/O	I/O
31	I/O	I/O	81	I/O	I/O
32	GND	GND	82	GND	GND
33	I/O	I/O	83	I/O	I/O
34	I/O	I/O	84	I/O	I/O
35	I/O	I/O	85	PRA, I/O	PRA, I/O
36	I/O	I/O	86	I/O	I/O
37	I/O	I/O	87	CLKA, I/O	CLKA, I/O
38	V _{CCA}	V _{CCA}	88	V _{CCA}	V _{CCA}
39	I/O	I/O	89	I/O	I/O
40	I/O	I/O	90	CLKB, I/O	CLKB, I/O
41	I/O	I/O	91	I/O	I/O
42	I/O	I/O	92	PRB, I/O	PRB, I/O
43	I/O	I/O	93	I/O	I/O
44	GND	GND	94	GND	GND
45	I/O	I/O	95	I/O	I/O
46	I/O	I/O	96	I/O	I/O
47	I/O	I/O	97	I/O	I/O
48	I/O	I/O	98	I/O	I/O
49	I/O	I/O	99	I/O	I/O
50	SDO, I/O	SDO, I/O	100	DCLK, I/O	DCLK, I/O

Package Pin Assignments (continued)

176-Pin TQFP Package (Top View)



176-Pin TQFP

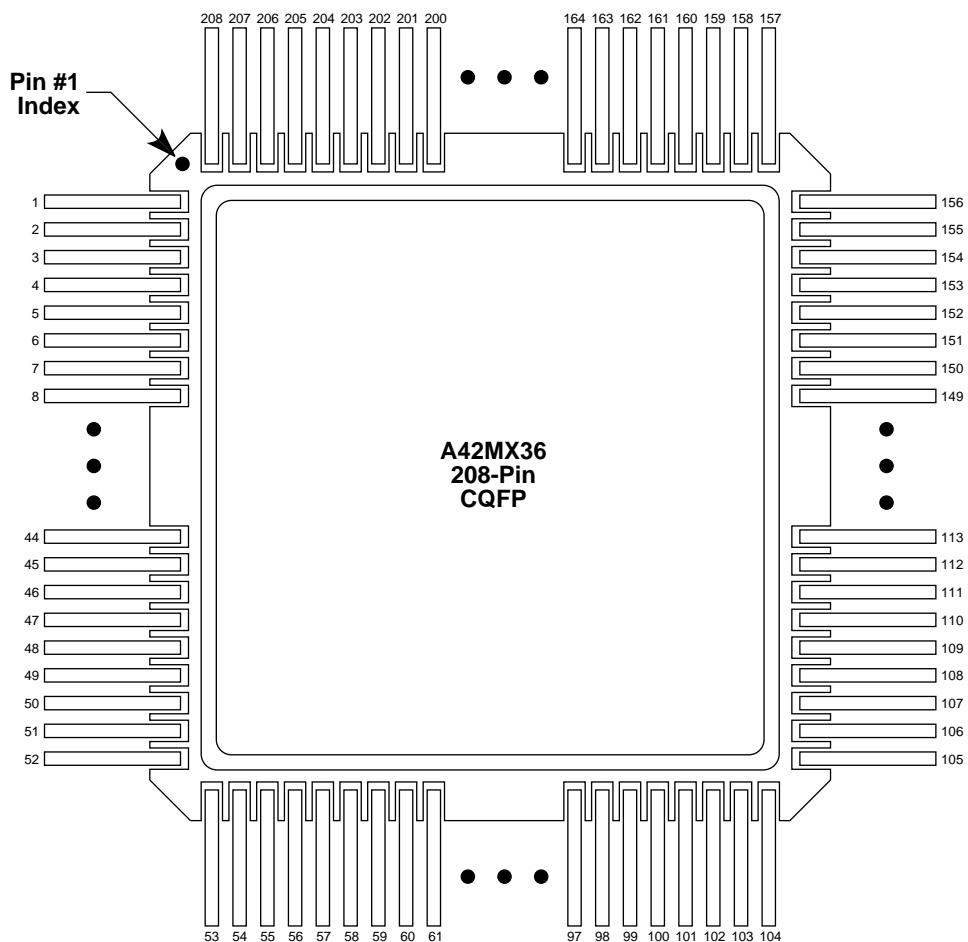
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function	Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	GND	GND	GND	45	GND	GND	GND
2	MODE	MODE	MODE	46	I/O	I/O	TMS, I/O
3	I/O	I/O	I/O	47	I/O	I/O	TDI, I/O
4	I/O	I/O	I/O	48	I/O	I/O	I/O
5	I/O	I/O	I/O	49	I/O	I/O	WD, I/O
6	I/O	I/O	I/O	50	I/O	I/O	WD, I/O
7	I/O	I/O	I/O	51	I/O	I/O	I/O
8	NC	NC	I/O	52	NC	V _{CCI}	V _{CCI}
9	I/O	I/O	I/O	53	I/O	I/O	I/O
10	NC	I/O	I/O	54	NC	I/O	I/O
11	NC	I/O	I/O	55	NC	I/O	WD, I/O
12	I/O	I/O	I/O	56	I/O	I/O	WD, I/O
13	NC	V _{CCA}	V _{CCA}	57	NC	NC	I/O
14	I/O	I/O	I/O	58	I/O	I/O	I/O
15	I/O	I/O	I/O	59	I/O	I/O	WD, I/O
16	I/O	I/O	I/O	60	I/O	I/O	WD, I/O
17	I/O	I/O	I/O	61	NC	I/O	I/O
18	GND	GND	GND	62	I/O	I/O	I/O
19	NC	I/O	I/O	63	I/O	I/O	I/O
20	NC	I/O	I/O	64	NC	I/O	I/O
21	I/O	I/O	I/O	65	I/O	I/O	I/O
22	NC	I/O	I/O	66	NC	I/O	I/O
23	GND	GND	GND	67	GND	GND	GND
24	NC	V _{CCI}	V _{CCI}	68	V _{CCA}	V _{CCA}	V _{CCA}
25	V _{CCA}	V _{CCA}	V _{CCA}	69	I/O	I/O	WD, I/O
26	NC	I/O	I/O	70	I/O	I/O	WD, I/O
27	NC	I/O	I/O	71	I/O	I/O	I/O
28	V _{CCI}	V _{CCA}	V _{CCA}	72	I/O	I/O	I/O
29	NC	I/O	I/O	73	I/O	I/O	I/O
30	I/O	I/O	I/O	74	NC	I/O	I/O
31	I/O	I/O	I/O	75	I/O	I/O	I/O
32	I/O	I/O	I/O	76	I/O	I/O	I/O
33	NC	NC	I/O	77	NC	NC	WD, I/O
34	I/O	I/O	I/O	78	NC	I/O	WD, I/O
35	I/O	I/O	I/O	79	I/O	I/O	I/O
36	I/O	I/O	I/O	80	NC	I/O	I/O
37	NC	I/O	I/O	81	I/O	I/O	I/O
38	NC	NC	I/O	82	NC	V _{CCI}	V _{CCI}
39	I/O	I/O	I/O	83	I/O	I/O	I/O
40	I/O	I/O	I/O	84	I/O	I/O	WD, I/O
41	I/O	I/O	I/O	85	I/O	I/O	WD, I/O
42	I/O	I/O	I/O	86	NC	I/O	I/O
43	I/O	I/O	I/O	87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
44	I/O	I/O	I/O	88	I/O	I/O	I/O

176-Pin TQFP (Continued)

Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function	Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
89	GND	GND	GND	133	GND	GND	GND
90	I/O	I/O	I/O	134	I/O	I/O	I/O
91	I/O	I/O	I/O	135	SDI, I/O	SDI, I/O	SDI, I/O
92	I/O	I/O	I/O	136	NC	I/O	I/O
93	I/O	I/O	I/O	137	I/O	I/O	WD, I/O
94	I/O	I/O	I/O	138	I/O	I/O	WD, I/O
95	I/O	I/O	I/O	139	I/O	I/O	I/O
96	NC	I/O	I/O	140	NC	V _{CCI}	V _{CCI}
97	NC	I/O	I/O	141	I/O	I/O	I/O
98	I/O	I/O	I/O	142	I/O	I/O	I/O
99	I/O	I/O	I/O	143	NC	I/O	I/O
100	I/O	I/O	I/O	144	NC	I/O	WD, I/O
101	NC	NC	I/O	145	NC	NC	WD, I/O
102	I/O	I/O	I/O	146	I/O	I/O	I/O
103	NC	I/O	I/O	147	NC	I/O	I/O
104	I/O	I/O	I/O	148	I/O	I/O	I/O
105	I/O	I/O	I/O	149	I/O	I/O	I/O
106	GND	GND	GND	150	I/O	I/O	WD, I/O
107	NC	I/O	I/O	151	NC	I/O	WD, I/O
108	NC	I/O	TCK, I/O	152	PRA, I/O	PRA, I/O	PRA, I/O
109	LP	LP	LP	153	I/O	I/O	I/O
110	V _{CCA}	V _{CCA}	V _{CCA}	154	CLKA, I/O	CLKA, I/O	CLKA, I/O
111	GND	GND	GND	155	V _{CCA}	V _{CCA}	V _{CCA}
112	V _{CCI}	V _{CCI}	V _{CCI}	156	GND	GND	GND
113	V _{CCA}	V _{CCA}	V _{CCA}	157	I/O	I/O	I/O
114	NC	I/O	I/O	158	CLKB, I/O	CLKB, I/O	CLKB, I/O
115	NC	I/O	I/O	159	I/O	I/O	I/O
116	NC	V _{CCA}	V _{CCA}	160	PRB, I/O	PRB, I/O	PRB, I/O
117	I/O	I/O	I/O	161	NC	I/O	WD, I/O
118	I/O	I/O	I/O	162	I/O	I/O	WD, I/O
119	I/O	I/O	I/O	163	I/O	I/O	I/O
120	I/O	I/O	I/O	164	I/O	I/O	I/O
121	NC	NC	I/O	165	NC	NC	WD, I/O
122	I/O	I/O	I/O	166	NC	I/O	WD, I/O
123	I/O	I/O	I/O	167	I/O	I/O	I/O
124	NC	I/O	I/O	168	NC	I/O	I/O
125	NC	I/O	I/O	169	I/O	I/O	I/O
126	NC	NC	I/O	170	NC	V _{CCI}	V _{CCI}
127	I/O	I/O	I/O	171	I/O	I/O	WD, I/O
128	I/O	I/O	I/O	172	I/O	I/O	WD, I/O
129	I/O	I/O	I/O	173	NC	I/O	I/O
130	I/O	I/O	I/O	174	I/O	I/O	I/O
131	I/O	I/O	I/O	175	DCLK, I/O	DCLK, I/O	DCLK, I/O
132	I/O	I/O	I/O	176	I/O	I/O	I/O

Package Pin Assignments

208-Pin CQFP (Top View)



208-Pin CQFP

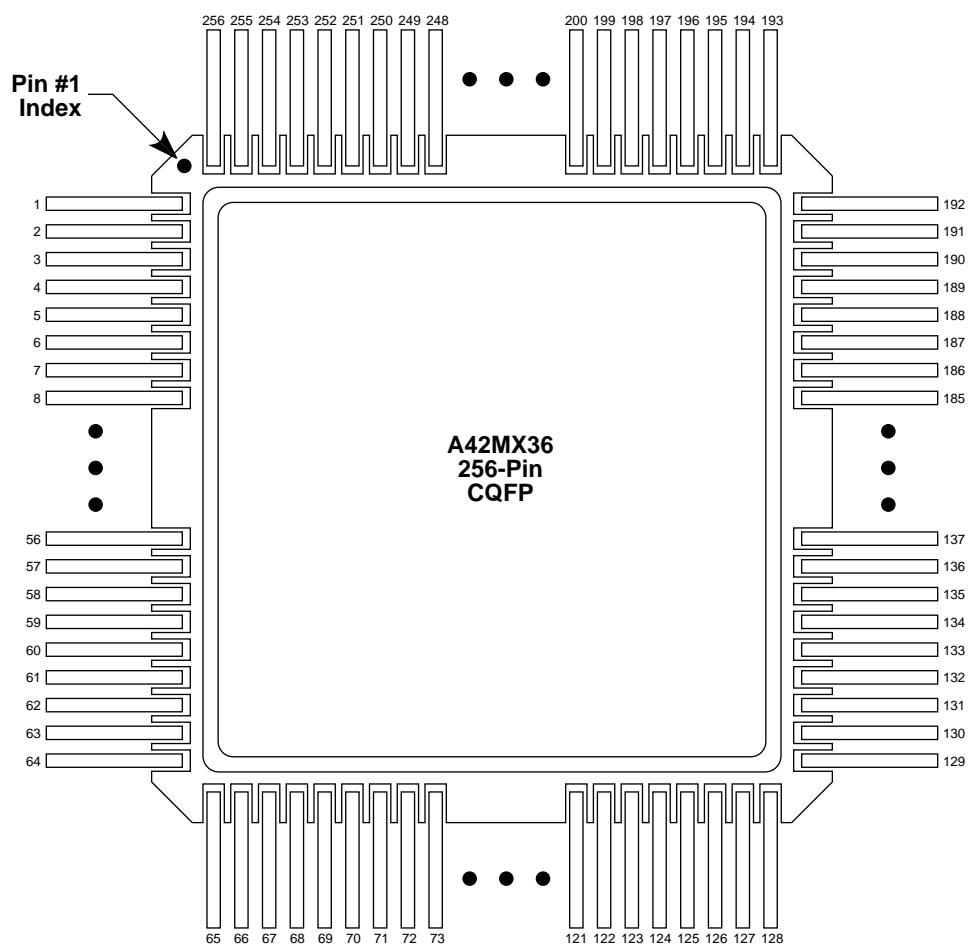
Pin Number	A42MX36 Function						
1	GND	40	I/O	79	V _{CCA}	118	I/O
2	V _{CCA}	41	I/O	80	V _{CCI}	119	I/O
3	MODE	42	I/O	81	I/O	120	I/O
4	I/O	43	I/O	82	I/O	121	I/O
5	I/O	44	I/O	83	I/O	122	I/O
6	I/O	45	I/O	84	I/O	123	I/O
7	I/O	46	I/O	85	WD, I/O	124	I/O
8	I/O	47	I/O	86	WD, I/O	125	I/O
9	I/O	48	I/O	87	I/O	126	GND
10	I/O	49	I/O	88	I/O	127	I/O
11	I/O	50	I/O	89	I/O	128	TCK, I/O
12	I/O	51	I/O	90	I/O	129	LP
13	I/O	52	GND	91	QCLKB, I/O	130	V _{CCA}
14	I/O	53	GND	92	I/O	131	GND
15	I/O	54	TMS, I/O	93	WD, I/O	132	V _{CCI}
16	I/O	55	TDI, I/O	94	WD, I/O	133	V _{CCA}
17	V _{CCA}	56	I/O	95	I/O	134	I/O
18	I/O	57	WD, I/O	96	I/O	135	I/O
19	I/O	58	WD, I/O	97	I/O	136	V _{CCA}
20	I/O	59	I/O	98	V _{CCI}	137	I/O
21	I/O	60	V _{CCI}	99	I/O	138	I/O
22	GND	61	I/O	100	WD, I/O	139	I/O
23	I/O	62	I/O	101	WD, I/O	140	I/O
24	I/O	63	I/O	102	I/O	141	I/O
25	I/O	64	I/O	103	TDO, I/O	142	I/O
26	I/O	65	QCLKA, I/O	104	I/O	143	I/O
27	GND	66	WD, I/O	105	GND	144	I/O
28	V _{CCI}	67	WD, I/O	106	V _{CCA}	145	I/O
29	V _{CCA}	68	I/O	107	I/O	146	I/O
30	I/O	69	I/O	108	I/O	147	I/O
31	I/O	70	WD, I/O	109	I/O	148	I/O
32	V _{CCA}	71	WD, I/O	110	I/O	149	I/O
33	I/O	72	I/O	111	I/O	150	GND
34	I/O	73	I/O	112	I/O	151	I/O
35	I/O	74	I/O	113	I/O	152	I/O
36	I/O	75	I/O	114	I/O	153	I/O
37	I/O	76	I/O	115	I/O	154	I/O
38	I/O	77	I/O	116	I/O	155	I/O
39	I/O	78	GND	117	I/O	156	I/O

208-Pin CQFP (Continued)

Pin Number	A42MX36 Function						
157	GND	170	I/O	183	V _{CCA}	196	QCLKC, I/O
158	I/O	171	QCLKD, I/O	184	GND	197	I/O
159	SDI, I/O	172	I/O	185	I/O	198	I/O
160	I/O	173	I/O	186	CLKB, I/O	199	I/O
161	WD, I/O	174	I/O	187	I/O	200	I/O
162	WD, I/O	175	I/O	188	PRB, I/O	201	I/O
163	I/O	176	WD, I/O	189	I/O	202	V _{CCI}
164	V _{CCI}	177	WD, I/O	190	WD, I/O	203	WD, I/O
165	I/O	178	PRA, I/O	191	WD, I/O	204	WD, I/O
166	I/O	179	I/O	192	I/O	205	I/O
167	I/O	180	CLKA, I/O	193	I/O	206	I/O
168	WD, I/O	181	I/O	194	WD, I/O	207	DCLK, I/O
169	WD, I/O	182	V _{CCI}	195	WD, I/O	208	I/O

Package Pin Assignments (continued)

256-Pin CQFP (Top View)



256-Pin CQFP

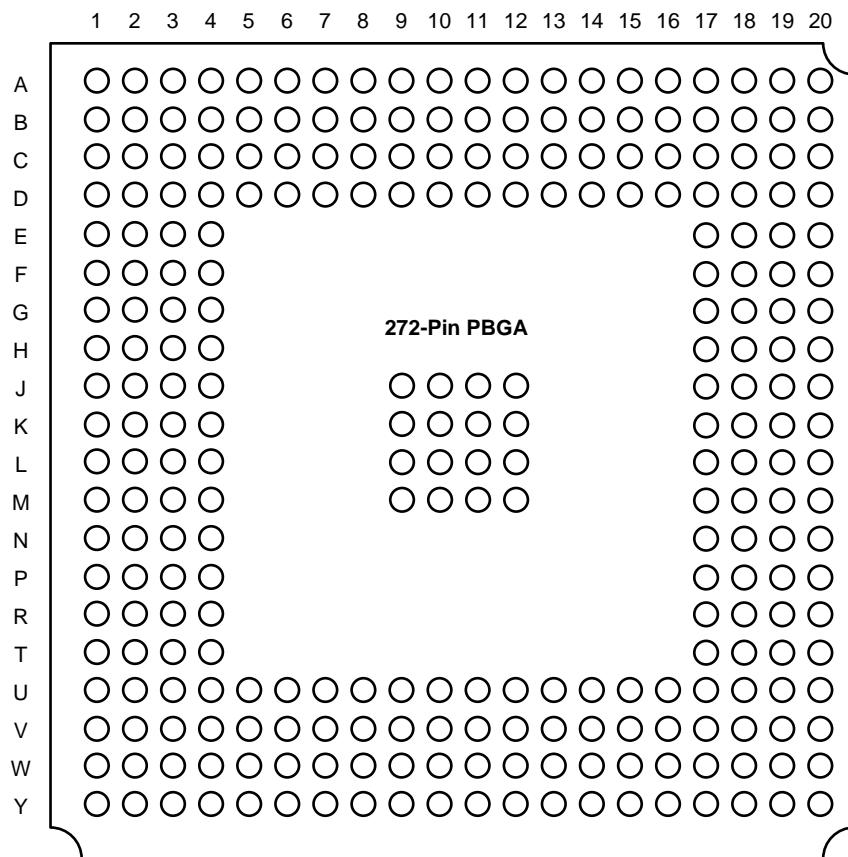
Pin Number	A42MX36 Function						
1	NC	44	I/O	87	WD, I/O	130	NC
2	GND	45	I/O	88	WD, I/O	131	GND
3	I/O	46	I/O	89	I/O	132	I/O
4	I/O	47	I/O	90	I/O	133	I/O
5	I/O	48	GND	91	I/O	134	I/O
6	I/O	49	I/O	92	I/O	135	I/O
7	I/O	50	I/O	93	I/O	136	I/O
8	I/O	51	I/O	94	I/O	137	I/O
9	I/O	52	I/O	95	V _{CCI}	138	I/O
10	GND	53	I/O	96	V _{CCA}	139	GND
11	I/O	54	I/O	97	GND	140	I/O
12	I/O	55	I/O	98	GND	141	I/O
13	I/O	56	I/O	99	I/O	142	I/O
14	I/O	57	I/O	100	I/O	143	I/O
15	I/O	58	I/O	101	I/O	144	I/O
16	I/O	59	I/O	102	I/O	145	I/O
17	I/O	60	V _{CCA}	103	I/O	146	I/O
18	I/O	61	GND	104	I/O	147	I/O
19	I/O	62	GND	105	WD, I/O	148	I/O
20	I/O	63	NC	106	WD, I/O	149	I/O
21	I/O	64	NC	107	I/O	150	I/O
22	I/O	65	NC	108	I/O	151	I/O
23	I/O	66	I/O	109	WD, I/O	152	I/O
24	I/O	67	SDO, TDO, I/O	110	WD, I/O	153	I/O
25	I/O	68	I/O	111	I/O	154	I/O
26	V _{CCA}	69	WD, I/O	112	QCLKA, I/O	155	V _{CCA}
27	I/O	70	WD, I/O	113	I/O	156	I/O
28	I/O	71	I/O	114	GND	157	I/O
29	V _{CCA}	72	V _{CCI}	115	I/O	158	V _{CCA}
30	V _{CCI}	73	I/O	116	I/O	159	V _{CCI}
31	GND	74	I/O	117	I/O	160	GND
32	V _{CCA}	75	I/O	118	I/O	161	I/O
33	LP	76	WD, I/O	119	V _{CCI}	162	I/O
34	TCK, I/O	77	GND	120	I/O	163	I/O
35	I/O	78	WD, I/O	121	WD, I/O	164	I/O
36	GND	79	I/O	122	WD, I/O	165	GND
37	I/O	80	QCLKB, I/O	123	I/O	166	I/O
38	I/O	81	I/O	124	I/O	167	I/O
39	I/O	82	I/O	125	I/O	168	I/O
40	I/O	83	I/O	126	I/O	169	I/O
41	I/O	84	I/O	127	GND	170	V _{CCA}
42	I/O	85	I/O	128	NC	171	I/O
43	I/O	86	I/O	129	NC	172	I/O

256-Pin CQFP (Continued)

Pin Number	A42MX36 Function						
173	I/O	194	I/O	215	WD, I/O	236	I/O
174	I/O	195	DCLK, I/O	216	WD, I/O	237	I/O
175	I/O	196	I/O	217	I/O	238	I/O
176	I/O	197	I/O	218	PRB, I/O	239	I/O
177	I/O	198	I/O	219	I/O	240	QCLKD, I/O
178	I/O	199	WD, I/O	220	CLKB, I/O	241	I/O
179	I/O	200	WD, I/O	221	I/O	242	WD, I/O
180	GND	201	V _{CCI}	222	GND	243	GND
181	I/O	202	I/O	223	GND	244	WD, I/O
182	I/O	203	I/O	224	V _{CCA}	245	I/O
183	I/O	204	I/O	225	V _{CCI}	246	I/O
184	I/O	205	I/O	226	I/O	247	I/O
185	I/O	206	GND	227	CLKA, I/O	248	V _{CCI}
186	I/O	207	I/O	228	I/O	249	I/O
187	I/O	208	I/O	229	PRA, I/O	250	WD, I/O
188	MODE	209	QCLKC, I/O	230	I/O	251	WD, I/O
189	V _{CCA}	210	I/O	231	I/O	252	I/O
190	GND	211	WD, I/O	232	WD, I/O	253	SDI, I/O
191	NC	212	WD, I/O	233	WD, I/O	254	I/O
192	NC	213	I/O	234	I/O	255	GND
193	NC	214	I/O	235	I/O	256	NC

Package Pin Assignments (continued)

272-Pin BGA Package (Top View)



272-Pin PBGA

Pin Number	A42MX36 Function	Ball	A42MX36 Function	Ball	A42MX36 Function	Ball	A42MX36 Function
A1	GND	C4	I/O	E19	I/O	K10	GND
A2	GND	C5	WD, I/O	E20	I/O	K11	GND
A3	I/O	C6	I/O	F1	I/O	K12	GND
A4	WD, I/O	C7	QCLKC, I/O	F2	I/O	K17	I/O
A5	I/O	C8	I/O	F3	I/O	K18	V _{CCA}
A6	I/O	C9	I/O	F4	V _{CCI}	K19	V _{CCA}
A7	WD, I/O	C10	CLKB	F17	I/O	K20	LP
A8	WD, I/O	C11	PRA, I/O	F18	I/O	L1	I/O
A9	I/O	C12	WD, I/O	F19	I/O	L2	I/O
A10	I/O	C13	I/O	F20	I/O	L3	V _{CCA}
A11	CLKA	C14	QCLKD, I/O	G1	I/O	L4	V _{CCA}
A12	I/O	C15	I/O	G2	I/O	L9	GND
A13	I/O	C16	WD, I/O	G3	I/O	L10	GND
A14	I/O	C17	SDI, I/O	G4	V _{CCI}	L11	GND
A15	I/O	C18	I/O	G17	V _{CCI}	L12	GND
A16	WD, I/O	C19	I/O	G18	I/O	L17	V _{CCI}
A17	I/O	C20	I/O	G19	I/O	L18	I/O
A18	I/O	D1	I/O	G20	I/O	L19	I/O
A19	GND	D2	I/O	H1	I/O	L20	TCK, I/O
A20	GND	D3	I/O	H2	I/O	M1	I/O
B1	GND	D4	I/O	H3	I/O	M2	I/O
B2	GND	D5	V _{CCI}	H4	V _{CCA}	M3	I/O
B3	DCLK, I/O	D6	I/O	H17	I/O	M4	V _{CCI}
B4	I/O	D7	I/O	H18	I/O	M9	GND
B5	I/O	D8	V _{CCA}	H19	I/O	M10	GND
B6	I/O	D9	WD, I/O	H20	I/O	M11	GND
B7	WD, I/O	D10	V _{CCI}	J1	I/O	M12	GND
B8	I/O	D11	I/O	J2	I/O	M17	I/O
B9	PRB, I/O	D12	V _{CCI}	J3	I/O	M18	I/O
B10	I/O	D13	I/O	J4	V _{CCI}	M19	I/O
B11	I/O	D14	V _{CCI}	J9	GND	M20	I/O
B12	WD, I/O	D15	I/O	J10	GND	N1	I/O
B13	I/O	D16	V _{CCA}	J11	GND	N2	I/O
B14	I/O	D17	GND	J12	GND	N3	I/O
B15	WD, I/O	D18	I/O	J17	V _{CCA}	N4	V _{CCI}
B16	I/O	D19	I/O	J18	I/O	N17	V _{CCI}
B17	WD, I/O	D20	I/O	J19	I/O	N18	I/O
B18	I/O	E1	I/O	J20	I/O	N19	I/O
B19	GND	E2	I/O	K1	I/O	N20	I/O
B20	GND	E3	I/O	K2	I/O	P1	I/O
C1	I/O	E4	V _{CCA}	K3	I/O	P2	I/O
C2	MODE	E17	V _{CCI}	K4	V _{CCI}	P3	I/O
C3	GND	E18	I/O	K9	GND	P4	V _{CCA}

272-Pin PBGA (Continued)

Pin Number	A42MX36 Function	Ball	A42MX36 Function	Ball	A42MX36 Function	Ball	A42MX36 Function
P17	I/O	U6	WD, I/O	V11	I/O	W16	WD, I/O
P18	I/O	U7	I/O	V12	I/O	W17	I/O
P19	I/O	U8	I/O	V13	WD, I/O	W18	WD, I/O
P20	I/O	U9	WD, I/O	V14	I/O	W19	GND
R1	I/O	U10	V _{CCA}	V15	WD, I/O	W20	GND
R2	I/O	U11	V _{CCI}	V16	I/O	Y1	GND
R3	I/O	U12	I/O	V17	I/O	Y2	GND
R4	V _{CCI}	U13	I/O	V18	SDO, TDO, I/O	Y3	I/O
R17	V _{CCI}	U14	QCLKB, I/O	V19	I/O	Y4	TDI, I/O
R18	I/O	U15	I/O	V20	I/O	Y5	WD, I/O
R19	I/O	U16	V _{CCI}	W1	GND	Y6	I/O
R20	I/O	U17	I/O	W2	GND	Y7	QCLKA, I/O
T1	I/O	U18	GND	W3	I/O	Y8	I/O
T2	I/O	U19	I/O	W4	TMS, I/O	Y9	I/O
T3	I/O	U20	I/O	W5	I/O	Y10	I/O
T4	I/O	V1	I/O	W6	I/O	Y11	I/O
T17	V _{CCA}	V2	I/O	W7	I/O	Y12	I/O
T18	I/O	V3	GND	W8	WD, I/O	Y13	I/O
T19	I/O	V4	GND	W9	WD, I/O	Y14	I/O
T20	I/O	V5	I/O	W10	I/O	Y15	I/O
U1	I/O	V6	I/O	W11	I/O	Y16	I/O
U2	I/O	V7	I/O	W12	I/O	Y17	I/O
U3	I/O	V8	WD, I/O	W13	WD, I/O	Y18	WD, I/O
U4	I/O	V9	I/O	W14	I/O	Y19	GND
U5	V _{CCI}	V10	I/O	W15	I/O	Y20	GND

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous version	Changes in current version (v6.0)	Page
v5.1	The “Ease of Integration” section on page 1 was updated.	page 1
	The “Temperature Grade Offerings” table on page 3 is new.	page 3
	The “Speed Grade Offerings” table on page 3 is new.	page 3
	The “General Description” section on page 4 was updated.	page 4
	The “MultiPlex I/O Modules” section on page 9 was updated.	page 9
	The “User Security” section on page 9 was updated.	page 9
	Table 1 on page 10 was updated.	page 10
	The “Power Dissipation” section on page 11 was updated.	page 11
	The “Static Power Component” section on page 11 was updated.	page 11
	The “Equivalent Capacitance” section on page 11 was updated.	page 11
	Figure 13 on page 14 was updated.	page 14
	Table 4 on page 14 was updated.	page 14
	Figure 14 on page 15 was updated.	page 15
	Table 5 on page 15 was updated.	page 15
	The “Development Tool Support” section on page 15 was updated.	page 15
	The “Absolute Maximum Ratings for 42MX Devices**” table on page 17 and the “Absolute Maximum Ratings for 40MX Devices**” table on page 19 were updated.	page 17
	The “5V TTL Electrical Specifications” table on page 18 was updated.	page 18
	The “3.3V LVTTL Electrical Specifications” table on page 20 was updated.	page 20
	In the “Mixed 5.0V/3.3V Operating Conditions (for 42MX devices only)” section on page 21, the “Absolute Maximum Ratings**” table , “Recommended Operating Conditions” table , and “Mixed 5.0V/3.3V Electrical Specifications” table were updated.	page 21
	The “DC Specification (5.0V PCI Signaling)1” table on page 22 was updated.	page 22
	The “DC Specification (3.3V PCI Signaling)1” table on page 23 was updated.	page 23
	The Junction Temperature (TJ) section, “Package Thermal Characteristics” section on page 25, and the tables were updated.	page 25
	The “40MX Timing Model**” on page 26 was updated.	page 26
	The “42MX Timing Model (Logic Functions using Quadrant Clocks)**” on page 28	page 28
	The “42MX Timing Model (SRAM Functions)**” on page 29 was updated.	page 29
	The “Output Buffer Latches” figure on page 32 was updated.	page 32
	The “42MX Temperature and Voltage Derating Factors” section on page 39 is new.	page 39
	The “40MX Temperature and Voltage Derating Factors” section on page 40 is new.	page 40
	The “Pin Descriptions” section on page 80 was updated.	page 80
	In the “100-Pin PQFP” table on page 87, the following pins changed: Pin 64 (42MX09 and 42MX16) has changed to LP	page 87
	In the “160-Pin PQFP” table on page 90, the following pins changed: Pin 61 (42MX09, 42MX16, and 42MX64) has changed to LP	page 90
	In the “208-Pin PQFP” table on page 93, the following pins changed: Pin 129 (42MX09, 42MX16, and 42MX64) has changed to LP Pin 198 (42MX09) has changed to I/O	page 93
	In the “240-Pin PQFP” table on page 97, the following pins changed: Pin 91 (42MX36) has changed to LP	page 97
	In the “100-Pin VQFP Package” table on page 102, the following pins changed: Pin 62 (42MX09 and 42MX16) has changed to LP	page 102
	In the “176-Pin TQFP” table on page 104, the following pins changed: Pin 109 (42MX09 and 42MX16) has changed to LP	page 104
	In the “272-Pin PBGA” table on page 113, the following pins changed: Pin K20 (42MX36) has changed to LP	page 113

v5.0	The “Low Power Mode” on page 5 was updated.	page 5
	Footnote 8 in the “Electrical Specifications” table on page 13 was updated.	page 13
	Footnote 8 in the “Electrical Specifications” table on page 14 was updated.	page 14
v4.0.1	Because the changes in this data sheet are extensive and technical in nature, this should be viewed as a new document. Please read it as you would a data sheet that is published for the first time.	ALL
	Note that the “Package Characteristics and Mechanical Drawings” section has been eliminated from the data sheet. The mechanical drawings are now contained in a separate document, “Package Characteristics and Mechanical Drawings,” available on the Actel web site.	

Data Sheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definition of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

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